Course		L-T-P-		r Of
No.		Credits		luction
AE202		2-2-0-4	20)16
Course ob		. ,		
	e provides students with an entry level foundatio	-		-
•	on . Also enables students to apply these program	mming skills	s in their fi	eld of
study.		- 1 E	с <i>г</i> .	
•	Basics of c programming, control statements, arr		-	ons, user
	a types: structure, union, enumerated data type, in to Python, comparisons of Python constructs v	-	mes.	
Expected		with C.	A	
1	ogram in c for various engineering, science and	technology	related pro	hlems
-	ise python language by comparison with C lang		erated pro	
	dents to write simple programs in python and al		em to none	ler more
	a language.		en to pon	
Text Book				
	Al & Pohl, Ira. A Book on Computer Programm	ing in C. 4th	Ed., Pears	son
Education		- <u>0</u> 0, 14	, _ cu	
	K. A., Fundamentals of Python - First Programs	s, Cengage I	earning Ir	ndia, 2015
			0	,
Reference				
1. Balaguri	asamy E., Programming in ANSI C, Tata McGra	aw Hill		
2 Someriit	Clash All CO DITLESS			
2. Samarju	Ghosh, All of C, PHI Learning			
	Head First Python, , O' Reilly Publishers			
3.Barry, P., 4. Guzdial,	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programm	.		
3.Barry, P., 4. Guzdial, 5 Pradip D	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey and Manas Ghosh, Computer Fundamentals a	.		
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C	and Program	ming in C	, Oxford.
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey,	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis	and Program	ming in C	, Oxford.
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis 5	and Program	ming in C	, Oxford.
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis thon .org	and Program	ming in C	, Oxford.
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis thon .org corialpoints.com	and Program	ming in C	, Oxford.
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals and Kamthane ; Programming in C A. et al., How to think like a Computer Scientis 5 thon .org torialpoints.com Course Plan	and Program	ming in C.	, Oxford. n, John
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis thon .org corialpoints.com	and Program	ming in C. with Pytho	, Oxford. n, John Semester
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals and Kamthane ; Programming in C A. et al., How to think like a Computer Scientis 5 thon .org torialpoints.com Course Plan	and Program	ming in C. with Pytho	, Oxford. n, John Semester Exam
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals and Kamthane ; Programming in C A. et al., How to think like a Computer Scientis 5 thon .org corialpoints.com Course Plan Contents	and Program t: Learning v Hour	ming in C. with Pytho	, Oxford. n, John Semester
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis thon .org torialpoints.com Course Plan Programming basics: Flowcharts and Algorith	and Program t: Learning v Hour	ming in C. with Pytho	, Oxford. n, John Semester Exam
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut Module	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis 5 thon .org corialpoints.com Course Plan Contents Programming basics: Flowcharts and Algorith Compiler– Interpreter-Linker-Loader.	and Program t: Learning v Hour	ming in C. with Pytho	, Oxford. n, John Semester Exam Marks
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals and Kamthane ; Programming in C A. et al., How to think like a Computer Scientis 5 thon .org corialpoints.com Course Plan Contents Programming basics: Flowcharts and Algorith Compiler–Interpreter-Linker-Loader. Structured programming	and Program t: Learning v Hour hms.	ming in C. with Pytho	, Oxford. n, John Semester Exam
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis 5 thon .org torialpoints.com Course Plan Contents Programming basics: Flowcharts and Algorith Compiler– Interpreter-Linker-Loader. <u>Structured programming</u> Introduction to C: Character set, Identif	and Program t: Learning v Hour hms.	ming in C. with Pytho	, Oxford. n, John Semester Exam Marks
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut Module	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis 5 thon .org corialpoints.com Course Plan Contents Programming basics: Flowcharts and Algorith Compiler–Interpreter-Linker-Loader. <u>Structured programming</u> Introduction to C: Character set, Identiff Keywords, Constants –Data Types- Variable	hms. fiers, es –	ming in C. with Pytho	, Oxford. n, John Semester Exam Marks
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut Module	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis 5 thon .org corialpoints.com Course Plan Contents Programming basics: Flowcharts and Algorith Compiler– Interpreter-Linker-Loader. <u>Structured programming</u> Introduction to C: Character set, Identiff Keywords, Constants –Data Types- Variable Operators and Expressions – Operator preceder	hms. Fiers, es – ence	ming in C. with Pytho	, Oxford. n, John Semester Exam Marks
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis thon .org corialpoints.com Course Plan Contents Programming basics: Flowcharts and Algorith Compiler– Interpreter-Linker-Loader. Structured programming Introduction to C: Character set, Identifi Keywords, Constants –Data Types- Variable Operators and Expressions – Operator preced and associativity – Expression Evaluation (Sir	and Program t: Learning v Hour hms. fiers, es – ence mple	ming in C. with Pytho	, Oxford. n, John Semester Exam Marks
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut Module	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals a Kamthane ; Programming in C A. et al., How to think like a Computer Scientis thon .org corialpoints.com Course Plan Contents Programming basics: Flowcharts and Algorith Compiler– Interpreter-Linker-Loader. Structured programming Introduction to C: Character set, Identiff Keywords, Constants –Data Types- Variable Operators and Expressions – Operator preced and associativity – Expression Evaluation (Sir Examples) – Simple computational problem	and Program t: Learning v Hour hms. fiers, es – ence mple	ming in C. with Pytho	, Oxford. n, John Semester Exam Marks
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut Module	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey ey and Manas Ghosh, Computer Fundamentals and Kamthane ; Programming in C A. et al., How to think like a Computer Scientis 5 thon .org corialpoints.com Course Plan Contents Programming basics: Flowcharts and Algorith Compiler– Interpreter-Linker-Loader. Structured programming Introduction to C: Character set, Identiff Keywords, Constants –Data Types- Variable Operators and Expressions – Operator preced and associativity – Expression Evaluation (Sin Examples) – Simple computational problinvolving the above constructs .	hms. Fiers, es – ence mple lems	ming in C. with Pytho	, Oxford. n, John Semester Exam Marks
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut Module	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey and Manas Ghosh, Computer Fundamentals and Kamthane ; Programming in C A. et al., How to think like a Computer Scientis thon .org corialpoints.com Course Plan Contents Programming basics: Flowcharts and Algorith Compiler– Interpreter-Linker-Loader. Structured programming Introduction to C: Character set, Identiff Keywords, Constants –Data Types- Variable Operators and Expressions – Operator preced and associativity – Expression Evaluation (Sin Examples) – Simple computational problinvolving the above constructs . Control Statements: Selection, Iteration	and Program t: Learning v Hour hms. fiers, es – ence mple lems (for,	ming in C. with Pytho	, Oxford. n, John Semester Exam Marks
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut Module	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmer ey and Manas Ghosh, Computer Fundamentals and Kamthane ; Programming in C A. et al., How to think like a Computer Scientis 5 thon .org corialpoints.com Course Plan Contents Programming basics: Flowcharts and Algorith Compiler- Interpreter-Linker-Loader. <u>Structured programming</u> Introduction to C: Character set, Identiff Keywords, Constants –Data Types- Variable Operators and Expressions – Operator preced and associativity – Expression Evaluation (Sin Examples) – Simple computational problinvolving the above constructs . Control Statements: Selection, Iteration while, do-while), Branching (switch, br	Hour hms. fiers, es ence mple lems (for, (for, reak,	ming in C. with Pytho s	, Oxford. n, John Semester Exam Marks 15%
3.Barry, P., 4. Guzdial, 5 Pradip D 6. Ashok N 7.Downey, Wiley, 201 8. www.py 9. www.tut Module	Head First Python, , O' Reilly Publishers M. J., Introduction to Computing and Programmey and Manas Ghosh, Computer Fundamentals and Kamthane ; Programming in C A. et al., How to think like a Computer Scientis thon .org corialpoints.com Course Plan Contents Programming basics: Flowcharts and Algorith Compiler– Interpreter-Linker-Loader. Structured programming Introduction to C: Character set, Identiff Keywords, Constants –Data Types- Variable Operators and Expressions – Operator preced and associativity – Expression Evaluation (Sin Examples) – Simple computational problinvolving the above constructs . Control Statements: Selection, Iteration	Hour hms. fiers, es ence mple lems (for, (for, reak,	ming in C. with Pytho	, Oxford. n, John Semester Exam Marks

Arrays and Strings: 1D and 2D arrays –Searching		
 (Linear and binary) - Sorting (Bubble, Selection) – Matrix manipulation programs – Strings and basic operations on strings – String functions – Basic Programs on string manipulation. Functions: Definition – Calling – Declaration – Parameter Passing (by value and by reference) – 	11	20%
Recursion – Library functions –Basic Programs based on functions.	LAM	
Enumerated data type - Programs involving structure and union.		20%
arrays – Pointers and structures – Pointers and functions – Command line arguments – Dynamic memory allocation – Operations on pointers – Basic Programs involving the above concepts Files: file operations	Y	
SECOND INTERNAL EXAM	INATION	
Object oriented programming Introduction to Python : Comparison of following Python constructs with C- keywords, variables, operators, expression and statements, control statements- programming examples	9	15%
Comparison of constructs of python with C - Functions, calling functions, user defined functions, strings and lists-programming examples Basics of Tuples, Dictionary and Exception handling in python.	9	15%
END SEMESTER EXAMINATION	J	
	 operations on strings – String functions – Basic Programs on string manipulation. Functions: Definition – Calling – Declaration – Parameter Passing (by value and by reference) – Recursion – Library functions –Basic Programs based on functions. User defined data types: Structure – Union – Enumerated data type - Programs involving structure and union. Pointers: Declaration, Initialization – Pointers and arrays – Pointers and structures – Pointers and functions – Command line arguments – Dynamic memory allocation – Operations on pointers – Basic Programs involving the above concepts Files: file operations SECOND INTERNAL EXAM Object oriented programming Introduction to Python : Comparison of following Python constructs with C- keywords, variables, operators, expression and statements, control statements- programming examples Comparison of constructs of python with C - Functions, calling functions, user defined functions, strings and lists-programming examples Basics of Tuples, Dictionary and Exception handling in python. 	operations on strings – String functions – Basic Programs on string manipulation. Functions: Definition – Calling – Declaration – Parameter Passing (by value and by reference) – Recursion – Library functions –Basic Programs based on functions. User defined data types: Structure – Union – Enumerated data type - Programs involving structure and union. Pointers: Declaration, Initialization – Pointers and arrays – Pointers and structures – Pointers and functions – Command line arguments – Dynamic memory allocation – Operations on pointers – Basic Programs involving the above concepts Files: file operations SECOND INTERNAL EXAMINATION Object oriented programming ntroduction to Python : Comparison of following Python constructs with C- keywords, variables, operators, expression and statements, control statements- programming examples 9 Comparison of constructs of python with C – Functions, calling functions, user defined functions, strings and lists-programming examples Basics of Tuples, Dictionary and Exception handling in python. 9

QUESTION PAPER PATTERN: Maximum marks : 100

Time : 3 hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2. Each question carries 15 marks and may have not more than four sub divisions. (15 x 2 = 30 marks)Part B 114

11

Answer any two out of three questions uniformly covering Modules 3 and 4. Each question carries 15 marks and may have not more than four (15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6. Each question carries 20 marks and may have not more than four sub divisions. (20 x 2 = 40 marks)

Course N	o. Course Name	L-T-P - Credit		Year of roduction
AE204	SENSORS AND TRANSDUCERS	3-0-0-3		2016
Prerequisi	te:	L		
Course Of • To give id • To unders • To enable industrial a Syllabus Definition transducer transducers seismic ins Expected		nsducers struments to meet the s – Resistance transd essure Transducers -	requirement ucer- Capa Hall effec	ents of acitance
diff gain use Text Boo 1. John P. 1 2. S.M. Sze		vailable neasuring instruments s", 3rd Edition, Pears ons Inc., Singapore, 1	on Educat	ors and their
Data Daa	h (A managed for any in the averaging tion)			
Data Boo Reference	k (Approved for use in the examination):		-	
 Murthy I Neubert I 2nd Editi Patranab Waldem Doebelin 	D. V. S, "Transducers and Instrumentation", H.K.P, "Instrument Transducers - An Introducers, Oxford University Press, Cambridge, 19 is, "Sensors and Transducers", 2nd Edition, ar Nawrocki, "Measurement Systems and Sec. E.O, "Measurement Systems - Application rk, 2003.	action to their Perform 99. Prentice Hall India Pensors", Artech House and Design", 4th Edi	nance and vt. Ltd., 20 v, 2005.	Design", 003.
	Course P	lan		
Module	Contents		Hours	Sem. Exam Marks
I	Transducers: Definition of transducers, class transduction principle, measurand, material Analog and digital transducers, Active and p Primary and Secondary transducers. Charac	and technology, bassive transducers,	6	
п	transducers. Resistance Transducer : Basic principle Loading effects, Resolution, Linearity, Res –Types.		6	15% 15%

	Inductance Transducer :- Basic principle – Linear variable differential transformer – RVDT-types. Capacitance Transducer : Basic principle- transducers using change in area of plates – distance between plates- variation of dielectric constants-frequency response –Types		
	FIRST INTERNAL EXAMINATION		
III	Force and Torque Transducers: Proving ring, hydraulic and pneumatic load cell, dynamometer and gyroscopes. Sound Transducers: Sound level meter, sound characteristics, Microphone. Torque transducer design-the torque measurement system-the rotation rate measurement system		15%
IV	Pressure Transducers: basic principle- different types of manometers-u tube manometer-well type manometers. Level transducer-continuous level measurement-discrete level measurement-mass –capacitive level gauges, Dead weight calibrator.	7	15%
	SECOND INTERNAL EXAMINATION		
V	Hall effect transducers, Digital transducers, Proximity devices, , Piezo-electric sensors, eddy current transducers, tachogenerators and stroboscope, Magnetostrictive transducers, Fibre optic sensor, Semiconductor sensor. Basics of Seismic instrument and accelerometers	8	20%
VI	Flow Transducers: Bernoulli's principle and continuity, orifice plate, nozzle plate, venture tube, Rota meter, anemometers, electromagnetic flow meter, impeller meter and turbid flow meter	8	20%
	END SEMESTER EXAM		

Maximum marks : 100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2. Each question carries 15 marks and may have not more than four sub divisions. $(15 \times 2 = 30 \text{ marks})$

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4. Each question carries 15 marks and may have not more than four $(15 \times 2 = 30 \text{ marks})$

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6. Each question carries 20 marks and may have not more than four sub divisions. $(20 \times 2 = 40 \text{ marks})$

Time : 3 hours

Course	e Course name	L-T-P-	Year of Introduction
Code AE232	TRANSDUCERS AND	Credits 0-0-3-1	2016
AL232	INSTRUMENTATION LAB	0-0-3-1	2010
	uisite : AE204 Sensors and transducers	MIN	CAI
Course	e objective	A III	AL
• Experi	To give a hands on experience to students in var ments :- (Minimum 12 experiments are mandat		's and instrumentation.
-	Determination of the characteristics of LVDT.	211	
2.	Determination of characteristics of temperature		
2. 3.	Determination of the characteristics of thermoc).
4.	Determination of the characteristics of RTD	ouple.	
5.	Determination of the characteristics of optical t	ransducers usin	g LDR.
6.	Determination of the characteristics of capacitiv		-
7.	Measurement of displacement using inductive tr	•	
8.	Calibration of force transducer signal conditioned		tage characteristics
	curve.	1	C
9.	Measurement of torque and pressure using strai	in gauges.	
10.	Determination of the characteristics of Micro pr	essure and Mic	ro accelerometer sensing
	device.		
11.	Measurement of pressure using piezoelectric pic	ck up.	
12.	Measurement of strain and load using strain gau	iges.	
13.	Determination of the characteristics of Hall Eff	ect sensor.	
14.	Calibration using dead weight tester.		
15.	Level measurement using capacitive transducer.		
16.	Pressure measurement using U-tube manometer	: <u>]</u>	
17.	Measurement of speed using photo electric pick	up transducers.	
18.	Measurement of position using synchro Transm	itter and receive	er.
Expect •	ted outcome At the end of the semester students are expected and its application.	l to be familiar	with various transducers

Course code	e Course name	L-T-P-Credits		nr of luction
AE301	CONTROL SYSTEM	3-1-0-4	20	16
	QUISITE : Nil		-	-
	bjectives			
	o familiarize the modelling of linear time in	nvariant systems and	their respo	onses in
	me and frequency domain.		mon roop	
	b learn state space techniques			
Syllabus		V A I A	A.A	
•	tical model of systems – transfer function	– block diagram -Sys	tem analv	sis-time
	nalysis- stability of linear systems -frequen			
	-state diagram.		AL	
	loutcome	CITTL	2.4.7	
-	d of the semester students will be able to u	inderstand and analyse	e the diffe	rent
	r of system performances.	COLLE		
Text Boo				
	Nagrath and M. Gopal, Control Systems	Engineering, New Ag	e Internat	ional
	ublishers, New Delhi, 1997	0 0 0		
2. M	. Gopal, Digital Control and State Variable	e Methods, 2 nd ed., 7	Tata McGr	aw Hill,
Ν	ew Delhi, 2003			
Referenc	e Books			
1.	G. J. Thaler, Automatic Control Systems	, Jaico Publishing Ho	use, Mum	bai, 2005
2.	K. Ogata, Modern Control Engineering,	4th ed., Pearson Edu	cation, De	elhi, 2002
3.	B. C. Kuo, Automatic Control Systems,	7th ed., Prentice Hall	of India, I	New Delhi
	1995			
4.	R. C. Dorf and R. H. Bishop, Modern Co Education, Delhi, 2004	ontrol Systems, 10th e	ed., Pearso	on
	Course Pla	an 🔰 🖉		
			_	Semester
Module	Contents		Hours	Exam
				Marks
	System Analysis: Systems, subsystems,	, and stochastic and		
	deterministic systems - Principles of auto	-	/	
т	loop and closed loop systems -Principles			
Ι	homogeneity-Transfer Function Appro			
	models of physical systems and transfer			150/
	Impulse response and transfer function		8	15%
		ctrical, mechanical,		
	electromechanical, hydraulic and pn	-		
	Analogous systems -Multiple-input mul	1 1 1		
	Block diagram algebra - block diagram	m reduction -Signal		
	flow graphs -Mason's gain formula.			
	Time Domain Analysis, Standard (set)	nionala Desmanas -f		
	Time Domain Analysis: Standard test s			
II	systems to standard test signals –Step	-	8	15%
••	order systems -Time domain specification			10/0
	system) -Steady state response -Steady s			
	dynamic error coefficients -Zero input an FIRST INTERNAL EX			
	FIKST INTERNAL EX			
III	Stability of linear systems -absolute stabi		8	15%

	-Hurwitz and Routh stability criterion -Root locus method - construction of root locus -root contours -root sensitivity to gain k -effect of poles and zeros and their locations on the root locus.		
IV	Frequency Domain Analysis: Frequency response representation -Frequency domain specifications -Correlation between time and frequency response -Polar plots - Logarithmic plots -Bode plots – All pass, minimum-phase and non-minimum-phase systems -Transportation lag - Stability in frequency domain -Nyquist stability criterion - Stability from polar and bode plot -Gain margin and phase margin -relative stability -M-N circles -Nichols chart.	9	15%
	SECOND INTERNAL EXAMINATION		
V	State Variable Analysis: Concepts of state, state variables, state vector and state space -State model of continuous time systems Transformation of state variable -Derivation of transfer function from state model -invariance property	9	20%
VI	State diagram -State variable from transfer function -bush or companion form -controllable canonical form - observable canonical form -Jordan canonical form -Diagonalization-State transition matrix -computation of state transition matrix by Laplace transform, Cayley-Hamilton theorem -Controllability and observability of a system. (proof not required)	10	20%
	END SEMESTER EXAMINATION		1

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Exam Duration: 3 Hours

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)

code	Course name	L-T-P-Credits		ar of luction
AE302	PROCESS CONTROL	4-0-0-4	20	16
Prerequi	site : Nil			
Course o	bjectives			
• To	introduce the principles of various co	ontrol and instrumentation	compone	ents and
stı	rategies applied in a process control sy	vstem.		
• To	Basics of Principals of Sensors and T	Fransducers, Control Syste	em Compo	onent and
Pr	ocess Loop Control		NA	
Syllabus	AL ADUU	IL NALA	IVI	
	naracteristics - Types of processes- An			
Control- I	Feedback Control- Multi Loop & Nonl	linear Systems-Concept o	f Multiva	riable
Control- I	ntelligent Controllers	DCITY		
Expected		KNIY		
	the end of the semester students will		analyse t	he
	fferent behaviour of process control sy	stem performances.		
Text Boo				
	Wayne Bequette, Process Control: Mo	8		ll
	onald Eckman – Automatic Process Co		1ted	
	G.Shinskey, Process control Systems,	IMH		
Referenc				
	G.Liptak ,Handbook of Instrumentatio			TT'11
	onsidine, Process Instrumentation and		a., McGr	aw Hill
	rishna Kant, <i>Computer Based Industric</i> urrill , <i>Applications concepts of Proces</i>			
4 1/1	$\Pi T \Pi A n n \Pi C n \Pi O N S C O N C P N S O I P V O C P S$			
5. M	urrill, Fundamentals of Process Contra	ol, ISA		
5. M 6. St	urrill, <i>Fundamentals of Process Contr</i> ephanopoulos George, <i>Chemical Proc</i> e	ol , ISA ess Control, PHI	& Sons ?	004
5. M 6. St 7. T.	urrill, <i>Fundamentals of Process Contraction Contracti</i>	ol, ISA ess Control, PHI Applications, John Wiley		
5. M 6. St 7. T. 8. Th	urrill, <i>Fundamentals of Process Contra</i> ephanopoulos George , <i>Chemical Proce</i> J.Ross <i>Fuzzy Logic with Engineering</i> nomas E Marlin - <i>Process Control</i> - De	ol , ISA ess Control, PHI Applications, John Wiley signing processes and Co		
5. M 6. St 7. T. 8. Th	urrill, <i>Fundamentals of Process Contraction Contracti</i>	ol , ISA ess Control, PHI Applications, John Wiley signing processes and Co		
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	features, faceplate, functions, MLPC- features, faceplate,		
	functions, SLPC and MLPC comparison. Scaling: types of		
	scaling, examples of scaling		
	FIRST INTERNAL EXAMINATION		
III	Feedback Control: Basic principles, Elements of the	8	15%
	feedback Loop, Block Diagram, Control Performance		
	Measures for Common Input Changes, Selection of Variables		
	for Control Approach to Process Control. Factors in		
	Controller Tuning, Determining Tuning Constants for Good	N A	
	Control Performance, Correlations for tuning Constants, Fine	IVI	
	Tuning of the controller tuning Constants.	A T	
IV	Multi Loop & Nonlinear Systems: Cascade control, Feed	9	15%
	forward control, feedback-feed forward control, Ratio	h. And	
	control, Selective Control , Split range control- Basic		
	principles, Design Criteria , Performance, Controller	_	
	Algorithm and Tuning, Implementation issues, Examples and		
	any special features of the individual loop and industrial		
	applications. Nonlinear Elements in Loop: Limiters, Dead		
	Zones, Backlash, Dead Band Velocity Limiting, Negative		
	Resistance.		
	SECOND INTERNAL EXAMINATION	10	2001
V	Multivariable Control: Concept of Multivariable Control:	10	20%
	Interactions and its effects, Modelling and transfer functions,		
	Influence of Interaction o the possibility of feedback control,		
	important effects on Multivariable system behaviour Relative		
	Gain Array, effect of Interaction on stability and tuning of		
	Multi Loop Control system. Multi Loop control Performance		
	through: Loop Paring, tuning, Enhancement through		
X/T	Decoupling, Single Loop Enhancements.	10	200/
VI	Intelligent Controllers: Step analysis method for finding first,	10	20%
	second and multiple time constants and dead time. Model Based controllers: Internal Model control, Smith predictor,	1	
	optimal controller, Model Predictive controller, Dynamic	1	
	matrix controller (DMC). Self Tuning Controller. Fuzzy logic	/	
	systems and Fuzzy controllers, Introduction, Basic Concepts		
	of Fuzzy Logic, Fuzzy Sets, Fuzzy Relation, Fuzzy Graphs,		
	and Fuzzy Arithmetic, Fuzzy If-Then Rules, Fuzzy Logic		
	Applications, Neuro-Fuzzy Artificial Neural networks and		
	ANN controller.		
	END SEMESTER EXAMINATION		l
	END SEIVIESTER EAAIVIINATION		

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

Part B

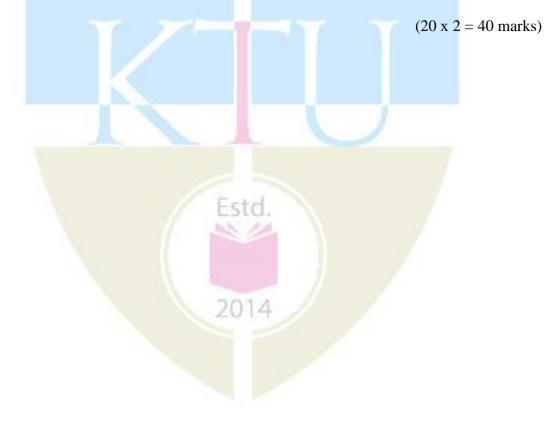
Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.



Course	Course name	L-T-P-	Year of
code		Credits	Introduction
AE303	ELECTRICAL MEASUREMENTS AND MEASURING INSTRUMENTS	3-0-0-3	2016
Prerequ	isite: Nil		
Course	objectives		
• 1	o impart knowledge on different types of measuring techni	ques using	g electrical an
e	lectronic measurement system.		
Syllabus	A DI A DI II VAI	AN	A
General	Principles of Measurements- Calibration of Meters- Errors	in Measur	ement and its
Analysis	- Essentials of indicating instruments- Moving Iron, Dynan	no Meter-	D.C bridges-
A.C brid	ges-Series and shunt type ohm meter- Electronic measurem	ents- Ana	log and digita
	ers- Waveform analyzing instruments: Distortion meter- S		
	e Measurements- Data Acquisition systems.	1	
0	d outcome	1	
-	ents will be able		
	o learn the use of different types of analogue meters for me	easuring el	ectrical
	uantities such as current, voltage, power energy power fact		
-	o learn the principle of working and applications of electro		
Text Bo			
	aldwin, C.T., "Fundamentals of electrical measurements" -	- Lvall Bo	ok Depot. Ne
	elhi, 1973.		
	avid.A.Bell, "Electronic Instrumentation and Measuremen	ts". 2nd E	dition. Prentio
	all, New Jersy, 1994.		,
	olding, E.W. and Widdis, F.C., "Electrical Measurements	and Meası	iring
	istruments" A.H.Wheeler and Co, 5th Edition, 1993.	and mouse	ining
	ce Books		
	booper, W.D. and Helfric, A.D., "Electronic Instrumentation	n and Mea	surement
	echniques" Prentice Hall of India, 1991.		Surement
	Calsi.H.S., "Electronic Instrumentation", Tata McGraw Hill	New Del	hi 1995
	attanabis, "Sensors and Transducers", 2nd Edition, Prentice		
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	Valdemar Nawrocki, "Measurement Systems and Sensors",	Artech H	2005
4 . v	Course Plan	Alterin	Juse, 2005
	Course Han		Semest
Module	Contents	U.	
Module	Contents	по	urs Exan Mark
Ι	Canonal Dringinlag of Massurements, Absolute and Was	rking 6	15%
l	General Principles of Measurements: Absolute and Wor Standards- Calibration of Meters- Qualities of Measurem		13%
	Accuracy, precision, sensitivity, resolution, loading effe		
		ci	
	Characteristics - Errors in Measurement and its Analysis		
т	Econticle of indicating instruments deflecting 1	ning 7	150/
II	Essentials of indicating instruments- deflecting, dam		15%
	controlling torques- Moving Coil, Moving Iron, Dyr		
	Meter, Induction, Thermal, Electrostatic and Rectifier	• •	
	meter; Shunts and Multipliers-Various Types	of	
	Galvanometers- Accuracy class.		
	FIRST INTERNAL EXAMINATION		
III	DC Bridges: Introduction, sources & detectors for DC bridges	dge. 7	15%

	•		
	general equation for bridge at balance. Wheatstone and		
	Kelvin's double bridge, Carry Foster Slide Wire Bridge –		
	Bridge Current Limitations.		
IV	AC bridges: Introduction, sources & detectors for a.c bridge, general equation for bridge at balance. Maxwell's Inductance & Maxwell's Inductance-Capacitance Bridge, Anderson bridge, Measurements of capacitance using Schering Bridge. Potentiometers: General principle, Modern forms of dc	8	15%
	potentiometers, standardization, Vernier dial principle, AC potentiometers – coordinate and polar types, application of dc and ac potentiometers	M	
	SECOND INTERNAL EXAMINATION	4	
V	Cathode ray oscilloscope (review), Special purpose oscilloscopes- delayed time base, analog storage, sampling oscilloscopes.	7	20%
	Digital storage oscilloscopes-DSO applications. Method of measuring voltage, current, phase, frequency and period using CRO, DSO. Graphic Recording Instruments: strip chart recorder, X-Y recorder, Plotter, liquid crystal display (LCD).		
VI	Waveform analysing instruments: Distortion meter, Spectrum analyser, Digital spectrum analyser, Q meter, Watthour meter, Power-factor meter, Instrument transformers, Thermocouple	7	20%
	instruments, Peak response voltmeter, True RMS meter		
	END SEMESTER EXAMINATION		

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)

Course	Course name	P- 1	Year of
code	Credi	ts Int	roduction
AE304	INDUSTRIAL INSTRUMENTATION 3-0-0-	3	2016
Prerequi	isite : Nil		
Course (Dbjective		
• T	o equip the students with the basic knowledge of Pressure, Te	mperature,	flow, level,
D	ensity and viscosity measurements.	-	
• T	o understand the construction and working of measuring instr	ruments	
Syllabus		AAA	
Tempera	ture measurement- Pressure measurement- Measuremen	t of visco	osity- Flow
measurer	nent- Anemometers- Target flow meters- Level measurement	LA L	-
	l outcome	AL	
- T	he students will be able to		
	i. grasp the working of different types of instruments for	measuremen	nt of
	mechanical quantities		
	ii. choose appropriate instruments for measurement of me	chanical qu	antities
Text Boo			
1. D	oebelin E.O, "Measurement Systems: Application and Design	ı", 4th Editi	on,
Ν	IcGraw Hill, New York, 2003.		
2. P	atranabis D, "Principles of Industrial Instrumentation", 2ndE	dition, Tata	McGraw
Н	lill, New Delhi, 1997.		
3. S	pitzer D. W., Flow measurement, ISA press, New York, 1998	3	
1. A	ce Books Indrew W.G, "Applied Instrumentation in Process Industries Fol II. Gulf Publishing Company, Houston, 2001	– A survey"	, Vol I &
1. A V 2. D E 3. L C 4. N	ndrew W.G, "Applied Instrumentation in Process Industries fol II, Gulf Publishing Company, Houston, 2001. ouglas M. Considine, "Process / Industrial Instruments & Co dition, McGraw Hill, Singapore, 1999. iptak B.G, "Process Measurement and Analysis", 4th Edition ompany, Radnor, Pennsylvania, 2003. foltingk B.E., "Instrumentation Reference Book", 2ndEdition	ontrols Hand	<i>dbook"</i> , 5th ook
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1. A V 2. D E 3. L C 4. N H Module	Indrew W.G, "Applied Instrumentation in Process Industries fol II, Gulf Publishing Company, Houston, 2001. Douglas M. Considine, "Process / Industrial Instruments & Con- dition, McGraw Hill, Singapore, 1999. iptak B.G, "Process Measurement and Analysis", 4th Edition ompany, Radnor, Pennsylvania, 2003. foltingk B.E., "Instrumentation Reference Book", 2ndEdition feinemann, 1995. Course Plan Contents Temperature measurement: Resistance temperature detect (RTD), principle and types, construction requirements to industry, measuring circuits. Thermistors, principle a sensor types, manufacturing techniques, measuring circuit linearization methods and applications. Pneumatic a suction pyrometers, integrated circuit sensors, diode ty	ontrols Hand , Chilton Bo , Butterwort , Butterwort Hours tor 7 for nd ts, nd pe	<i>dbook</i> ", 5th ook th Semester Exam Marks
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1. A V 2. D E 3. L C 4. N H Module	ndrew W.G, "Applied Instrumentation in Process Industries fol II, Gulf Publishing Company, Houston, 2001. oouglas M. Considine, "Process / Industrial Instruments & Co dition, McGraw Hill, Singapore, 1999. iptak B.G, "Process Measurement and Analysis", 4th Edition ompany, Radnor, Pennsylvania, 2003. foltingk B.E., "Instrumentation Reference Book", 2ndEdition teinemann, 1995. Course Plan Contents Temperature measurement: Resistance temperature detect (RTD), principle and types, construction requirements in industry, measuring circuits. Thermistors, principle a sensor types, manufacturing techniques, measuring circuit linearization methods and applications. Pneumatic a suction pyrometers, integrated circuit sensors, diode ty sensors, ultrasonic thermometers, Johnson no thermometer, fluidic sensors, spectroscopic temperature	ontrols Hand , Chilton Bo , Butterwort , Butterwort Hours tor 7 for nd ts, nd pe ise	<i>dbook</i> ", 5th ook th Semester Exam Marks
1. A V 2. D E 3. L C 4. N H Module	ndrew W.G, "Applied Instrumentation in Process Industries fol II, Gulf Publishing Company, Houston, 2001. oouglas M. Considine, "Process / Industrial Instruments & Co dition, McGraw Hill, Singapore, 1999. iptak B.G, "Process Measurement and Analysis", 4th Edition ompany, Radnor, Pennsylvania, 2003. foltingk B.E., "Instrumentation Reference Book", 2ndEdition teinemann, 1995. Course Plan Contents Temperature measurement: Resistance temperature detect (RTD), principle and types, construction requirements findustry, measuring circuits. Thermistors, principle a sensor types, manufacturing techniques, measuring circuit linearization methods and applications. Pneumatic a suction pyrometers, integrated circuit sensors, diode ty sensors, ultrasonic thermometers, Johnson no thermometer, fluidic sensors, spectroscopic temperature	ontrols Hand , Chilton Bo , Butterword Hours tor 7 for nd ts, nd pe ise ure	<i>dbook</i> ", 5th ook th Semester Exam Marks
1. A V 2. D E 3. L C 4. N H Module	Indrew W.G, "Applied Instrumentation in Process Industries fol II, Gulf Publishing Company, Houston, 2001. Douglas M. Considine, "Process / Industrial Instruments & Co dition, McGraw Hill, Singapore, 1999. iptak B.G, "Process Measurement and Analysis", 4th Edition ompany, Radnor, Pennsylvania, 2003. foltingk B.E., "Instrumentation Reference Book", 2ndEdition leinemann, 1995. Course Plan Contents Temperature measurement: Resistance temperature detect (RTD), principle and types, construction requirements for industry, measuring circuits. Thermistors, principle a sensor types, manufacturing techniques, measuring circuit linearization methods and applications. Pneumatic a suction pyrometers, integrated circuit sensors, diode ty sensors, ultrasonic thermometers, Johnson no thermometer, fluidic sensors, spectroscopic temperature measurements, thermograph, temperature switches a	ontrols Hand , Chilton Bo , Butterword Hours tor 7 for 7 for 7 for 1 for	<i>dbook</i> ", 5th ook th Semester Exam Marks
1. A V 2. D E 3. L C 4. N H Module	ndrew W.G, "Applied Instrumentation in Process Industries fol II, Gulf Publishing Company, Houston, 2001. Pouglas M. Considine, "Process / Industrial Instruments & Co dition, McGraw Hill, Singapore, 1999. iptak B.G, "Process Measurement and Analysis", 4th Edition ompany, Radnor, Pennsylvania, 2003. foltingk B.E., "Instrumentation Reference Book", 2ndEdition teinemann, 1995. Course Plan Contents Temperature measurement: Resistance temperature detect (RTD), principle and types, construction requirements industry, measuring circuits. Thermistors, principle a sensor types, manufacturing techniques, measuring circui linearization methods and applications. Pneumatic a suction pyrometers, integrated circuit sensors, diode ty sensors, ultrasonic thermometers, Johnson no thermometer, fluidic sensors, spectroscopic temperature measurements, thermograph, temperature switches a thermostats.	ontrols Hand , Chilton Bo , Butterword Hours tor 7 for 7 for 7 nd ts, 1 nd pe ise 1 ise 1	dbook", 5th ook th Semester Exam Marks 15%
1. A V 2. D E 3. L C 4. N H Module	ndrew W.G, "Applied Instrumentation in Process Industries of II, Gulf Publishing Company, Houston, 2001. Douglas M. Considine, "Process / Industrial Instruments & Co dition, McGraw Hill, Singapore, 1999. iptak B.G, "Process Measurement and Analysis", 4th Edition ompany, Radnor, Pennsylvania, 2003. foltingk B.E., "Instrumentation Reference Book", 2ndEdition leinemann, 1995. Course Plan Contents Temperature measurement: Resistance temperature detect (RTD), principle and types, construction requirements in industry, measuring circuits. Thermistors, principle a sensor types, manufacturing techniques, measuring circuit linearization methods and applications. Pneumatic a suction pyrometers, integrated circuit sensors, diode ty sensors, ultrasonic thermometers, Johnson no thermometer, fluidic sensors, spectroscopic temperature measurements, thermograph, temperature switches a thermostats. Pressure measurement basics, mechanical type instrument	ontrols Hand , Chilton Bo , Butterword Hours tor 7 for 7 for 7 for 1 for	dbook", 5th ook th Semester Exam Marks 15%

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	transmitter-force balance type, torque balance type, two wire and four wire transmitters, I/P and P/I converters.		
	FIRST INTERNAL EXAMINATION		
III	Measurement of viscosity: definitions, units, Newtonian and Newtonian behaviour, measurement of viscosity using laboratory viscometers, industrial viscometers. Viscometer selection and application. Measurement of density, definitions, units, liquid density measurement, gas densitometers, its application and selection.	7	15%
IV	Flow measurement: Introduction, definitions and units, classification of flow meters, pitot tubes, positive displacement liquid meters and provers, positive displacement gas flow meters, variable area flow meters.	6	15%
	SECOND INTERNAL EXAMINATION		
V	Anemometers: Hot wire/hot film anemometer, laser Doppler anemometer (LDA), electromagnetic flow meter, turbine and other rotary element flow meters, ultrasonic flow meters, doppler flow meters, cross correlation flow meters, vortex flow meters. Measurement of mass flow rate: radiation, angular momentum, impeller, turbine, constant torque hysteresis clutch, twin turbine Coriolis, gyroscopic and heat transfer type mass flow meters. Target flow meters: V-cone flow meters purge flow regulators, flow switches, flow meter calibration concepts, flow meter selection and application.	8	20%
VI	Level measurement: introduction, float level devices, displacer level devices, rotating paddle switches, diaphragm and deferential pressure detectors, resistance, capacitance and RF probes, radiation, conductivity, field effect, thermal, ultrasonic, microwave level switches, radar and vibrating type level sensors. Level sensor selection and application.	7	20%
	END SEMESTER EXAMINATION	7	•
OUEST	TION PAPER PATTERN:		

Exam Duration: 3 Hours

Maximum Marks:100

Part A

Part B

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course code	Course name	L-T-P- Credits	Yea Introd	
AE305	MICROPROCESSORS MICROCONTROLLEI	5_0_0_5	20	16
Prerequi	site: Nil			
Course C	Dbjective			
• To	expose the features of advanced micr	oprocessors like 8086, 80	386, and Pe	entium
1	ocessors			
	o introduce the architecture, programmi	ng, and interfacing of the	microcontr	oller
Syllabus	TECLINIO	I OCICI	1.1	
	6 - Assembler directives and operato			
	tion - Memory (RAM and ROM) inte			
	tion - Introduction to 80386 - Super-	scalar architecture - 805	I Microcor	troller -
	Language programming in 8051.			
-	l outcome d of the semester students will be			
	miliar with microprocessors and micro	ontrollorg		
	ble to study the processor architecture, a		ry manager	nent
	terfacing etc.	issembly language, memo	i y managei	iiciit,
Text Boo				
	K Ray and K M Bhurchandi, , Advanc	ed Microprocessors and P	eripherals.	Tata
	cGraw Hill, 2006	- 0 6 0 6	1 ,	
	V Hall, Microprocessors and Interfact	ing: Programming and Ha	rdware, 2n	d ed.,
Ta	ata McGraw Hill, 1999.			
3. M	A Mazidi and J. G. Mazidi, The 80 <mark>5</mark> 1	Microcontroller and Emb	bedded Sys	tems,
	earson Education, Delhi, 2004			
	amani Kalpathi and Ganesh Raja, Micro	ocontrollers and Applicati	ons, Pearso	n
Ec	ducation, 2010			
D	D 1			
Referenc	e Books Brey, The Intel Microprocessors, 8086	0000 00106 00006 000	96 and 904	06
	chitecture, Programming and interfacin	and the second		
	003	g, our eu., Frenuce man o	i iliula, Ne	w Denn,
	J Ayala, The 8051 Microcontroller- Are	chitecture Programming	and applica	tions
	nomson Delmar Publishers Inc., India r		ina appnea	
	C Liu and G A Gibson, Microcomputer		family, 2nd	ed.,
	entice Hall of India, New Delhi, 1986	4	J ,	,
	Course	Plan		
		e 1		Sem.
Module	Contents		Hours	Exam
				Marks
Ι	Intel 8086, format:, Assembler dire	1		15%
	Assembly process, Linking and reloc	ation, stacks, procedures,		
	interrupt routines, macros.			4 11
II	8086 hardware design - Bus struc			15%
	latching, system bus timing with	-		
	maximum mode configurations of	· · ·		
	configuration, 8087 co-process			
	configuration, Memory (RAM and R	Jwi) mierracing, memory		

address decoding.		
FIRST INTERNAL EXAMINATION		
8087 co-processor architecture and configuration, Memory (RAM and ROM) interfacing, memory address decoding	6	15%
Introduction to 80386 – Memory management unit – Descriptors, selectors, description tables and TSS – Real and protected mode – Memory paging – Pentium processor -Special features of the Pentium processor – Branch prediction logic– Superscalar architecture, microprocessors - state of the art	7	15%
SECOND INTERNAL EXAMINATION		
8051 Microcontroller: Overview of 8051 family, architecture of 8051, Program counter, ROM space in 8051, data types and directives, flags and PSW register, register bank and stack, Addressing modes. Instruction set Arithmetic instructions JUMP, LOOP,CALL instructions, time delay generations.	7	20%
Assembly Language programming in 8051 (some simple programs): programs using arithmetic and logic instructions, single bit instructions and programs, Timer/counter programming, 8051 serial communication programming, programming timer interrupts. Interfacing with Stepper motor,	7	20%
	FIRST INTERNAL EXAMINATION 8087 co-processor architecture and configuration, Memory (RAM and ROM) interfacing, memory address decoding Introduction to 80386 – Memory management unit – Descriptors, selectors, description tables and TSS – Real and protected mode – Memory paging – Pentium processor -Special features of the Pentium processor – Branch prediction logic–Superscalar architecture, microprocessors - state of the art SECOND INTERNAL EXAMINATION 8051 Microcontroller: Overview of 8051 family, architecture of 8051, Program counter, ROM space in 8051, data types and directives, flags and PSW register, register bank and stack, Addressing modes. Instruction set Arithmetic instructions JUMP, LOOP,CALL instructions, time delay generations. Assembly Language programming in 8051 (some simple programs): programs using arithmetic and logic instructions, single bit instructions and programs, Timer/counter programming, 8051 serial communication programming,	FIRST INTERNAL EXAMINATION 8087 co-processor architecture and configuration, Memory (RAM and ROM) interfacing, memory address decoding Introduction to 80386 – Memory management unit – 7 Descriptors, selectors, description tables and TSS – Real and protected mode – Memory paging – Pentium processor -Special features of the Pentium processor – Branch prediction logic–Superscalar architecture, microprocessors - state of the art 7 SECOND INTERNAL EXAMINATION 8051 Microcontroller: Overview of 8051 family, architecture of 8051, Program counter, ROM space in 8051, data types and directives, flags and PSW register, register bank and stack, Addressing modes. Instruction set Arithmetic instructions JUMP, LOOP, CALL instructions, time delay generations. 7 Assembly Language programming in 8051 (some simple programs): programs using arithmetic and logic instructions, single bit instructions and programs, Timer/counter programming, 8051 serial communication programming, 7

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

Estd.

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

2014

(15 x 2 = 30 marks)

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course	Course name L-T-P-	Y	ear Of
code	Credits	Intr	oduction
AE306	Digital Signal Processing 3-0-0-3		2016
Prerequi	isite : Nil		
Course (Dbjective		
• T	o introduce the basic concepts and techniques for processing s	ignals on a	Computer.
Syllabus			
	time and digital signals- DFT and the FFT- Z-transform- FIR I	Filters- IIR	Filters-
	alization- Computer architectures for signal processing.	NA A	
-	l outcome	TAT	
	The students will be familiar with the most important methods i		•
	ligital filter design, transform-domain processing and importan	ce of Signa	al
	rocessors.		
Text Boo		E:14 D	
	hen, C.T., "Digital Signal Processing: Spectral Computation & xford Univ. Press, 2001	x ritter De	esign,
	eachor, E.C., & Jervis, B.W., "Digital Signal Processing: A Processing	ractical An	proach"
	eachor, E.C., & Jervis, B.W., Digital Signal Processing. A Pr	испсиі Ар	prouch,
	roakis, J.G. & Manolakis, D.G., "Digital Signal Processing: Pi	rinciples. A	Algorithms.
	Applications", 3/e Prentice Hall of India, 1996.		
Referenc	e Books:		
	ee Books: mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign	al Process	sing", 2/e,
1. Er Pr	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, <mark>1</mark> 999.		0
1. Er Pr	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign		0
1. En Pr 2. M Aj	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998	Multimedi	a
1. En Pr 2. M <i>Ap</i> 3. M	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App	Multimedi	a
1. En Pr 2. M <i>Ap</i> 3. M	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App fill, NY, 1998	Multimedi	a
1. En Pr 2. M <i>Ap</i> 3. M	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App	Multimedi	a IcGraw
1. En Pn 2. M <i>Aj</i> 3. M H	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App fill, NY, 1998 Course Plan	Multimedia proach", M	a IcGraw Semester
1. En Pr 2. M <i>Ap</i> 3. M	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App fill, NY, 1998	Multimedi	a IcGraw Semester Exam
1. En Ph 2. M Aj 3. M H Module	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App fill, NY, 1998 Course Plan	Multimedia proach", M <mark>Hou</mark> rs	a lcGraw Semester Exam Marks
1. En Pn 2. M <i>Aj</i> 3. M H	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App ill, NY, 1998 Course Plan Signal Processing Fundamentals: Discrete-time and digital	Multimedia proach", M <mark>Hou</mark> rs	a IcGraw Semester Exam
1. En Ph 2. M Aj 3. M H Module	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 fitra, S.K., "Digital Signal Processing: A Computer-Based App fill, NY, 1998 Course Plan Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency	Multimedia proach", M <mark>Hou</mark> rs	a lcGraw Semester Exam Marks
1. En Ph 2. M Aj 3. M H Module	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App ill, NY, 1998 Course Plan Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters.	Multimedia proach", M <mark>Hou</mark> rs	a lcGraw Semester Exam Marks
1. En Ph 2. M Aj 3. M H Module	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App ill, NY, 1998 Course Plan Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters. Discrete Time Fourier transform and frequency spectra,	Multimedia proach", M <mark>Hou</mark> rs	a lcGraw Semester Exam Marks
1. En Ph 2. M Aj 3. M H Module	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 fitra, S.K., "Digital Signal Processing: A Computer-Based App ill, NY, 1998 Course Plan Contents Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters. Discrete Time Fourier transform and frequency spectra, Spectral computation, Computational complexity of the	Multimedia proach", M <mark>Hou</mark> rs	a lcGraw Semester Exam Marks
1. En Ph 2. M Aj 3. M H Module	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 fitra, S.K., "Digital Signal Processing: A Computer-Based App fill, NY, 1998 Course Plan Contents Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters. Discrete Time Fourier transform and frequency spectra, Spectral computation, Computational complexity of the DFT and the FFT, Algorithmic development and	Multimedia proach", M <mark>Hou</mark> rs	a lcGraw Semester Exam Marks
1. En Ph 2. M Aj 3. M H Module	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 fitra, S.K., "Digital Signal Processing: A Computer-Based App fill, NY, 1998 Course Plan Contents Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters. Discrete Time Fourier transform and frequency spectra, Spectral computation, Computational complexity of the DFT and the FFT, Algorithmic development and computational advantages of the FFT, Inverse FFT,	Multimedia proach", M <mark>Hou</mark> rs	a lcGraw Semester Exam Marks
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1. En Ph 2. M Aj 3. M H Module I	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 litra, S.K., "Digital Signal Processing: A Computer-Based App ill, NY, 1998 Course Plan Contents Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters. Discrete Time Fourier transform and frequency spectra, Spectral computation, Computational complexity of the DFT and the FFT, Algorithmic development and computational advantages of the FFT, Inverse FFT, Implementation of the FFT, Correlation of discrete-time signals.	Multimedia proach", M Hours 7	a IcGraw Semester Exam Marks 15%
1. En Ph 2. M Aj 3. M H Module	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 fitra, S.K., "Digital Signal Processing: A Computer-Based App fill, NY, 1998 Course Plan Contents Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters. Discrete Time Fourier transform and frequency spectra, Spectral computation, Computational complexity of the DFT and the FFT, Algorithmic development and computational advantages of the FFT, Inverse FFT, Implementation of the FFT, Correlation of discrete-time signals. Discrete-time systems, Difference equations and the Z-	Multimedia proach", M <mark>Hou</mark> rs	a lcGraw Semester Exam Marks
1. En Pn 2. M Aj 3. M H Module I	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App ill, NY, 1998 Course Plan Contents Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters. Discrete Time Fourier transform and frequency spectra, Spectral computation, Computational complexity of the DFT and the FFT, Algorithmic development and computational advantages of the FFT, Inverse FFT, Implementation of the FFT, Correlation of discrete-time signals. Discrete-time systems, Difference equations and the Z- transform, Analysis of discrete-time LTIL systems, Stability	Multimedia proach", M Hours 7	a IcGraw Semester Exam Marks 15%
1. En Pn 2. M Aj 3. M H Module I	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 fitra, S.K., "Digital Signal Processing: A Computer-Based App ill, NY, 1998 Course Plan Contents Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters. Discrete Time Fourier transform and frequency spectra, Spectral computation, Computational complexity of the DFT and the FFT, Algorithmic development and computational advantages of the FFT, Inverse FFT, Implementation of the FFT, Correlation of discrete-time signals. Discrete-time systems, Difference equations and the Z- transform, Analysis of discrete-time LTIL systems, Stability and Jury's test.	Multimedia proach", M Hours 7	a IcGraw Semester Exam Marks 15%
1. En Pn 2. M Aj 3. M H Module I	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App ill, NY, 1998 Course Plan Contents Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters. Discrete Time Fourier transform and frequency spectra, Spectral computation, Computational complexity of the DFT and the FFT, Algorithmic development and computational advantages of the FFT, Inverse FFT, Implementation of the FFT, Correlation of discrete-time signals. Discrete-time systems, Difference equations and the Z- transform, Analysis of discrete-time LTIL systems, Stability and Jury's test. FIRST INTERNAL EXAMINATION	Multimedia proach", M Hours 7 6	a IcGraw Semester Exam Marks 15%
1. En Pn 2. M Aj 3. M H Module I	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App ill, NY, 1998 Course Plan Contents Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters. Discrete Time Fourier transform and frequency spectra, Spectral computation, Computational complexity of the DFT and the FFT, Algorithmic development and computational advantages of the FFT, Inverse FFT, Implementation of the FFT, Correlation of discrete-time signals. Discrete-time systems, Difference equations and the Z- transform, Analysis of discrete-time LTIL systems, Stability and Jury's test. FIRST INTERNAL EXAMINATION FIR Filters: Ideal digital filters, Realizability and filter	Multimedia proach", M Hours 7	a IcGraw Semester Exam Marks 15%
1. En Pn 2. M Aj 3. M H Module I	mbree, P.M., & Danieli, D., "C++ Algorithms for Digital Sign rentice Hall Upper Saddle River, NJ, 1999. IcClellan, J.H., Schafer, R.W., & Yoder, M.A., "DSP First: A pproach", Prentice Hall Upper Saddle River, NJ, 1998 Iitra, S.K., "Digital Signal Processing: A Computer-Based App ill, NY, 1998 Course Plan Contents Signal Processing Fundamentals: Discrete-time and digital signals, A/D, D/A conversion and Nyquist rate, Frequency aliasing due to sampling, Need for anti-aliasing filters. Discrete Time Fourier transform and frequency spectra, Spectral computation, Computational complexity of the DFT and the FFT, Algorithmic development and computational advantages of the FFT, Inverse FFT, Implementation of the FFT, Correlation of discrete-time signals. Discrete-time systems, Difference equations and the Z- transform, Analysis of discrete-time LTIL systems, Stability and Jury's test. FIRST INTERNAL EXAMINATION	Multimedia proach", M Hours 7 6	a IcGraw Semester Exam Marks 15%

	Minimax optimal FIR filters, Design of digital differentiators and Hilbert transformers, comparison of		
	design methods.		
IV	IIR Filters: Design of analogue prototype filters, Analog	7	15%
	frequency transformations, Impulse invariance method and		
	digital frequency transformations, Bilinear transformation,		
	Analog prototype to digital transformations, Difficulties in		
	direct IIR filter design, Comparisons with FIR filters.		
	SECOND INTERNAL EXAMINATION	A A	
V	Filter Realization: Structures for FIR filters, Structures for	7	20%
	IIR filters, State-space analysis and filter structures, Fixed	A T	
	point and floating-point representation of numbers, Errors	AL	
	resulting from rounding and truncating, Quantization effects	1.1	
	of filter coefficients, Round-off effects of digital filters.		
VI	DSP Processors: Computer architectures for signal	8	20%
	processing – Harvard architecture and pipelining, General		
	purpose digital signal processors, Selection of DSPs,		
	Implementation of DSP algorithms on a general purpose		
	DSP, Special purpose hardware – hardware digital filters		
	and hardware FFT processors, Evaluation boards for real-		
	time DSP.		
	END SEMESTER EXAMINATION		

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

Estd.

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

2014

(15 x 2 = 30 marks)

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course	Course name	L-T-P-	Y	ear of
code		Credits	Inti	oduction
AE307	SIGNALS AND SYSTEMS	3-0-0-3		2016
Prerequi	site : Nil			
Course C	Dbjective			
• To	impart the basic concepts of continuous and discrete	signals and	d system	S
• To	develop understanding about frequency domain appro	oaches use	d for an	alysis of
	ntinuous and discrete time signals and systems.			5
	establish the importance of z-transform and its proper	rties for an	alyzing	discrete
	ne signals and systems	LA	IV I	
Syllabus	TICINIOLOO	IC	λ T	
•	on to signals and systems - Classification of signation	als - Prop	erties of	f systems -
	tation of LTI systems - Continuous & Discrete Tir			
	of LTI - Continuous Time Fourier Series - Discre			
	Transform – Causality and stability- Z Transform-			
-	from poles and zeros.			
_	outcome			
-	onts are expected to:			
	ave an advanced knowledge in continuous and discrete	e signals ai	1d syster	ns
	ave knowledge in z-transform	8	j	
Text Boo				
	aykin S. & Veen B.V., Signals & Systems, John Wiley			
	ppenheim A.V., Willsky A.S. & Nawab S.H., Signals a	nd System	s. Tata N	/IcGraw
Н			~,	
	ylor F.H., Principles of Signals & Systems, McGraw H	Fill		
	······································			
Referenc	es			
	cacewell R.N., Fourier Transform & Its Applications, 1	McGraw H	Iill	
	aykin S., Communication Systems, John Wiley			
	athi B.P., Modern Digital & Analog Communication Sy	stems, Ox	ford Un	iversity
	ess	,		2
4. Pa	apoulis A., <i>Fourier Integral & Its Applications</i> , McGra	w Hill		
	Course Plan		1	
Module	Contents]	Hours	Semester
				exam
				marks
Ι	Introduction to signals and systems - Classifica	tion of 7	7	15%
-	signals - Basic operations on signals – Elementary s			1070
	Concept of system - Properties of systems - S	-		
	invertability, time invariance - Linearity - Caus	•		
	Memory - Time domain description - Convolution - I			
	response.	inpuise		
	response.			
II	Representation of LTI systems - Differential equation	ion and (ń	15%
**	• • •	systems		1570
	,Continuous Time LTI systems and Convolution I			
	Discrete Time LTI systems and linear convolution.	incgrai,		
	FIRST INTERNAL EXAMINATIO	ON		
	FINDE INTERNAL EXAMINATION			

III	Frequency response of LTI systems - Correlation theory of deterministic signals - Condition for distortionless transmission through an LTI system - Transmission of a rectangular pulse through an ideal low pass filter - Hilbert transform – Sampling and reconstruction	8	15%
IV	Frequency Domain Representation of Continuous Time Signals- Continuous Time Fourier Series: Convergence. Continuous Time Fourier Transform: Properties. Frequency Domain Representation of Discrete Time Signals- Discrete Time Fourier Transform: Properties, Sampling Theorem, aliasing, reconstruction filter, sampling of band pass signals. Fourier Series Representation of Discrete Time Periodic Signals.	7 AL	15%
	SECOND INTERNAL EXAMINATION		
V	Laplace Transform – ROC – Inverse transform – properties – Analysis of Continuous LTI systems using Laplace Transform – unilateral Laplace Transform. Relation between Fourier and Laplace Transforms. Laplace transform analysis of systems - Relation between the transfer function and differential equation - Causality and stability - Inverse system - Determining the frequency response from poles and zeros	7	20%
VI	convergence - Properties of the Z transform - Analysis of LTI systems - Relating the transfer function and difference equation - Stability and causality - Inverse systems - Determining the frequency response from poles and zeros	7	20%
	END SEMESTER EXAMINATION		

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Exam Duration: 3 Hours

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

	Course name		Year of
code	Credit		roduction
AE308	ADVANCED MICROPROCESSORS 3-0-0-3	•	2016
-	site: AE305 Microprocessors & microcontrollers		
Course (•		
	familiarise the importance and applications of advance micro	processor	
	o understand architecture of ARM processor		
	o understand instruction set of ARM processor		
Syllabus		M	
	advance microprocessors- RISC and CISC- ARM Architectu		
	ARM Instruction set- C Programming for ARM- Memory	manager	nent units-
	Microprocessor Bus Architecture.		
-	outcome	1	
	ne students will have good idea about ARM processor and its ap	plication.	
Text Boo		<i>.</i>	G . 1
	ndrew N. Sloss, Dominic Symes, Chris Wright ARM System De	eveloper's	Guide,
	esigning and Optimizing System Software, Elsevier	0 4 1.	
	uhammad Ali Mazidi, ARM Assembly Language Programming indle edition	g & Archi	tecture,
		200000 011	hlipption
	eve Furber ARM System-on-chip Architecture, 2nd Edition, , P	-	
	Villiam Hohl and Christopher Hinds, <i>ARM Assembly Language</i> , <i>echniques</i> , 2nd edition, CRC Press.	r unaame.	ntais ana
1	conniques, 2nd edition, CKC Fless.		
Reference	a Baaka		
	ouglas V.Hall, " <i>Microprocessors and Interfacing</i> ", Tata McGra		Edition
	006	aw 11111, 11	Lantion
		Rased Sv	stom
	ohamed Rafiquzzaman, "Microproce <mark>s</mark> sors and Microcomputer	Based Sy.	stem
D	ohamed Rafiquzzaman, " <i>Microprocessors and Microcomputer</i> esign", II Edition, CRC Press, 2007	Based Sy.	stem
	ohamed Rafiquzzaman, "Microproce <mark>s</mark> sors and Microcomputer	Based Sy.	
	Cohamed Rafiquzzaman, " <i>Microprocessors and Microcomputer</i> esign", II Edition, CRC Press, 2007 Course Plan		Semester
Module	ohamed Rafiquzzaman, " <i>Microprocessors and Microcomputer</i> esign", II Edition, CRC Press, 2007	Based Sy.	Semester Exam
Module	Contents	Hours	Semester Exam Marks
	Contents Introduction: Need of advance microprocessors, Difference	Hours 7	Semester Exam
Module	Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM	Hours 7	Semester Exam Marks
Module	Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM	Hours 7	Semester Exam Marks
Module	Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM	Hours 7	Semester Exam Marks
Module	Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM processor family, Development of ARM architecture.	Hours 7	Semester Exam Marks
Module I	Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM processor family, Development of ARM architecture. The ARM Architecture and Programmers Model : The Acorn	Hours 7 7	Semester Exam Marks 15%
Module I	Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM processor family, Development of ARM architecture. The ARM Architecture and Programmers Model : The Acorn RISC Machine, ARM Core data flow model, Architectural	Hours 7 7	Semester Exam Marks 15%
Module I	Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM processor family, Development of ARM architecture. The ARM Architecture and Programmers Model : The Acorn RISC Machine, ARM Core data flow model, Architectural inheritance, The ARM7TDMI programmer's model: General	Hours 7 7	Semester Exam Marks 15%
Module I	Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM processor family, Development of ARM architecture. The ARM Architecture and Programmers Model : The Acorn RISC Machine, ARM Core data flow model, Architectural	Hours 7 7	Semester Exam Marks 15%
Module I	Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM processor family, Development of ARM architecture. The ARM Architecture and Programmers Model : The Acorn RISC Machine, ARM Core data flow model, Architectural inheritance, The ARM7TDMI programmer's model: General purpose registers, CPSR, SPSR, ARM memory map, data	Hours 7 7	Semester Exam Marks 15%
Module I	Cohamed Rafiquzzaman, "Microprocessors and Microcomputer esign", II Edition, CRC Press, 2007 Course Plan Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM processor family, Development of ARM architecture. The ARM Architecture and Programmers Model : The Acorn RISC Machine, ARM Core data flow model, Architectural inheritance, The ARM7TDMI programmer's model: General purpose registers, CPSR, SPSR, ARM memory map, data format, load and store Architecture, Core extensions,	Hours 7 7	Semester Exam Marks 15%
Module I	Cohamed Rafiquzzaman, "Microprocessors and Microcomputer esign", II Edition, CRC Press, 2007 Course Plan Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM processor family, Development of ARM architecture. The ARM Architecture and Programmers Model : The Acorn RISC Machine, ARM Core data flow model, Architectural inheritance, The ARM7TDMI programmer's model: General purpose registers, CPSR, SPSR, ARM memory map, data format, load and store Architecture, Core extensions,	Hours 7 7	Semester Exam Marks 15%
Module I	Cohamed Rafiquzzaman, "Microprocessors and Microcomputer esign", II Edition, CRC Press, 2007 Course Plan Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM processor family, Development of ARM architecture. The ARM Architecture and Programmers Model : The Acorn RISC Machine, ARM Core data flow model, Architectural inheritance, The ARM7TDMI programmer's model: General purpose registers, CPSR, SPSR, ARM memory map, data format, load and store Architecture, Core extensions, Architecture revisions, ARM development tool.	Hours 7 7 7	Semester Exam Marks 15%
Module I II	ohamed Rafiquzzaman, "Microprocessors and Microcomputer esign", II Edition, CRC Press, 2007 Course Plan Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM processor family, Development of ARM architecture. The ARM Architecture and Programmers Model : The Acorn RISC Machine, ARM Core data flow model, Architectural inheritance, The ARM7TDMI programmer's model: General purpose registers, CPSR, SPSR, ARM memory map, data format, load and store Architecture, Core extensions, Architecture revisions, ARM development tool. FIRST INTERNAL EXAMINATION ARM Instruction set: Data processing instructions,	Hours 7 7 7 8	Semester Exam Marks 15%
Module I II	Cohamed Rafiquzzaman, "Microprocessors and Microcomputer esign", II Edition, CRC Press, 2007 Course Plan Contents Introduction: Need of advance microprocessors, Difference between RISC and CISC, RISC Design philosophy, ARM Design Philosophy, History of ARM microprocessor, ARM processor family, Development of ARM architecture. The ARM Architecture and Programmers Model : The Acorn RISC Machine, ARM Core data flow model, Architectural inheritance, The ARM7TDMI programmer's model: General purpose registers, CPSR, SPSR, ARM memory map, data format, load and store Architecture, Core extensions, Architecture revisions, ARM development tool.	Hours 7 7 7 8	Semester Exam Marks 15%

	Conditional execution, Multiple register load and store instructions, Stack instructions, Thumb instruction set, advantage of thumb instructions, Assembler rules and directives, Assembly language programs for shifting of data, factorial calculation, swapping register contents, moving values between integer and floating point registers		
IV	C Programming for ARM: Overview of C compiler and optimization, Basic C data types, C Looping structures, Register allocations, function calls, pointer aliasing, structure arrangement, bit fields, unaligned data and Endianness, Division, floating point, Inline functions and inline assembly, Portability issues. C programs for General purpose I/O, general purpose timer, PWM Modulator, UART, I2C Interface, SPI Interface, ADC, DAC.	7 M AL	15%
	SECOND INTERNAL EXAMINATION		
V	Memory management units: Moving from memory protection unit (MPU) to memory management unit (MMU), Working of virtual memory, Multitasking, Memory organization in virtual memory system, Page tables, Translation look aside buffer, Caches and write Buffer, Fast context switch extension.	7	20%
VI	Advanced Microprocessor Bus Architecture (AMBA) Bus System, User peripherals, Exception handling in ARM, ARM optimization Techniques.	6	20%
	END SEMESTER EXAMINATION		

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

Estd.

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)

Exam Duration: 3 Hours

Course	Course name	L-T-P-		ear Of
code		Credits		oduction
AE312	POWER ELECTRONICS	3-0-0-3		2016
Prerequi				
Course C	0			
	o introduce various power semiconductor devices and	converter	rs used in	industrial
	oplications.			
Syllabus		DC	10	
	miconductor devices- Controlled rectifiers- DC chopp		AC conv	verters- DC
*	ower supplies- Advanced control of power electronic	circuits	1.1 1 1.	
-	l outcome t the end of the semester students will have idea regar	ding now	er semico	nductor
	evices, controlled rectifiers, DC chopper, DC to AC co			
	upplies and advanced control of power electronic circu		DC and F	
Text Boo		4103.		
	. H. Rashid, Power Electronics: Circuits, Device	s and Ar	oplication	s. 3rd ed.
	earson Education, Delhi, 2002		1	.,,
	. Mohan, T. M. Underland, and W. P. Robbins, F	Power Ele	ctronics:	Converter,
	oplications and Design, John Wiley & Sons, New Yor			,
3. P.	S. Bimbhra, Power Electronics, Khanna Publishers, I	New Delhi	i, 2002.	
Referenc	e Books			
	. K. Dubey, S. R. Doradla, A. Joshi and R. M. K. Sin	-		
Pe	ower Controllers, NewAge International Publishers, N	lew Delhi	, 1996	
	Cour <mark>se</mark> Plan			
Module	Contents		Hours	Semester Exam
-			_	Marks
Ι	Power semiconductor devices: Power diodes-types		7	15%
	transistors, thyristor family, SCRs, Triac, GTOs, MOSFETs, IGBTs, MCTs-static and o	alynamic		
	characteristics, protection circuits, series and	•		
	connections, turn-on characteristics, turn off character			
	Esto,			
II	Controlled rectifiers- single phase and three	phase	7	15%
	converters-power factor improvements-design of c	1		
	circuits-AC volt-age controllers-single phase an	d three		
	phase-cyclo converters-single phase and three phase	, design		
	of AC voltage controller circuits.2014			
	FIRST INTERNAL EXAMINATI	1		
III	DC choppers – principle of step down and		6	15%
	operations – step down chopper with RL load, Cl	asses of		
	chopper, MOSFET/IGBT choppers.			
TX 7		M	7	150/
IV	DC to AC converters: Thyristor inverters, Mc	-	7	15%
	McMurray Bedford inverter, current source inverter,	-		
	control waveform control, inverters using devices ot thyristors, vector control of induction motors.			

	SECOND INTERNAL EXAMINATION		
V	DC and AC power supplies: Switched mode, resonant, bi- directional and multistage conversions, buck, boost, buck boost regulators. UPS-block diagram, types. Drive requirements and design of simple drive circuits for power	9	20%
VI	BJT, MOSFET and IGBT.	6	20%
V I	Advanced control of power electronic circuits using microprocessors, microcontrollers, isolation amplifier circuits, synchronization circuits.	M	20%

END SEMESTER EXAMINATION

QUESTION PAPER PATTERN:

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Exam Duration: 3 Hours

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course code	Course name	L-T-P-Credits	Year of Introduction
AE331	MICROPROCESSORS &	0-0-3-1	2016
	MICROCONTROLLERS LAB		
Prerequisite :	AE305 Microprocessors & Microcontrolle	ers	
Course objecti	ives		
To write	e ALP for arithmetic and logical operation	s in 8086 and 8051	
 To diffe 	rentiate Serial and Parallel Interface		
• To inter	face different I/Os with Microprocessors		A
1	1 MDDOL	MLAN	1
List of Experim	ents (Out of 18 experiments minimum 12	experiments are com	pulsory)
-		AJU	•••
8086 Program	is using kits :	TTV	
1.Basic	arithmetic and Logical operations	Y I I Y	
2. Move	e a data block without overlap	1 L L	
3. Separ	rating Odd and Even numbers		
4. Code	conversion, decimal arithmetic and Matri	ix operations.	
5. Prog	ram for sorting an array		
6. Progi	ram for string manipulation		
7. Float	ing point operations and searching.		
Peripherals an	d Interfacing Experiments		
	per motor control.		
	l interface and Parallel interface		
	and D/A interface and Waveform Genera	tion	
	ents using kits :		
	ic arithmetic and Logical operations		
	are and Cube program, Find 2's complem	ent of a number	
	backed BCD to ASCII		
	gram to verify Timer/Counter in 8051		
	gram and verify interrupt handling in 8051		
	RT operation in 8051		
	munication between 8051 kit and PC		
18. Inte	rfacing LCD to 8051.		

2014

8086 and 8051.

Course code	Course name	L-T-P-	Year of
4 5 3 3 3		Credits	introduction
AE332	PROCESS CONTROL LAB AE302 Process control	0-0-3-1	2016
Course Object			
•	vide experience on control of various industr	ial processes u	sing different
	paradigms		C
• To prov applicat	vide experience in development of virtual institutions	strumentation s	systems for industry
	oduce few novel control strategies based on	artificial neura	ıl networks, fuzzy
logic, di	igital control algorithm, etc.	CIC.	A T
LIST OF EXP	ERIMENTS: (Minimum 12 experiments a	are to be done)	11.
1 .ON-0	OFF controller with and without neutral zone	e-level control	, flow control
2. Temp	perature control using P, PI, PD, and PID co	ntrollers-Stud	y of output response
3. Flow	control using P, PI, PD, and PID controllers	s-Study of out	put response
4. Li <mark>q</mark> ui	d level control using P, PI, PD, and PID cor	ntrollers–Study	of output response
5. Press	ure control using P, PI, PD, and PID control	llers–Study of	output response
6.Contr	ol valve characteristics		
7. Contr	roller tuning for various processes – using Z	iegler-Nichols	rule
8. Contr	roller tuning for various processes – using C	ohen and Coor	n rule
9.Contro	oller Tuning – Simulation		
10.Bloc	k diagram simulation of a com <mark>pl</mark> ex control s	system	
11Study	y of feed-forward, cascade, and ratio control	S	
12.Data	Logger		
13. PC	based control of robotic actions		
14. Sim	ulati <mark>on of Artificial</mark> Neural Networks –use a	any software	
15.Simu	ulation of Heat Exchanger Temperature Con	trol	
16. Inte	rface of DCS with PLC/SCADA using proto	ocol/fieldbus	
	2014		

Course code	Course name	L-T-P- Credits	Year of introduction
AE334	POWER ELECTRONICS LAB	0-0-3-1	2016
Prerequisite	:AE312 Power Electronics		I
Course Obje			
	niliarise the characteristics of power sem ovide experience on design, testing, and a		
	pose simulation of power electronic circ		
	Course Plan		$\Delta \Lambda \Lambda$
LIST OF EX	EXPERIMENTS: (Minimum 12 experime	ents are to be don	e)
1. SC	R characteristics)GIC	AL
2. Tri	ac and Diac characteristics	CITV	
3. Pha	ase controlled rectifier-resistance triggeri	ing ¹	
4. Pha	ase controlled rectifier- UJT triggering		
5. Ch	opper circuits		
6. MC	OSFET characteristics		
7. Sin	ple DC to AC inverter circuit		
8. Dri	ven DC to AC inverter using MOSFET a	& IC	
9. IGI	3T characteristics		
10. In	verter circuit using IGBT		
11. D	igital triggering circuit for phase controll	led rectifiers	
12. A	pplication of ICS: PWM IC TL 494, opto	ocoupler IC -MC	Г2Е
13. D	C motor speed control – Using digital log	gic circuits/micro	processor/PC
14. A	C motor speed control – Using digital log	gic circuits/micro	processor/PC
15. Si	mulation of power electronic converter a	and inverter circu	its using software like
MAT	LAB,PSPIC		
16. SO	CR turn-off circuits using (i) LC circuit (ii) Auxiliary Con	nmutation.
17. A	C voltage c <mark>ontroller using</mark> Triac – Diac c	combination.	
18. G	eneration of firing signals for Thyristor/1	<mark>Friac using</mark> digita	l Circuit/
Micro	processor.		

Course	Course name		Year of
code	Credits		roduction
AE361		3	2016
Prerequi			
Course o	bjectives		
• To	o review background information required for studying virtual in	strument	ation.
• To	o study the basic building blocks of virtual instrumentation.		
• Te	o study the various graphical programming environment in virtua	al instrun	nentation.
• To	o study few applications in virtual instrumentation.	NA	
Syllabus	ALL ADDUL MLA	TAT.	
-	of digital instrumentation - Fundamentals of virtual instru	rumentati	ion - VI
programm	ning techniques - Data acquisition - VI Chassis requirer	nents -	Graphical
	ning environment - Analysis tools and simple applications		
	loutcome		
	he students will gain knowledge in virtual instrumentation and so	ome of its	S
	oplications.		
Text Boo	* · · · · · · · · · · · · · · · · · · ·		
1. Pe	eter W. Gofton, 'Understanding Serial Communications', Sybex	Internatio	onal.
2. R	obert H. Bishop, 'Learning with Lab-view', Prentice Hall, 2003.		
3. S.	. Gupta and J.P Gupta, 'PC Interfacing for Data Acquisition and	Process (Control',
	strument society of America, 1994.		
Reference			
1. G		nming', I	McGraw
	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program	nming', I	McGraw
Н	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006.		
Н 2. К	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program		
H 2. K In	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for		
H 2. K In	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for strumentation and Control', Newness, 2000. OURCES: com		
H 2. K In WEB RES	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for strumentation and Control', Newness, 2000. OURCES:		rement,
H 2. K In WEB RES www.ni.c	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for astrumentation and Control', Newness, 2000. OURCES: com Course Plan	or Measur	rement, Semester
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H 2. K In WEB RES www.ni.c	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for strumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog	or Measur	rement, Semester Exam Marks
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H 2. K In WEB RES www.ni.c	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for astrumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in amplitude and time axes, sample and hold, sampling theorem,	or Measur	rement, Semester Exam Marks
H 2. K In WEB RES www.ni.c	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for astrumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in	or Measur	rement, Semester Exam Marks
H 2. K In WEB RES www.ni.c	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for astrumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in amplitude and time axes, sample and hold, sampling theorem, ADC and DAC.	or Measure Hours 6	rement, Semester Exam Marks 15%
H 2. K In WEB RES www.ni.c	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for astrumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in amplitude and time axes, sample and hold, sampling theorem, ADC and DAC. Virtual Instrumentation: Historical perspective - advantages -	or Measur	rement, Semester Exam Marks
H 2. K In WEB RES www.ni.c	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for strumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in amplitude and time axes, sample and hold, sampling theorem, ADC and DAC. Virtual Instrumentation: Historical perspective - advantages - block diagram and architecture of a virtual instrument -	or Measure Hours 6	rement, Semester Exam Marks 15%
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H 2. K In WEB RES www.ni.c	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for astrumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in amplitude and time axes, sample and hold, sampling theorem, ADC and DAC. Virtual Instrumentation: Historical perspective - advantages - block diagram and architecture of a virtual instrument - Conventional Instruments versus Traditional Instruments - data-flow techniques, graphical programming in data flow,	or Measure Hours 6	rement, Semester Exam Marks 15%
H 2. K In WEB RES www.ni.c	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for astrumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in amplitude and time axes, sample and hold, sampling theorem, ADC and DAC. Virtual Instrumentation: Historical perspective - advantages - block diagram and architecture of a virtual instrument - Conventional Instruments versus Traditional Instruments -	or Measure Hours 6	rement, Semester Exam Marks 15%
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H 2. K In WEB RES www.ni.c	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for istrumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in amplitude and time axes, sample and hold, sampling theorem, ADC and DAC. Virtual Instrumentation: Historical perspective - advantages - block diagram and architecture of a virtual instrument - Conventional Instruments versus Traditional Instruments - data-flow techniques, graphical programming in data flow, comparison with conventional programming.	or Measure Hours 6	rement, Semester Exam Marks 15%
H 2. K In WEB RES www.ni.c Module I I	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for instrumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in amplitude and time axes, sample and hold, sampling theorem, ADC and DAC. Virtual Instrumentation: Historical perspective - advantages - block diagram and architecture of a virtual instrument - Conventional Instruments versus Traditional Instruments - data-flow techniques, graphical programming in data flow, comparison with conventional programming. VI programming techniques: VIs and sub-VIs, loops and	or Measure Hours 6	rement, Semester Exam Marks 15%
H 2. K In WEB RES www.ni.c	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for instrumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in amplitude and time axes, sample and hold, sampling theorem, ADC and DAC. Virtual Instrumentation: Historical perspective - advantages - block diagram and architecture of a virtual instrument - Conventional Instruments versus Traditional Instruments - data-flow techniques, graphical programming in data flow, comparison with conventional programming. VI programming techniques: VIs and sub-VIs, loops and charts, arrays, clusters and graphs, case and sequence	or Measure Hours 6	rement, Semester Exam Marks 15%
H 2. K In WEB RES www.ni.c Module I I	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for istrumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in amplitude and time axes, sample and hold, sampling theorem, ADC and DAC. Virtual Instrumentation: Historical perspective - advantages - block diagram and architecture of a virtual instrument - Conventional Instruments versus Traditional Instruments - data-flow techniques, graphical programming in data flow, comparison with conventional programming. VI programming techniques: VIs and sub-VIs, loops and charts, arrays, clusters and graphs, case and sequence structures, formula nodes, local and global variables, State	or Measure Hours 6	rement, Semester Exam Marks 15%
H 2. K In WEB RES WWW.ni.c Module I I	ary W. Johnson, Richard Jennings, 'Lab-view Graphical Program ill Professional Publishing, 2006. evin James, 'PC Interfacing and Data Acquisition: Techniques for instrumentation and Control', Newness, 2000. OURCES: com Course Plan Contents Review of digital instrumentation: - Representation of analog signals in the digital domain – Review of quantization in amplitude and time axes, sample and hold, sampling theorem, ADC and DAC. Virtual Instrumentation: Historical perspective - advantages - block diagram and architecture of a virtual instrument - Conventional Instruments versus Traditional Instruments - data-flow techniques, graphical programming in data flow, comparison with conventional programming. VI programming techniques: VIs and sub-VIs, loops and charts, arrays, clusters and graphs, case and sequence	or Measure Hours 6	rement, Semester Exam Marks 15%

IV Data acquisition basics: Introduction to data acquisition on PC, Sampling fundamentals, Input/Output techniques and buses. ADC, DAC, Digital I/O, counters and timers, DMA, Software and hardware installation, Calibration, Resolution, Data acquisition interface requirements. 6 15% SECOND INTERNAL EXAMINATION VI Chassis requirements. Common Instrument Interfaces: 8 20% V Current loop, RS 232C/ RS485, GPIB. Bus Interfaces: USB, 8 20%
IV PC, Sampling fundamentals, Input/Output techniques and buses. ADC, DAC, Digital I/O, counters and timers, DMA, Software and hardware installation, Calibration, Resolution, Data acquisition interface requirements. Second INTERNAL EXAMINATION VI Chassis requirements. Common Instrument Interfaces: 8 20%
buses. ADC, DAC, Digital I/O, counters and timers, DMA, Software and hardware installation, Calibration, Resolution, Data acquisition interface requirements. SECOND INTERNAL EXAMINATION VI Chassis requirements. Common Instrument Interfaces: 8 20%
Software and hardware installation, Calibration, Resolution, Data acquisition interface requirements. Image: Composition of the second
Data acquisition interface requirements. Image: Composition of the second s
SECOND INTERNAL EXAMINATION VI Chassis requirements. Common Instrument Interfaces: 8 20%
VI Chassis requirements. Common Instrument Interfaces: 8 20%
VI Chassis requirements. Common Instrument Interfaces: 8 20%
V Current loop, RS 232C/ RS485, GPIB. Bus Interfaces: USB,
PCMCIA, VXI, SCSI, PCI, PXI, Firewire. PXI system
controllers, Ethernet control of PXI. Networking basics for
office & Industrial applications, VISA and IVI.
I INTIVED SITV
VI toolsets, Distributed I/O modules. Application of Virtual 8 20%
VI Instrumentation: Instrument Control, Development of process
database management system, Simulation of systems using
VI, Development of Control system, Industrial
Communication, Image acquisition and processing, Motion
control.
END SEMESTER EXAMINATION

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

-std

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(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)

Exam Duration: 3 Hours

Cours		L-T-P-	Year of
code		Credits	Introduction
AE36	2 INDUSTRIAL PSYCHOLOGY	3-0-0-3	2016
Prereq	uisite: Nil		
Course	e objectives		
•	To introduce major topics and sub-specialties including cr	itical theory	y and research
	findings that have served to define the field of Industrial /	Organizatio	onal (I/O)
	psychology		
•	To increase understanding of the complicated systems of it	individual a	nd group
	psychological processes involved in the world of work	LAI	V1
•	To connect the basic principles of I/O Psychology to Pers	onnel and H	luman Resources
	management within organizations	LA	
•	To allow participants to explore ways in which individual	career choi	ces and work-
	life success can be improved through the benefits of I/O F	sychology	
Syllab		14. T	
Introdu	ction to Industrial and Organizational Psychology – Leader	ership - Dev	velopment of
Human	Resources - Consumer Psychology - Decision making	-	-
	ted outcome		
After c	ompleting the course the students will be able to:		
i.	Demonstrate fundamental knowledge about need and sco	be of I/O Ps	ychology
ii.	Be aware of the brief history and various related fields of	I/O Psycho	logy
iii.	Learn about employee motivation, job satisfaction and lea	dership sty	les.
iv.	Understand the concept of organizational culture and learn	n the variou	s types and
	functions of organizational culture		
v.	Comprehend the concept of Job analysis and be aware about the concept of	out the varie	ous methods of
	Job analysis.		
vi.	Learn about the process of employee selection and unders	tand the var	rious methods of
	selection process with special emphasis on psychological	testing.	
vii.	Demonstrate knowledge about the processes of training and		
viii.	Understand the meaning of consumer behaviour and the d		
	the consumer. Level of Basic knowledge of psychological	concepts a	nd principles
Text B	ooks		
1.	Aswathappa K (2008) Human Resource Management (f	ifth edition), Tata McGraw
_	Hill		
2.	Blum & Naylor (1982) Industrial Psychology. Its theor	etical & so	cial foundations,
_	CBS Publications.		
3.	Singh N. (2011). Industrial Psychology. Tata McGraw hil	l Education	private limited.
	2014		
Refere	nces		
			1.4 1.40.1
1.	Aamodt.M G (2016) Industrial/Organizational Psycholog	y: An appli	ed Approach (8th
2	edition), Cengage Learning		TT'11
	Miner J B (1992) Industrial/Organizational Psychology. N		
3.	Robbins, S. P. (2010). Organizational behaviour. Tata Mcc		
4.	Schiffman, L G & Wisenblit, J. (2010). Consumer behavio		
5.	Schultz, D. P., & Schultz, E. S. (2008). Psychology and "	work today	. New York: Mac
	Milan publishing company.		

Module	Contents	Hours	Semester Exam Marks
I	Introduction to Industrial and Organizational Psychology: Introduction to industrial psychology, Definition, scope, major influences, goals, key forces, and fundamental concepts, History of industrial psychology, Major Fields of I/O Psychology, scientific management.	6	15%
П	Individual in Workplace : Motivation- Definition, Types, Theory-Maslow's and Herzberg, Job satisfaction- Definition, Factors affecting Job Satisfaction, Consequences, Leadership - Definition, Leadership Styles, Approaches to Leadership, Organizational Culture -Definition, Levels, Characteristics, Types, Functions		15%
	FIRST INTERNAL EXAMINATION		1
ш	Development of Human Resources: Job Analysis- Definition, Purpose, Types, Process, Methods, Recent Developments Recruitment and Selection- Nature and objectives, Sources- Internal and External, Process, Definition and steps in selection process Performance Management- Definition, Scope, Process, Tools Training and Development- Meaning and nature, Objectives, Methods- on the job and off the job	7	15%
IV	Introduction to Consumer Psychology: Definition, Scope, Marketing concept. Market Segmentation- consumer rooted, consumption specific, and brand experience as segmentation bases. Targeting- criteria for effective targeting; Positioning and repositioning	7	15%
	SECOND INTERNAL EXAMINATION		
V	Consumer Decision Making : Levels of Decision making, Views of consumer decision making, Model of consumer decision making: Input – marketing efforts, socio cultural environment. Process – psychological field, need recognition, pre-purchase search, Evaluation of alternatives Output – Purchase behavior and post purchase evaluation.	8	20%
VI	Performance management: Training & Development: Work environment & engineering psychology – fatigue, boredom, accidents & safety, Job analysis, Recruitment & Selection, Reliability & Validity of recruitment tests.	7	20%
	END SEMESTER EXAMINATION	1	l

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.



Course	Course name L-T-P-	Y	ear of
code	Credits	intro	duction
AE363	VLSI CIRCUIT DESIGN 3-0-0-3	2	2016
Prerequisi	e : Nil		
Course Ob	jective		
 To b 	ring circuits and system views on design together.		
	nderstand the design of digital VLSI circuits for hardware de	sign.	
Syllabus		0	
	al considerations in IC processing - NMOS IC technology - C	CMOS IC	technology
	IC technology- The MOS device- capacitance of MOS struct		
	er MOS device effects- pass transistors and transmission gate		
	S- Basic NAND, NOR circuits - The CMOS inverter, - pse		
	atic MOS circuits – Stick Diagram – Fabrication Combinatio		
	SI system design.		-
Expected o	utcome		
The student	s will be able		
i.	o learn layout, stick diagrams, fab <mark>ric</mark> ation steps , static and sv	vitching	
	characteristics of inverters		
ii.	o design digital system using MOS circuits.		
Text Books			
1. Dou	glas A. Pucknell & Kamran Eshraghian, <i>Basic VLSI Design</i> , I	PHI.	
2. Jan	M. Rabaey, A. Chandrakasan, B. Nikolic, Digital Integrated	Circuits- A	A Design
pers	pective, 2/e, Pearson education.		
3. Sun	g-Mo Kang, Yusuf Leblebici, CM <mark>OS</mark> Digital Integrated Circu	its Anal <mark>y</mark>	sis and
Des	gn, Tata Mc-Graw-Hill		
References			
	rles H Roth Jr – <i>Fundamentals of Logic Design</i> 4 Ed, Jaico Pu		
	d & Conway, Introduction to VLSI System Design-Addison V	Wesley	
	Sze, VLSI Technology, PHI		
	ne Wolf: Modern VLSI Design Systems on Chip-Pearson Edu		d ed
	te and Eshraghian, Principles of CMOS VLSI Design, A Syste	ems Persp	
Pear	son Education.		
	Course Plan		
Module		1	ective,2/e,
	Contents	Hours	
	Contents	Hours	ective,2/e, Semester exam
			ective,2/e, Semester exam marks
I	VLSI process integration: - fundamental considerations in		ective,2/e, Semester exam
I	VLSI process integration: - fundamental considerations in IC processing - NMOS IC technology - CMOS IC		ective,2/e, Semester exam marks
I	VLSI process integration: - fundamental considerations in IC processing - NMOS IC technology - CMOS IC technology - BiCMOS IC technology - GaAs technology.		ective,2/e, Semester exam marks
	VLSI process integration: - fundamental considerations in IC processing - NMOS IC technology - CMOS IC technology - BiCMOS IC technology - GaAs technology. Ion implantation in IC fabrication.	6	ective,2/e, Semester exam marks 15%
I II	VLSI process integration: - fundamental considerations in IC processing - NMOS IC technology - CMOS IC technology - BiCMOS IC technology - GaAs technology. Ion implantation in IC fabrication. The MOS device: (n - channel & p- channel) - capacitance	6	ective,2/e, Semester exam marks
	VLSI process integration: - fundamental considerations in IC processing - NMOS IC technology - CMOS IC technology - BiCMOS IC technology - GaAs technology. Ion implantation in IC fabrication. The MOS device: (n - channel & p- channel) - capacitance of MOS structure - accumulation, depletion and inversion,	6	ective,2/e, Semester exam marks 15%
	VLSI process integration: - fundamental considerations in IC processing - NMOS IC technology - CMOS IC technology - BiCMOS IC technology - GaAs technology. Ion implantation in IC fabrication. The MOS device: (n - channel & p- channel) - capacitance of MOS structure - accumulation, depletion and inversion, threshold voltage, current equations - characteristics,	6	ective,2/e, Semester exam marks 15%
	VLSI process integration: - fundamental considerations in IC processing - NMOS IC technology - CMOS IC technology - BiCMOS IC technology - GaAs technology. Ion implantation in IC fabrication. The MOS device: (n - channel & p- channel) - capacitance of MOS structure - accumulation, depletion and inversion, threshold voltage, current equations - characteristics, channel pinch-off. Second order MOS device effects:	6	ective,2/e, Semester exam marks 15%
	VLSI process integration: - fundamental considerations in IC processing - NMOS IC technology - CMOS IC technology - BiCMOS IC technology - GaAs technology. Ion implantation in IC fabrication. The MOS device: (n - channel & p- channel) - capacitance of MOS structure - accumulation, depletion and inversion, threshold voltage, current equations - characteristics, channel pinch-off. Second order MOS device effects: short-channel effect, narrow width effect, sub-threshold	6	ective,2/e, Semester exam marks 15%
	VLSI process integration: - fundamental considerations in IC processing - NMOS IC technology - CMOS IC technology - BiCMOS IC technology - GaAs technology. Ion implantation in IC fabrication. The MOS device: (n - channel & p- channel) - capacitance of MOS structure - accumulation, depletion and inversion, threshold voltage, current equations - characteristics, channel pinch-off. Second order MOS device effects: short-channel effect, narrow width effect, sub-threshold current, device saturation characteristics.	6	ective,2/e, Semester exam marks 15%
II	VLSI process integration: - fundamental considerations in IC processing - NMOS IC technology - CMOS IC technology - BiCMOS IC technology - GaAs technology. Ion implantation in IC fabrication. The MOS device: (n - channel & p- channel) - capacitance of MOS structure - accumulation, depletion and inversion, threshold voltage, current equations - characteristics, channel pinch-off. Second order MOS device effects: short-channel effect, narrow width effect, sub-threshold current, device saturation characteristics. FIRST INTERNAL EXAMINATION	6	ective,2/e, Semester exam marks 15%
	VLSI process integration: - fundamental considerations in IC processing - NMOS IC technology - CMOS IC technology - BiCMOS IC technology - GaAs technology. Ion implantation in IC fabrication. The MOS device: (n - channel & p- channel) - capacitance of MOS structure - accumulation, depletion and inversion, threshold voltage, current equations - characteristics, channel pinch-off. Second order MOS device effects: short-channel effect, narrow width effect, sub-threshold current, device saturation characteristics.	6 6 8	ective,2/e, Semester exam marks 15%

	equations - pull up to pull down ratio- transfer		
	characteristics- Alternate forms of pull up. Basic NAND,		
	NOR circuits. The CMOS inverter, characteristics -		
	NAND, NOR and compound circuits using CMOS. Other		
	forms of CMOS logic: pseudo CMOS, CMOS domino		
	logic, n-p logic.		
IV	Layout design of static MOS circuits - Layout rules -	7	15%
	general principles & steps of lay-out design - use of stick		
	diagrams - design rules - Layout examples of NAND and	N.A	
	NOR-Fabrication.	IVI	
	SECOND INTERNAL EXAMINATION	A T	
V	Combinational circuits - clocked sequential circuit - drivers	7	15%
	for bus lines. Scaling of MOS circuits: scaling models and	h. And	
	scaling factors for device parameters.		
VI	Timing issues in VLSI system design: timing	8	20%
	classification- synchronous timing basics – skew and jitter-		
	latch based clocking- self timed circuit design - self timed		
	logic, completion signal generation, self-timed signalling-		
	synchronizers and arbiters		
	END SEMESTER EXAMINATION		

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Exam Duration: 3 Hours

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

Estd.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)

Course code	Course name L-T-P- Credits		ar of duction
AE364	MEMS/NEMS 3-0-0-3		016
Prerequi			
	bjectives		
• T	o introduce the concept of MEMS and Microsystems.		
• T	o understand the diverse technological and functional approaches	s and app	olications
• T	o provide an insight of micro sensors, actuators and micro fluidic	cs.	
Syllabus	And And And And And	ono Conce	-
	tems - Micro Manufacturing Techniques - Micro Actuators - Mic ano Fluids - Microsystem Design and Packaging	cio Senso	018 -
	l outcome	4	
-	letion of the course, the students will be able to	A day	
-	ecome familiar with micro fabrication techniques		
	ssess whether using a MEMS based solution is the relevant and b	best appr	oach
	elect the most suitable manufacturing process and strategies for n		
Text Boo			
	Maluf, Nadim "An introduction to Microelectromechanical Sy AR Tech house, Boston 2000.	ystems I	Engineering
	ee Books:		
	Iohamed Gad – el – Hak "MEMS Handbook" Edited CRC Press	2002	
	abrie Solomon "Sensors Handbook", Mc Graw Hill, 1998		
3. M		2002 2n	d Edition
	larc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM		
4. F	larc F Madou, "Fundamentals of micro fabrication," CRC Press		
4. Fr II	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM		
4. Fr II N	larc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press	IS applic	ation"
4. Fr II N	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N	IS applic	ation"
4. Fr II N 5. Tr	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press w York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan	IS applic	ation" k 1997
4. Fr II N	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N	IS applic	ation" k 1997 Semester
4. Fr II N 5. Tr	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press w York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan	IS applic	ation" k 1997 Semester Exam
4. Fr II N 5. Tr	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents	IS application	ation" k 1997 Semester Exam Marks
4. Fr IE N 5. Tr Module	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics	IS applic	ation" k 1997 Semester Exam
4. Fr II N 5. Tr	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of	IS application	ation" k 1997 Semester Exam Marks
4. Fr IE N 5. Tr Module	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi-	IS application	ation" k 1997 Semester Exam Marks
4. Fr IE N 5. Tr Module	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press w York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi- disciplinary nature of MEMS- Survey of materials central to	IS application	ation" k 1997 Semester Exam Marks
4. Fr IE N 5. Tr Module	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi-	IS application	ation" k 1997 Semester Exam Marks
4. Fr IE N 5. Tr Module	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press w York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi- disciplinary nature of MEMS- Survey of materials central to micro engineering- Applications of MEMS in various industries	IS application	ation" k 1997 Semester Exam Marks
4. Fr IE N 5. Tr Module	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press w York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi- disciplinary nature of MEMS- Survey of materials central to micro engineering- Applications of MEMS in various industries Micro Manufacturing Techniques : Photolithography- Film	IS applications of the second	ation" k 1997 Semester Exam Marks 15%
4. Fr IE N 5. Tr Module	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press w York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi- disciplinary nature of MEMS- Survey of materials central to micro engineering- Applications of MEMS in various industries	IS applications of the second	ation" k 1997 Semester Exam Marks 15%
4. Fr IF N 5. Tr Module	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press w York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi- disciplinary nature of MEMS- Survey of materials central to micro engineering- Applications of MEMS in various industries Micro Manufacturing Techniques : Photolithography- Film deposition, Etching Processes-Bulk micro machining, silicon	IS applications of the second	ation" k 1997 Semester Exam Marks 15%
4. Fr IE N 5. Tr Module	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press w York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi- disciplinary nature of MEMS- Survey of materials central to micro engineering- Applications of MEMS in various industries Micro Manufacturing Techniques : Photolithography- Film deposition, Etching Processes-Bulk micro machining, silicon	IS applications of the second	ation" k 1997 Semester Exam Marks 15%
4. Fr IE N 5. Tr Module	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi- disciplinary nature of MEMS- Survey of materials central to micro engineering- Applications of MEMS in various industries Micro Manufacturing Techniques : Photolithography- Film deposition, Etching Processes-Bulk micro machining, silicon surface micro machining	IS applications of the second	ation" k 1997 Semester Exam Marks 15%
4. Fr IE N 5. Tr Module	Iarc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi- disciplinary nature of MEMS- Survey of materials central to micro engineering- Applications of MEMS in various industries Micro Manufacturing Techniques : Photolithography- Film deposition, Etching Processes-Bulk micro machining, silicon surface micro machining FIRST INTERNAL EXAMINATION Micro Actuators : Energy conversion and force generation- Electromagnetic Actuators, Reluctance motors, piezoelectric	IS applies New Yorl Hours 6 6	ation" k 1997 Semester Exam Marks 15%
4. Fr IF N 5. Tr Module I I	farc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi- disciplinary nature of MEMS- Survey of materials central to micro engineering- Applications of MEMS in various industries Micro Manufacturing Techniques : Photolithography- Film deposition, Etching Processes-Bulk micro machining, silicon surface micro machining FIRST INTERNAL EXAMINATION Micro Actuators : Energy conversion and force generation- Electromagnetic Actuators, Reluctance motors, piezoelectric actuators, bi-metal-actuator Friction and wear	IS applies New Yorl Hours 6 7	ation" k 1997 Semester Exam Marks 15% 15% 20%
4. Fr IR N 5. Tr Module II II	farc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM GEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi- disciplinary nature of MEMS- Survey of materials central to micro engineering- Applications of MEMS in various industries Micro Manufacturing Techniques : Photolithography- Film deposition, Etching Processes-Bulk micro machining, silicon surface micro machining FIRST INTERNAL EXAMINATION Micro Actuators : Energy conversion and force generation- Electromagnetic Actuators, Reluctance motors, piezoelectric actuators, bi-metal-actuator Friction and wear Micro Sensors : Transducer principles-Signal detection and	IS applies New Yorl Hours 6 6	ation" k 1997 Semester Exam Marks 15%
4. Fr IE N 5. Tr Module I	farc F Madou, "Fundamentals of micro fabrication," CRC Press rancis E.H Tay and W. O. Choong, "Micro fluidics and bio MEM EEE Press ew York 1997 rimmer William S, "Micromachanics and MEMS", IEEE Press, N Course Plan Contents Foundation in Microsystems : Review of microelectronics manufacture and introduction to MEMS- Overview of microsystems technology, Laws of scaling- The multi- disciplinary nature of MEMS- Survey of materials central to micro engineering- Applications of MEMS in various industries Micro Manufacturing Techniques : Photolithography- Film deposition, Etching Processes-Bulk micro machining, silicon surface micro machining FIRST INTERNAL EXAMINATION Micro Actuators : Energy conversion and force generation- Electromagnetic Actuators, Reluctance motors, piezoelectric actuators, bi-metal-actuator Friction and wear	IS applies New Yorl Hours 6 7	ation" k 1997 Semester Exam Marks 15% 15%

	SECOND INTERNAL EXAMINATION		
V	Introduction to Micro/Nano Fluids : Fundamentals of micro fluidics- Micro pump – introduction – Types - Mechanical Micro pump – Non mechanical micro pumps, Actuating Principles, Design rules for micro pump – modeling and simulation, Verification and testing – Applications	8	20%
VI	Microsystem Design and Packaging : Design considerations-Mechanical Design, Process design, Realization of MEMS components using Intellisuite. Micro system packaging-Packing Technologies-Assembly of Microsystems- Reliability in MEMS.	8	20%
	END SEMESTER EXAMINATION		

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

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(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course code	Course name	L-T-P- Credits		Year of troduction
AE365	INSTRUMENTATION FOR AGRICULTURE	3-0-0-3		2016
Prerequi		0000		2010
Course C				
	impart background information required for studyin	g instrumen	ntation ar	nd its
	pplication in agriculture.	5	itution ui	iu ius
Syllabus				
•	of instrumentation & control for agriculture, engine	eering prope	erties of	soil - Flow
•	of sugar plant - fermenter & control - dairy industry			
	- soil moisture measurement methods - Application o			
	l - green houses & instrumentation - Hydraulic, p			
	classification of pumps-TDR-ground water occur			
aquifers.	ermoniter of particle for a contraction			
-	loutcome	1		
-	t the end of the semester students will have the know	ledge about	instrume	entation in
	riculture and some of its applications.		inou ann	
Text Boo				
	C D Johnson Process control and instrumentation t	echnology	PHI	
	Patranabis, Industrial instrumentation, TMH.			
3.		EdPergamo	on Press.	
Referenc		, 8		
	G.Liptak, Instrumentation handbook-process contro	l. Chilton		
· D	Course Plan	i, ennion		
Module	Contents		Hours	Semester
mouule	contents		nouis	exam
				marks
Ι	Necessity of instrumentation & control for a	griculture.	8	15%
-	engineering properties of soil: fundamental defi		U	10 /0
	relationships, index properties of soil, permeability			
	analysis, shear strength, Mohr's circle of stress,			
	passive earth pressures, stability & slopes,			
	introduction to sonic anemometers, hygrometers,			
	thermocouples, open & close path gas analys			
	introduction to various bio-sensors.	.,		
II	Flow diagram of sugar plant & instrumentation set	up for it.	6	15%
	flow diagram of fermenter & control(batch pro	-		
	diagram of dairy industry & instrumentation set			
	juice extraction control process & instrumentation	-		
	it.	1 I		
	FIRST INTERNAL EXAMINAT	ION		
III	Irrigation systems: necessity, irrigation methods:		7	15%
	centre pivot, lateral move, micro irrigation system			
	performance, comparison of different irrigation sys			
	moisture measurement methods: resistance based			
	voltage based	,		
	method, thermal based method, details of gypsum	block soil		
	moisture sensor, irrigation scheduling, irrigation ef			
	design considerations in irrigation channels.			
				1

IV	Application of SCADA for DAM parameters & control, irrigation control management up- stream & down - stream control systems, green houses & instrumentation: ventilation, cooling & heating, wind speed, temperature & humidity, rain gauge carbon dioxide enrichment measurement & control.	6	15%
	SECOND INTERNAL EXAMINATION		
V	Automation in earth moving equipments & farm equipments, application of SCADA & PLC in packing industry and cold storage systems, implementation of Hydraulic, pneumatic & electronics control circuits in harvester's cotton pickers, tractor etc. classification of pumps: pump characteristics, pump selection & installation.		20%
VI	Leaf area length evapotranspiration, temperature, wetness & respiration measurement & data logging, electromagnetic radiations photosynthesis, infrared & UV bio sensor methods in agriculture, agro metrological instrumentation weather stations, surface flux measurement, soil water content measurement using time-domain reflectrometery (TDR), ground water occurrence confined & unconfined aquifers, evaluation of aquifer properties, ground water recharge.	8	20%
	END SEMESTER EXAMINATION		

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Exam Duration: 3 Hours

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course code	Course name	L-T-P-Credits		Year of roduction
AE366	EMBEDDED SYSTEM DESIGN	3-0-0-3		2016
Prerequi	site : Nil		1	
Course o	bjectives			
• T	o impart the basic functions and structure of emb	bedded systems C	Outcome	es.
Syllabus		-		
Embedde	d Systems Vs General Computing Systems - Pu	rpose of Embedo	led Syst	tems - Core
	nbedded System – Memory - Embedded Firmwar			
	Task Communication - Task Synchronization - P			
	ning in C Program - Concepts of embedded	programming in	C++ -	- Real time
	systems Definitions of process.	III F	11.	
-	loutcome	ITY		
	t the end of the semester students will be able	to understand the	e basic	concepts &
	oplications of embedded systems.	4 4 4	_	
Text Boo		0 1111		
	hibu K.V, Introduction to Embedded Systems, Mc		<i>a</i>	
	Vayne Wolf, Computers as Components: Principle			
Reference	esign – Harcourt India, Morgan Kaufman Publis	ners, First Indian	Keprin	1 2001
	avid E. Simon An Embedded Software Primer, Po	open Education		
	rank Vahid and Tony Givargis, Embedded System			dwara /
	oftware Introduction, John Wiley, 2002.	Design – A unin	icu Hai	uwale /
	yla B Das, Embedded Systems An Integrated App	proach Pearson	2013	
	ajkamal, Embedded Systems Architecture, Progra			ГА
	IcGraw-Hill, First reprint Oct. 2003	anning and Desi	5", 11	
	Course Plan			
Module	Contents	H	lours	Semester
				Exam
				Marks
Ι	Introduction to Embedded Systems: Do	efinition of 6		15%
	Embedded System, Embedded Systems	Vs General		
	Computing Systems, History of Embedde		7	
	Classification, Major Application Areas,	ed Systems, Purpose of	/	
	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali	ed Systems, Purpose of		
	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems.	ed Systems, Purpose of ity Attributes		
II	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed	ed Systems, Purpose of ity Attributes dded System: 7		15%
II	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed General Purpose and Domain Specific Proces	ed Systems, Purpose of ity Attributes dded System: 7 ssors, ASICs,		15%
II	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed General Purpose and Domain Specific Proces PLDs, Commercial Off-The-Shelf Compone	ed Systems, Purpose of ity Attributes ided System: 7 isors, ASICs, nts (COTS),		15%
II	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed General Purpose and Domain Specific Proces PLDs, Commercial Off-The-Shelf Compone Memory: ROM, RAM, Memory according to	ed Systems, Purpose of ity Attributes dded System: 7 ssors, ASICs, nts (COTS), o the type of		15%
II	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed General Purpose and Domain Specific Proces PLDs, Commercial Off-The-Shelf Compone Memory: ROM, RAM, Memory according to Interface, Memory Shadowing, Memory s	ed Systems, Purpose of ity Attributes dded System: 7 ssors, ASICs, nts (COTS), o the type of		15%
II	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed General Purpose and Domain Specific Proces PLDs, Commercial Off-The-Shelf Compone Memory: ROM, RAM, Memory according to Interface, Memory Shadowing, Memory s Embedded Systems, Sensors and	ed Systems, Purpose of ity Attributes Ided System: 7 sors, ASICs, nts (COTS), the type of selection for		15%
II	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed General Purpose and Domain Specific Proces PLDs, Commercial Off-The-Shelf Compone Memory: ROM, RAM, Memory according to Interface, Memory Shadowing, Memory s Embedded Systems, Sensors and Actuators, Communication Interface: On board	ed Systems, Purpose of ity Attributes Ided System: 7 sors, ASICs, nts (COTS), the type of selection for		15%
II	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed General Purpose and Domain Specific Proces PLDs, Commercial Off-The-Shelf Compone Memory: ROM, RAM, Memory according to Interface, Memory Shadowing, Memory s Embedded Systems, Sensors and Actuators, Communication Interface: On board Communication Interfaces.	ed Systems, Purpose of ity Attributes dded System: 7 ssors, ASICs, nts (COTS), o the type of selection for and External		15%
	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed General Purpose and Domain Specific Proces PLDs, Commercial Off-The-Shelf Compone Memory: ROM, RAM, Memory according to Interface, Memory Shadowing, Memory s Embedded Systems, Sensors and Actuators, Communication Interface: On board Communication Interfaces. FIRST INTERNAL EXAMIN	ed Systems, Purpose of ity Attributes dded System: 7 ssors, ASICs, nts (COTS), o the type of selection for and External NATION		
II III	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed General Purpose and Domain Specific Proces PLDs, Commercial Off-The-Shelf Compone Memory: ROM, RAM, Memory according to Interface, Memory Shadowing, Memory s Embedded Systems, Sensors and Actuators, Communication Interface: On board Communication Interfaces. FIRST INTERNAL EXAMIN Embedded Firmware: Reset Circuit, Brown-or	ed Systems, Purpose of ity Attributes dded System: 7 ssors, ASICs, nts (COTS), o the type of selection for and External NATION ut Protection 7		15% 15%
	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed General Purpose and Domain Specific Proces PLDs, Commercial Off-The-Shelf Compone Memory: ROM, RAM, Memory according to Interface, Memory Shadowing, Memory s Embedded Systems, Sensors and Actuators, Communication Interface: On board Communication Interfaces. FIRST INTERNAL EXAMIN Embedded Firmware: Reset Circuit, Brown-or Circuit, Oscillator Unit, Real Time Clock, Wate	ed Systems, Purpose of ity Attributes Ided System: 7 sors, ASICs, nts (COTS), the type of selection for and External NATION ut Protection 7 chdog Timer,		
	Classification, Major Application Areas, Embedded Systems, Characteristics and Quali of Embedded Systems. Typical Embedded System: Core of the Embed General Purpose and Domain Specific Proces PLDs, Commercial Off-The-Shelf Compone Memory: ROM, RAM, Memory according to Interface, Memory Shadowing, Memory s Embedded Systems, Sensors and Actuators, Communication Interface: On board Communication Interfaces. FIRST INTERNAL EXAMIN Embedded Firmware: Reset Circuit, Brown-or	ed Systems, Purpose of ity Attributes Ided System: 7 sors, ASICs, nts (COTS), the type of selection for and External NATION ut Protection 7 chdog Timer,		

IV		7	15%
	Basics, Types of Operating Systems, Tasks, Process and		
	Threads, Multiprocessing and Multitasking, Task		
	Scheduling.		
	SECOND INTERNAL EXAMINATION		
V	Task Communication: Shared Memory, Message Passing,	7	20%
	Remote Procedure Call and Sockets,		
	Task Synchronization: Task Communication		
	/Synchronization Issues, Task Synchronization	N.A.	
	Techniques, Device Drivers, How to Choose an RTOS.	UVI	
VI	Programming concepts of Embedded programming in C	8	20%
	Program Elements, Macros and functions - Use of Pointers -	A L	
	NULL Pointers - Use of Function Calls – Multiple function	1 1.1.	
	calls in a Cyclic Order in the Main Function Pointers –		
	Function Queues and Interrupt Service Routines Queues		
	Pointers – Concepts of embedded programming in C++ –		
	Cross compiler – Optimization of memory codes. Real time		
	operating systems Definitions of process, tasks and threads.		
	END SEMESTER EXAMINATION		

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Exam Duration: 3 Hours

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)

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Estd.

Course			Year of
code	Credits		troduction
AE368			2016
	iisite: Nil		
	objectives		
	To give the concept of plastic engineering and their standards.		
	To understand the diverse technological and functional approach	-	plications
•]	To provide an insight of testing, identification and quality control	ol.	
Syllabus	And	NA 4	
0	ring Plastics- Concept of testing & identification of plastic		
	s for bio-degradable plastics - Recycling technologies for bio		ble plastics -
	on and quality control of moulds - Environmental consideration	AL.	
-	d outcome		
	pletion of the course, the students will		
	become familiar with testing methods and standards of plastic.		
	be able to test the quality control of different modules.		
	be able to identify how to engineer along with the environmental	l consider	ation.
Text Bo			
	Cyril Donaldson, George H.Lecain, V C Goold, Tool Des	agn, IA	IA McGraw
	Hill, 1998. Find W. Billmover, Ir. Toyt Book of Bolymon Science.	John W	ilar e Sana
	Fred W. Billmeyer, Jr., Text Book of Polymer Science, Singapore, 1994.	John w	ney asons,
	G.J.L. Griffin, Chemistry and Tech <mark>no</mark> logy of Biodegradabl	e Dolum	ors Blackie
	Academic Professional, 1994.	e rorym	ers, Diackie
	ce Books:		
	Abraham J. Domb, Joseph Kost & David M.Wiseman, Handbe	ook of B	iodegradable
	polymers, CRC Press	OOK OI D	louegradable
1	Dominick V. Rosato, DonaldV. Rosato, Injection Molding	Hand	Book CBC
	Publishers&Distributors,1987	, mana	DOOK, CDC
	Gerald Scott & Dan Gilad, Degradable Polymers-Principles & A	pplicatio	ns. Chapman
	& Hall, 1995.	ppneadle	no, enapinar
4. 0	Gordon L. Robertson, Food Packaging Principles and Practice,	Marcel	Dekker. Inc
	New York 1993.	777	,,
	rwinI Rubin, Injection Molding Theory and Practice, V	Visely In	nter science
	Publication, 1972.		
6. I	Louis T. Manzione, Plastic Packaging of Microelectronic De	evices, V	an Nostrand
	Reinhold, New York, 1990.		
7. F	Plastics Engineering Hand Book of the Society of the Plast	ics Indus	stry Inc.,Van
Ν	Nostrand Reinhold Company, 1945.		
8. V	Vishu Shah, Hand Book <mark>of Plastics Te</mark> sti <mark>ng Technolog</mark> y, John Wi	iley & So	ons Inc., New
Υ	York, 1998.		
	Course Plan	1	ſ
Module	Contents	Hours	Semester
			Exam
			Marks
	Engineering Plastics : Sources and Manufacture of raw	8	15%
Ι	materials, Methods of Manufacture of Polymer, General		
	Properties and applications of Acrylonitrile Butadiene		

		1	
	Styrene -Polyamides (PA-6,PA-66,PA-6,10,PA-11&12) –		
	Polycarbonates – Poly acetal & Copolymers -		
	Thermoplastic Polyesters (PET&PBT) Poly phenylene		
	oxide – Poly sulfones Fluoropolymers		
	(PVF,PVDF,PTFE,PCTFE) - Thermoplastic Polyurethane.		
	Concept of testing & identification of plastics : Basic	8	15%
II	concepts of testing - Specification and Standards - National		
	and International Standards - Test specimen preparation -		
	Pre-conditioning and test atmosphere. Identification of	NA 1	
	plastics by simple tests - Visual examination - Density -	1VI	
	Melting point - Solubility test - Flame test - Chemical tests.	A T	
	FIRST INTERNAL EXAMINATION	AL	
	Test methods and standards for bio-degradable plastics:	6	15%
III	Plastics – criteria used in evaluation of biodegradable		
	plastics – description of current Test methods – Scanning		
	test for ready biodegradability – Test for inherent		
	biodegradability – Test for simulation studies – Other		
	methods for assessing polymer biodegradability		
IV	Recycling technologies for bio degradable plastics:	6	
	Conventional recycling – Degradable complicate recycling		
	– reprocessing polyethylene starch/film scrap – Economics		
	in in-plant recycling		
	SECOND INTERNAL EXAMINATION		
	Inspection and quality control of moulds : Introduction to	7	20%
V	Tool Room measuring instruments – Vernier– Micrometer –		
	Height Gauge–Slip Gauge–Dial Gauge–Measuring tapers		
	and angles-CMM		_
		1	
	Environmental consideration: Plastic waste –	7	20%
VI	Classification, Segregation, Sorting and Waste Management		
	viz. source reduction, reuse/repair, recycling related to	1	
	packaging films and constrainers. Pollutants an outline –		
	Chloro Fluoro Carbon (CFC), Dioxin Life cycle assessment:	1.	
	A case study		
	Trouse study		
	END SEMESTER EXAMINATION		

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

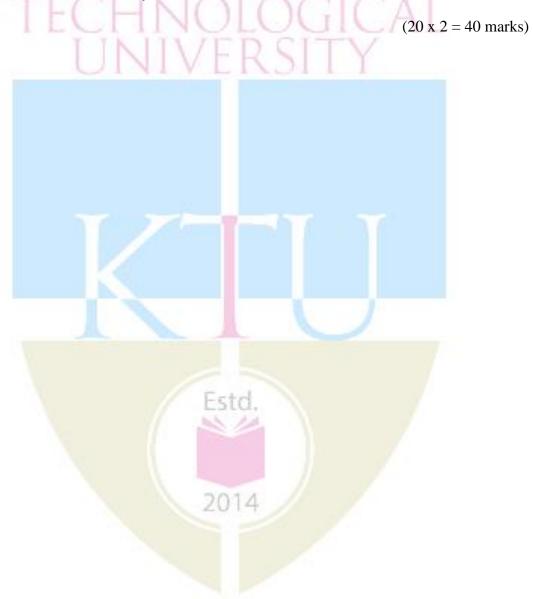
Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.



Course code	course name	L-T-P-Credits	Year of Introduction
AE401	LOGIC & DISTRIBUTED CONTROL SYSTEM	4-0-0-4	2016
Prerequisite:	AE301 Control system		
Course objec			
 To giv 	e an introductory knowledge about F	LC and the progra	mming languages.
-	e basic knowledge in the architecture		
ol syst			AAA
-	e adequate information in the interfa	ces used in DCS.	AIVI
• To giv	e basic knowledge about Computer	Controlled System	s.
Syllabus	3	UNIT	AL
•	e Logic Controller - Architecture	of PLC - Design	n of PLC - PLC Basic
0	pplications Of PLC - Instructions ir		
	SCADA - Distributed Control Syste		• •
	& Safety Management System - Ri		
Expected out			·
	the course, students will be able to :		
i. Un	derstand the basics of PLC and PLC	Programming	
ii. Kn	low the whereabouts of implementation	ion of SCADA	
iii. Re	produce the working of Distributed (Control System	
iv. Pe	rform the implementation of DCS		
v. Re	cognise the safety procedures to be r	naintained in an in	dustry
Applic 2. Micha Co.,Ca 3. Petruz	W. Webb Ronald A Reis - Programm cations, Fourth edition, Prentice Hall el P. Lukas, 'Distributed Control Sys mada,1986 ella, 'Industrial Electronics', McGrav	Inc., New Jersey, stems', Van Nostra	1998. and Reinhold
Reference Bo			
	a Kant – Computer based Industrial		
2. Thoma	as A. Hughes, 'Programmable Logic Course P		press,2007.
	Course r		Semester Exam
Module	Contents	Ho	urs Marks
Ι	Programmable Logic Controller : H	Evolution of 9	15%
-	PLC's, Components of PLC, Adva		
	relay logic, Architecture of PLC, Pr	-	
	devices, Discrete and Analog I/	0 0	
	Programming languages, Ladde	er diagram,	
	Programming timers and counters		
	PLC, Definition of PLC, , overvi	ew of PLC	
	systems, input/output modules, pow	ver supplies,	
	•	ogramming	
	procedures, programming on-o		
	outputs. Auxiliary commands and		
	PLC Basic Functions: Register b	asics, timer	
	functions, counter functions.		1.50/
II	Applications Of PLC : Instruction	ons in PLC 9	15%

	Program control instructions math		
	Program control instructions, math		
	instructions, sequencer instructions, Use of		
	PCas PLC, Application of PLC, Case study of		
	bottle filling system, PLC programming		
	methods as per IEC 61131, Developing		
	programs using Sequential Function Chart,		
	Functional Block Diagram, Analog control		
	using PLC (PID controller configuration),		
	Interfacing PLC to SCADA/DCS using	T A	N.A.
	communication link (RS232, RS485),	ALA	M
	Protocols (Modbus ASCII/RTU) and OPC,	The second secon	
	Development stages involved for PLC based	1	
	automation systems.		
FIDST INTI	ERNAL EXAMINATION	1	
		7	15%
III	Computer Controlled Systems:	/	13%
	Basic building blocks of Computer controlled		
	systems, SCADA, Data Acquisition System,		
	Supervisory Control,		
	Direct digital Control.		
IV	Distributed Control System : DCS -	10	15%
	Architectures, Comparison, Local control		
	unit, Process interfacing issues,		
	Communication facilities. Distributed Control	10	
	System Basics: DCS introduction, Various		
	function Blocks, DCS components/block		
	diagram, DCS Architecture of different makes,		
	comparison of these architectures with		
	automation pyramid, DCS specification, latest	1.1.1	
	trend and developments, DCS support to		
	Enterprise Resources Planning (ERP),		
	performance criteria for DCS and other		
	automation tools.		
	SECOND INTERNAL EXAMINAT		
N7		1	200/
V	Interfaces In Dcs : Operator interfaces, Low	9	20%
	level and high level operator interfaces,		
	Operator displays, Engineering interfaces, Low		
	level and high level engineering interfaces,		
	General purpose computers in DCS, DCS detail		
	Engineering, configuration and programming,		
	functions including database management,		
	reporting, alarm management, diagnosis.		
VI	Process Safety & Safety Management System :	10	20%
	Process safety and Safety Management		
	Systems: Introduction to process safety, risk,		
	risk terminologies, consequence and risk, risk		
	measurement, Process Hazard Analysis (PHA),		
	Hazard and operability study (HaZOp), Safety		
	Integrity Level (SIL), Introduction to		
	IEC61511 standard for Functional safety,		
1	incorsin standard for Functional safety,		
	protection layers, Safety Instrumented System:		

function,	architecture,	safety	life	cycle,		
Applicatio	n of safety syst	em.				
	END SEME	ESTER H	EXAM	INATIO	ON	

Maximum Marks:100	Exam Duration: 3 Hours
Part A APIABDUL	KALAM
Answer any two out of three questions uniformly cover	ring Modules 1 and 2 together. Each
question carries 15 marks and may have not more than	four sub divisions.
UNIVER.	(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)

2014

Estd

Course code	Course name I	L-T-P-Credits	Year of Introduction
AE402	ANALYTICAL INSTRUMENTATION	3-0-0-3	2016
Prerequi			
Course o			
	preview background information required for study	ing virtual instr	umentation.
	study the basic building blocks of virtual instrume	-	
	study the various graphical programming environm		nstrumentation.
	study a few applications in virtual instrumentation		. A
Syllabus		ALA	VI
-	ntals of analytical instruments –Classification	of instrumen	tal techniques -
	agnetic radiation- Electromagnetic spectrum- Absor		•
	le absorption spectroscopy - Colorimeters/ photo	• •	
	spectroscopy - Atomic absorption spectrophotometer		
	bectrometer - Mass spectrometer - Nuclear Mag		
	spectroscopy - X- Ray spectrometers - Chromatog		
	matography - Liquid Chromatography - High pre		
	Gas analysers - Gas analysers - Blood PH measure		
gas senso	rs- Thermal Sensors.		
Expected	outcome		
	t the end of the semester students will be able to obt	-	sive knowledge
in	analytical instrumentation and some of its applicati	ons.	
ри 2. W	coog, Holler, Nieman, "Principles of Instrumental A Iblications, 5th edition. illard, Merritt, Dean, Settle , "Instrumental Methods Distributors, New Delhi, Seventh edition.	•	
Referenc	e Books		
1. G	alen W. Ewing, "Instrumental Methods of Chemica	l Analysis", , M	lcGraw-Hill
	ook Company, Fifth edition.		
2. R.	S. Khandpur, "Handbook of Analytical Instrument	ts", , Tata McG	raw–Hill
	iblications, 3rd edition.		
	obert D. Braun, "Introduction to Instrumental Analy	ysis", , McGraw	/-Hill Book
C	ompany		
	Course Plan		
	2 1 2014		Semester
Module	Contents 4	Ho	urs Exam
•			Marks
I	Introduction to Analytical Instrumentation: Fundar		15%
	analytical instruments: Elements of an analytical i		
	– PC based analytical instruments –Classific instrumental techniques. Electromagnetic	radiation-	
	Electromagnetic spectrum- Laws relating to abso		
	radiation. Absorption spectroscopy: Absorption in	-	
	- Radiation sources- Optical filters- Monoch		
	Detectors. Ultra violet and visible absorption spect		
	* *	¥ ¥	1 50/
II	Colorimeters/ photometers: Single beam and dou	ible beam 7	15%

	double beam spectro photo meters- Infra red spectroscopy:		
	Basic components- Radiation sources- Monochromators-		
	Detectors. Flame Photometry: Principle and constructional		
	details of flame photometer- Emission system - Optical		
	system – Detectors. Atomic absorption spectrophotometers:		
	Theoretical concepts, Instrumentation: Radiation sources -		
	Burners and flames - Plasma excitation sources - Optical		
	and electronic system.		
	FIRST INTERNAL EXAMINATION	-	150/
III	Fluorescence spectroscopy: Principle of fluorescence –	VI VI	15%
	Measurement of fluorescence – Single beam and double	AT	
	beam filter fluorimeter- Ratio fluorimeter. Spectro	AL	
	fluorimeters. Raman spectrometer- Basic theory-Photo	I h first	
	acoustic spectroscopy- Photo thermal spectroscopy. Mass		
	spectrometer: Principle of operation- Magnetic deflection		
	mass spectrometers- Components of a mass spectrometer –		
	Inductively coupled plasma mass spectrometer.		
IV		7	15%
- •	- Constructional details of NMR spectrometer - Nuclear		10 / 0
	radiation detectors. Electron Spin Resonance spectrometer:		
	Basic ESR spectrometer – Electron spectroscopy:		
	Instrumentation for electron spectroscopy. X- Ray		
	spectrometers: X – ray spectrum –Instrumentation for x –ray		
	spectrometry. X-ray diffractometers- X-ray absorption		
	meters- X- ray fluorescence spectrometry.		
	SECOND INTERNAL EXAMINATION		
V	SECOND INTERNAL EXAMINATION Chromatography: Chromatographic process –	7	20%
V		7	20%
V	Chromatography: Chromatographic process – Classification- Terms in chromatography- Gas	7	20%
V	Chromatography: Chromatographic process – Classification- Terms in chromatography- Gas chromatography: Block diagram- Principle - Constructional	7	20%
V	Chromatography: Chromatographic process – Classification- Terms in chromatography- Gas chromatography: Block diagram- Principle - Constructional details – Column details- GC detectors. Liquid	7	20%
V	Chromatography: Chromatographic process – Classification- Terms in chromatography- Gas chromatography: Block diagram- Principle - Constructional details – Column details- GC detectors. Liquid Chromatography: Types of liquid chromatography- High	7	20%
V	Chromatography: Chromatographic process – Classification- Terms in chromatography- Gas chromatography: Block diagram- Principle - Constructional details – Column details- GC detectors. Liquid Chromatography: Types of liquid chromatography- High pressure Liquid Chromatography (HPLC): Principle-	7	20%
	Chromatography: Chromatographic process – Classification- Terms in chromatography- Gas chromatography: Block diagram- Principle - Constructional details – Column details- GC detectors. Liquid Chromatography: Types of liquid chromatography- High pressure Liquid Chromatography (HPLC): Principle- Constructional details.		
	Chromatography:Chromatographicprocess–Classification-Termsinchromatography-Gaschromatography:Block diagram-Principle -Constructionaldetails–Columndetails-GCdetectors.LiquidChromatography:Typesofliquidchromatography-HighpressureLiquidChromatography(HPLC):Principle-Constructionaldetails.IndustrialGasanalyzers-pH	7 8	20%
	Chromatography:Chromatographicprocess–Classification-Termsinchromatography-Gaschromatography:Block diagram-Principle -Constructionaldetails–Columndetails-GCdetectors.LiquidChromatography:Typesofliquidchromatography-HighpressureLiquidChromatography(HPLC):Principle-Constructionaldetails.IndustrialGasanalyzers-pHDissolvedoxygenmeters-Sodiumanalyser-Gasanalysers-		
	Chromatography:Chromatographicprocess–Classification-Termsinchromatography-Gaschromatography:Block diagram-Principle -Constructionaldetails–Columndetails-GCdetectors.LiquidChromatography:Types of liquid chromatography-HighpressureLiquidChromatography(HPLC):Principle-Constructional details.Industrial Gas analyzers-pHmeters-Conductivitymeters -Dissolved oxygenmeters-Sodiumanalyser-Gasanalysers-Paramagneticoxygenanalyser–COanalysers -Fluegas		
V	Chromatography:Chromatographicprocess–Classification-Termsinchromatography-Gaschromatography:Block diagram-Principle -Constructionaldetails–Columndetails-GCdetectors.LiquidChromatography:Typesofliquidchromatography-HighpressureLiquidChromatography(HPLC):Principle-Constructional details.IndustrialGasanalyzers-pHDissolved oxygenmeters-Sodiumanalysers-Gasanalysers-Paramagneticoxygenanalyser–COanalysers-Fluegasanalysers-BloodPHmeasurement–Thinfilmtechnology		
	Chromatography:Chromatographicprocess–Classification-Termsinchromatography-Gaschromatography:Block diagram-Principle -Constructionaldetails–Columndetails-GCdetectors.LiquidChromatography:Types of liquid chromatography-HighpressureLiquidChromatography(HPLC):Principle-Constructional details.Industrial Gas analyzers-pH meters-Conductivity meters -Dissolved oxygen meters-Sodium analyser-Gas analysers-Paramagnetic oxygen analyser–CO analysers -Flue gasanalysers-Blood PH measurement -Thin film technologyfor gas sensors-Basic concepts.Measurement techniques		
	Chromatography:Chromatographicprocess–Classification-Termsinchromatography-Gaschromatography:Block diagram-Principle -Constructionaldetails–Columndetails-GCdetectors.LiquidChromatography:Typesofliquidchromatography-HighpressureLiquidChromatography(HPLC):Principle-Constructional details.IndustrialGasanalyzers-pHDissolved oxygenmeters-Sodiumanalysers-Gasanalysers-Paramagneticoxygenanalyser–COanalysers-Fluegasanalysers-BloodPHmeasurement–Thinfilmtechnology		
	Chromatography:Chromatographicprocess–Classification-Termsinchromatography-Gaschromatography:Block diagram-Principle -Constructionaldetails–Columndetails-GCdetectors.LiquidChromatography:Types of liquid chromatography-HighpressureLiquidChromatography(HPLC):Principle-Constructional details.Industrial Gas analyzers-pH meters-Conductivity meters -Dissolved oxygen meters-Sodium analyser-Gas analysers-Paramagnetic oxygen analyser–CO analysers -Flue gasanalysers-Blood PH measurement -Thin film technologyfor gas sensors-Basic concepts.Measurement techniques		

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

Part B

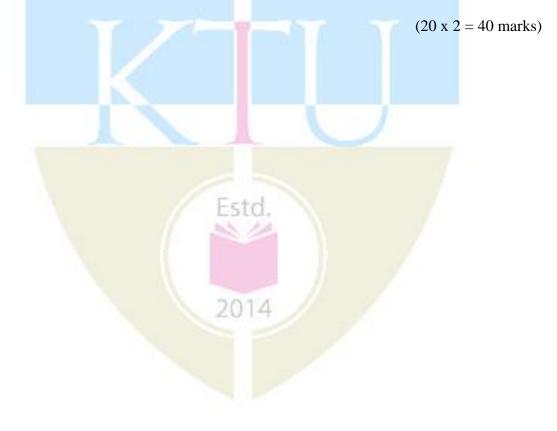
Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.



Course code		-T-P- redits		ar of duction
AE403		·0-0-3)16
Prerequis		0-0-5	2	510
Course of				
	-	and de	aion of	hismodical
	impart knowledge of the principle of operation struments.	and de	sign of	biomedical
	render a broad and modern account of biomedical inst	ruments.	N 4	
	introduce idea about human physiology system	A	M	
Syllabus		1.1.1	- D	· 1
-	ysiology- Bioelectric potential and cardiovascular mea y measurements and rehabilitation- Patient monitoring			
Instrumen	ts- Imaging technique & Telemetry.	17	h. And	-
Expected		Y		
-	of the semester students will	- A		
i. be	able to understand about human physiology			
	ve knowledge of the principle operation and design and	the bac	kground l	nowledge
	biomedical instruments and specific applications of bio			
Text Bool			Ŭ	Ū.
1. Ar	umugam.M. "Biomedical Instrumentation", Anuradha	Agencie	s Publis <mark>he</mark>	ers,
Ku	umbakonam, 2006.	-		
2. Le	slie Cromwell, Fred J. Weibell and Erich A. Pfeiffer, "A	Biomedic	cal Instr <mark>u</mark>	nentation
an	d Measurements", 2nd Edition, Prentice Hall, New Del	lhi, 1998		
Reference	e Books:			
	eddes L. A. and Baker L. E., " <i>Principles of Applied Bio</i>	omedical	Instrume	ntation",
	d Edition, John Wiley, New York, 1989.			XX7:1
	hn. G. Webster, <i>"Medical Instrumentation, Application</i>	ana Des	sign Jon	n wiley,
	ew York, 1998 S. Khan daver, "Ulum dhaab, of Diamadiaal Instrumentat		tion II.	11 of India
	S.Khandpur, "Handbook of Biomedical Instrumentation of Biomedical Inst	ion, Pro	entice Ha	II of India,
		ntation	and Mar	······································
	chard Aston, "Principles of Bio-medical Instrume erril Publishing Company, New York, 1990.	nialion	ana mec	isurement,
IVIC				
	Course Plan			Comoct
Modula	Contents		Hours	Semester Exam
Module	Contents		Hours	
T			7	Marks
	Electro physiology: Review of physiology and a		7	15%
	resting potential, action potential, bioelectric po			
	cardiovascular dynamics, electrode theory, bipolar a			
	polar electrodes, surface electrodes, physi	ological		
	transducers. Systems approach to biological systems.			
TT	Pipelestria potential and condiaversaling recommend	o EMC	6	150/
	Bioelectric potential and cardiovascular measurement		6	15%
	- Evoked potential response, EEG, foetal monito			
	phonocardiography, vector cardiograph, BP, bloc			
	cardiac output, plethysmography, impedance card	liology,		
	cardiac arrhythmia's, pace makers, defibrillators.			
	FIRST INTERNAL EXAMINATIO			1 50/
III	Respirator and pulmonary measurements and rehabi	litation:	7	15%

	Physiology of respiratory system, respiratory rate		
	Physiology of respiratory system, respiratory rate measurement, artificial respirator, oximeter, hearing aids,		
	1 1 0		
	functional neuromuscular simulation, physiotherapy,		
	diathermy, nerve stimulator, artificial kidney machine.		
IV	Patient monitoring systems: Intensive cardiac care, bedside	7	15%
	and central monitoring systems, patient monitoring through		
	bio-telemetry, implanted transmitters, telemetering multiple		
	information. Sources of electrical hazards and safety		
	techniques.	N.A.	
	SECOND INTERNAL EXAMINATION	IVI	
V	Clinical Flame photometer - spectrophotometer -	7	20%
	Colorimeter- chromatography- Automated Biochemical	4	
	analysis system - Blood Gas Analyzer: Blood pH	A day	
	Measurement- Measurement of Blood pCO2- Blood pO2		
	Measurement- Blood Cell Counters: Types and Methods of		
	cell Counting.		
VI	Recent trends: Medical imaging, X-rays, laser applications,	8	20%
	ultrasound scanner, echo cardiography, CT Scan MRI/NMR,		
	cine angiogram, colour doppler systems, Holter monitoring,		
	endoscopy.		
	END SEMESTER EXAMINATION		<u> </u>

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Module 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

Estd.

Part B

Answer any two out of three questions uniformly covering Module 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

2014

(15 x 2 = 30 marks)

(15 x 2 = 30 marks)

Exam Duration: 3 Hours

Part C

Answer any two out of three questions uniformly covering Module 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course code		Course name		L-T-P- Credits	Year of Introduction
AE405	ADVA	NCED CONTROL	THEORY	3-0-0-3	2016
	site: AE301 Con				-010
Course of					
	0	theory required for sol	ving complex contro	l problem	5.
	•	modelling of systems	0 1	- p	
Syllabus					
Concept o function a		inear time varying systory ov stability analysis –			
Expected	and the second sec	-N()		AI	
-		emester students will h	nave comprehensive l	nowledge	e in advanced
	ntrol theory.		RALLA		
	ks/Reference bo	ooks	INOT L 1		_
1. C.	D. Johnson, Pre	ocess Control Instru <mark>me</mark>	ntation Technology,	7th ed., Pr	entice Hall of
Inc	dia, New Delhi, 1	2003			
	0	e Time Control Syste <mark>m</mark> s			
		Control Engineering"			
		n Control System Th <mark>e</mark> c	ory",New Age Interna	tional Pul	olishers, 2 nd
	ition,1996				
	01 0	ital control and state v			F1
		H. Bishop, <i>Modern Co</i>	ontrol Systems, 8th ed	., Pearson	Education,
De	elhi, 2004	Course	Plan		
		Course	1 1411		Semester
Module		Contents		Hou	
					Marks
	Concept of stat	te space-state space re	presentation of system	n, 6	Marks 15%
I	-	te space-state space re ne invariant state equ		,	
I	solution of tir		ation- state transition	n	
I	solution of tir matrix. Linear space represen	ne invariant state equitime varying system. tation and solution.	ation- state transitio Discrete system sta	on te	15%
I	solution of tin matrix. Linear space represen Non-linear sys	ne invariant state equi- time varying system. tation and solution. stem, types of non-lir	ation- state transition Discrete system state nearity, singular point	nt, 6	
	solution of tin matrix. Linear space represen Non-linear syst	ne invariant state equi- time varying system. tation and solution. stem, types of non-lir tem stability analysis-	ation- state transition Discrete system state nearity, singular point phase plane technique	nt, 6	15%
	solution of tin matrix. Linear space represen Non-linear syst	ne invariant state equi- time varying system. tation and solution. stem, types of non-lir	ation- state transition Discrete system state nearity, singular point phase plane technique	nt, 6	15%
	solution of tin matrix. Linear space represen Non-linear syst	ne invariant state equ time varying system. tation and solution. stem, types of non-lir tem stability analysis- f phase trajectories, iso	ation- state transition Discrete system state mearity, singular point phase plane technique pocline method.	nt, 6	15%
I	solution of tin matrix. Linear space represen Non-linear syst non-linear syst construction of	ne invariant state equ time varying system. tation and solution. stem, types of non-lir tem stability analysis- f phase trajectories, isc FIRST INTERNAL	ation- state transition Discrete system state hearity, singular point phase plane technique poline method.	nte it, 6 e, 7	15%
П	solution of tin matrix. Linear space represen Non-linear syst non-linear syst construction of Describing fun	ne invariant state equ time varying system. tation and solution. stem, types of non-lin tem stability analysis- f phase trajectories, isc FIRST INTERNAL action analysis : Basic	ation- state transition Discrete system state mearity, singular point phase plane technique poline method. EXAMINATION concepts, derivation	nte it, 6 e, 7	15%
П	solution of tin matrix. Linear space represen Non-linear syst non-linear syst construction of Describing fun	ne invariant state equ time varying system. tation and solution. stem, types of non-lir tem stability analysis- f phase trajectories, isc FIRST INTERNAL	ation- state transition Discrete system state mearity, singular point phase plane technique poline method. EXAMINATION concepts, derivation	nte it, 6 e, 7	15%
П	solution of tir matrix. Linear space represen Non-linear syst construction of Describing fun describing fund	ne invariant state equ time varying system. tation and solution. stem, types of non-lin tem stability analysis- f phase trajectories, isc FIRST INTERNAL action analysis : Basic	ation- state transition Discrete system state mearity, singular point phase plane technique ocline method. EXAMINATION concepts, derivation m-linearities	nte it, 6 e, 7	15%
	solution of tin matrix. Linear space represen Non-linear syst non-linear syst construction of Describing fun describing fun Describing fun	ne invariant state equ time varying system. tation and solution. stem, types of non-lir tem stability analysis- f phase trajectories, isc FIRST INTERNAL action analysis : Basic ctions for common nor	ation- state transition Discrete system state mearity, singular point phase plane technique ocline method. EXAMINATION concepts, derivation m-linearities non-linear systems	nte it, 6 e, 7	15%
П	solution of tin matrix. Linear space represen Non-linear syst construction of Describing fun describing fun Describing fun Conditions for	ne invariant state equitime varying system. tation and solution. stem, types of non-line tem stability analysis- f phase trajectories, isc FIRST INTERNAL action analysis : Basic ctions for common non inction analysis of	ation- state transition Discrete system state mearity, singular point phase plane technique ocline method. EXAMINATION concepts, derivation n-linearities non-linear systems oscillations.	on te it, 6 e, 7 of 7 –	15%
П	solution of tir matrix. Linear space represen Non-linear syst construction of Describing fund describing fund Describing fund Conditions for	ne invariant state equitime varying system. tation and solution. stem, types of non-line tem stability analysis- f phase trajectories, isc FIRST INTERNAL action analysis : Basic ctions for common non unction analysis of stability – Stability of	ation- state transition Discrete system state mearity, singular point phase plane technique ocline method. EXAMINATION concepts, derivation mon-linearities non-linear systems oscillations.	on te nt, 6 e, 7 of 7 - y, 7	15% 15% 15%
	solution of tin matrix. Linear space represen Non-linear syst construction of Describing fund describing fund Describing fund Conditions for	ne invariant state equitime varying system. tation and solution. stem, types of non-line tem stability analysis- f phase trajectories, isc FIRST INTERNAL action analysis : Basic ctions for common non unction analysis of stability – Stability of ability analysis- de	ation- state transition Discrete system state mearity, singular point phase plane technique ocline method. EXAMINATION concepts, derivation n-linearities non-linear systems oscillations. finition of stability y. Lyapunov stability	on te nt, 6 e, 7 of 7 - y, 7	15% 15% 15%

SECOND INTERNAL EXAMINATION

V	MIMO systems-controllability- Observability- Effect of pole-zero cancellation, Practical examples-controllable and uncontrollable systems-observable and unobservable systems. Optimal control system-definition- design using state variable feedback and error squared performance indices.	8	20%
VI	Z- Transform and digital control system- Z-transfer function- block diagram- signal flow graph- discrete root locus.	8 M	20%
	END SEMESTER EXAMINATION	A	

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

Estd

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

14

Course	Course 1	ame	L-T	-P-	Year of
code			Cre	dits	Introduction
AE407	DIGITAL CONTI		3-0-	-0-3	2016
	site: AE301 Control system	l			
Course o	0				
	study the stability analysis	•			
	equip the basic knowledge	of digital process c	ontrol design		
Syllabus			2 A T .		· · –
	Data Control Systems - Sig				
	- Digital control systems- P				
	f discrete systems - State sp outcome	ace representation -	Controllabil	ity and O	
-	the end of the semester Stu	dents will have kno	wledge of di	rital proc	ess control
	sign.	dents will have kno	wieuge of uig	gitai proc	
Text Boo	0	YLNO			
	C. Kuo, "Digital control sy	stems" (Second Ed	ition). Oxfo	rd Unive	rsity Press.
	07	(),		<i>J 2</i> ,
2. K	Ogatta, "Discrete Time con	trol systems ", 2nd	ed. (PHI),19	95	
3. M	. Gopal, "Digital Control sy	stems and state vari	iable methods	s", Tata N	/Ic Graw Hill.
Referenc					
	hn Dorsey, "Continuous &			/	
2. N	agrath & Gopal , "Control S	<u> </u>	(Wiley East	ern).	
		Cour <mark>se</mark> Plan			
					Semester
Module	Ca	ontents		Hours	Exam
I	Introduction: Basic Elem	ants of discrete d	lata control	6	Marks
1	systems, advantages of c			0	1370
	examples.		or systems,		17 <mark>-</mark>
	Signal conversion & proces	sing: Digital signal	s & coding		
	0 1	sing. Digital signal	is a counig.		
	data conversion & quantization		-		
	data conversion & quantiza Mathematical modeling o	ation, sample and h	old devices,	1	
	-	ation, sample and h f the sampling pr	old devices, ocess; Data		
	Mathematical modeling o	ation, sample and h f the sampling pr of sampled signals	old devices, ocess; Data		
	Mathematical modeling or reconstruction and filtering hold, first order Hold and p	ation, sample and h f the sampling pr of sampled signals olygonal hold.	old devices, ocess; Data : Zero order		
II	Mathematical modeling or reconstruction and filtering hold, first order Hold and p Review of Z transform.	ation, sample and h f the sampling pr of sampled signals olygonal hold. z transform and	old devices, ocess; Data : Zero order inverse z	6	15%
II	Mathematical modeling or reconstruction and filtering hold, first order Hold and p Review of Z transform. transform . Relationship be	ation, sample and h f the sampling pr of sampled signals olygonal hold. z transform and tween s- plane and	old devices, ocess; Data : Zero order inverse z z- plane-	6	15%
II	Mathematical modeling or reconstruction and filtering hold, first order Hold and p Review of Z transform. transform . Relationship be Difference equation . S	ation, sample and h f the sampling pr of sampled signals olygonal hold. z transform and tween s- plane and	old devices, ocess; Data : Zero order inverse z z- plane-	6	15%
II	Mathematical modeling or reconstruction and filtering hold, first order Hold and p Review of Z transform. transform . Relationship be	ation, sample and h f the sampling pr of sampled signals olygonal hold. z transform and tween s- plane and	old devices, ocess; Data : Zero order inverse z z- plane-	6	15%
II	Mathematical modeling or reconstruction and filtering hold, first order Hold and p Review of Z transform. transform . Relationship be Difference equation . S transform.	ation, sample and h f the sampling pr of sampled signals olygonal hold. z transform and tween s- plane and olution by recurs	old devices, ocess; Data : Zero order inverse z z- plane- ion and z-	6	15%
	Mathematical modeling or reconstruction and filtering hold, first order Hold and p Review of Z transform. transform . Relationship be Difference equation . S transform. FIRST IN	ation, sample and h f the sampling pr of sampled signals olygonal hold. z transform and tween s- plane and olution by recurs	old devices, ocess; Data : Zero order inverse z z- plane- ion and z- NATION		
II	Mathematical modeling of reconstruction and filtering hold, first order Hold and p Review of Z transform. transform . Relationship be Difference equation . S transform. FIRST IN Digital control systems-	ation, sample and h f the sampling pro of sampled signals olygonal hold. z transform and tween s- plane and olution by recurs TERNAL EXAMI Pulse transfer fu	old devices, ocess; Data : Zero order : inverse z z- plane- ion and z- NATION unction . z	6	20%
	Mathematical modeling or reconstruction and filtering hold, first order Hold and p Review of Z transform. transform . Relationship be Difference equation . S transform. FIRST IN Digital control systems- transform analysis of clo	ation, sample and h f the sampling pro- of sampled signals olygonal hold. z transform and tween s- plane and olution by recurse TERNAL EXAMI Pulse transfer fu- sed loop open loop	old devices, ocess; Data : Zero order		
	Mathematical modeling or reconstruction and filtering hold, first order Hold and p Review of Z transform. transform . Relationship be Difference equation . S transform. FIRST IN Digital control systems- transform analysis of clo Modified z- transfer funct	ation, sample and h f the sampling pro- of sampled signals olygonal hold. z transform and tween s- plane and olution by recurse TERNAL EXAMI Pulse transfer fu- sed loop open loop	old devices, ocess; Data : Zero order		
	Mathematical modeling or reconstruction and filtering hold, first order Hold and p Review of Z transform. transform . Relationship be Difference equation . S transform. FIRST IN Digital control systems- transform analysis of clo	ation, sample and h f the sampling pro- of sampled signals olygonal hold. z transform and tween s- plane and olution by recurse TERNAL EXAMI Pulse transfer fu- sed loop open loop	old devices, ocess; Data : Zero order		
	Mathematical modeling or reconstruction and filtering hold, first order Hold and p Review of Z transform. transform . Relationship be Difference equation . S transform. FIRST IN Digital control systems- transform analysis of clo Modified z- transfer funct	tion, sample and h f the sampling pr of sampled signals olygonal hold. z transform and tween s- plane and olution by recurs TERNAL EXAMI Pulse transfer fu sed loop open loc ion- Stability of li	old devices, ocess; Data : Zero order inverse z z- plane- ion and z- <u>NATION</u> inction . z op systems- near digital		

	phase margin		
	SECOND INTERNAL EXAMINATION		
V	Review of state space techniques to continuous data systems, state space representation of discrete time systems- Transfer function from state space model-various canonical forms- conversion of transfer function model to state space model-characteristics equation- solution to discrete state equations.	7	15%
VI	Controllability and Observability - Response between sampling instants using state variable approach-Pole placement using state feedback . Dynamic output feedback- Effects of finite wordlength on controllability and closed loop pole placement-	7 IV [A]	15%
	END SEMESTER EXAMINATION	1	

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course	Course name	L-T-P-	Year of
code		Credits	Introduction
AE409	OPTICAL INSTRUMENTATION	3-0-0-3	2016
Prerequi			
	bjectives		
	o understand the basic concepts of fiber optics.		
	o study optical communication and optical instruments.		
	provide basic knowledge in Laser and its application.	TAX	4
Optical d Interferer Semicond • A op Text Boo 1. G 2. J. In 3. Jc 4. Jc Ed 5. K	of Optical fiber - Numerical aperture - Types of optical letectors - Fibre optic sensors - Different types of mode ince filters - Optical spectrum analyzer - Lasers ductor lasers - Laser Doppler Anemometry - Medical app I outcome t the end of the semester the students will have knowledge optical instrumentation techniques. bks/Reference books . Keiser, "Optical Fibre Communication", McGraw Hill, Wilson and J.F.B.Hawkes , "Optoelectronics: An Introduce dia. ohn F. Ready, "Industrial Applications of Lasers", Academ ohn M. Senior, "Optical Fiber Communications-Principles ducation Limited. . Thygarajan and A.K.Ghatak , "Lasers: Theory and Appli	lulators – In - Populati lication of la ge of optical 1995. ction", Pren nic Press, 19 s and Practic	nterferometers - on inversion - asers. fiber and tice Hall of 078. ce", Pearson
	.Svelto, "Principles of Lasers ",Plenum Press.		
	Cour <mark>se</mark> Plan		
Module	Contents	Hours	Semester
		/	Exam Marks
I	Principle of Optical fiber – Acceptance angle and acceptance cone –Numerical aperture – V-number – Types of optical fibers (Material, Refractive index and mode) – properties- Optical sources-Optical detectors. Optical fiber production and fabrication.	6	15%
П	Fibre optic sensors – Fibre optic instrumentation system for measurement of fibre characteristics – Different types of modulators – Interferometric method for measurement of length – Moire fringes – Measurement of pressure, temperature, current, voltage, liquid level and strain – fiber optic gyroscope. Source coupling- Fiber connection-Splicing Techniques.	8	15%
	FIRST INTERNAL EXAMINATION	N	
III	Interferometers – Fabry – perot and Michelson interferometers – Interference filters – Interferometeric method of measurement – Interference filters – Interferometeric method of	7	15%

IV	Lasers – Principles of operation – Einstein relations –	6	15%
	Population inversion – Optical feedback – laser modes		
	– Classes of laser – Solid state, gas and liquid dye		
	lasers– Semiconductor lasers – Q-switching and mode		
	locking – Properties of laser light.		
	SECOND INTERNAL EXAMINATIO	DN	
V	Laser applications: Laser for measurement of distance, length, atmospheric effect and pollutants-Laser	8	20%
	Doppler Anemometry (LDA) - Material processing: Laser heating, Melting, Scribing, Trimming, Welding.	LAN	1
VI	Medical application of lasers- Laser and Tissue interaction-Laser diagnosis-Laser instruments for microsurgery, Removal of tumors of vocal chords, Brain surgery, dermatology, Oncology and	7 A Y	15%
	Ophthalmology.		
	END SEMESTER EXAMINATION		

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

Estd.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)

2014

Course		L-T-P-	Year of
code		Credits	Introduction
AE410		3-0-0-3	2016
Prerequis			
Course O	0		
	introduce the basics of Power generation	.1 1	
	enable the design of power plant control using various n	nethods	_
Syllabus	A DI A DEDUITA A CAL		
-	methods of power generation-Boiler -P & I diagram o	the second s	
	turbine-Measurements in power plants -Controls in bo	oiler-Nucle	ear power plant
instrumen		A	
Expected		SA	1.5
	of the semester students will be	1	
	miliar with the basics of Power plant and power generation		
	miliar with the design of Analysers and control loops used	in power	plant.
Text Bool			
	ll A.B, "Power Plant Performance", Butterworth, London		
	C Martin, I.W Hannah, "Modern Power Station Prac	<i>ctice</i> ", Bri	tish Electricity
	ernational Vol. 1 & VI, Pergamon Press, London, 1992.		
3. Sa	m. G.Dukelow, " <i>The Control of Boilers</i> ", 2nd Edition, ISA	A Press, No	ew York, 1991
Reference			
1 1)_			
	vid Lindsley, "Boiler Control Systems", McGraw Hill, Ne		
2. Jer	vis M.J, "Power Station Instrumentation", Butterworth H	einemann,	Oxford, 1993.
 Jer Mo 	vis M.J, " <i>Power Station Instrumentation</i> ", Butterworth Ho odern Power Station Practice, Vol.6, " <i>Instrumentation</i> ,	einemann,	Oxford, 1993.
 Jer Mo 	vis M.J, " <i>Power Station Instrumentation</i> ", Butterworth Ho odern Power Station Practice, Vol.6, " <i>Instrumentation</i> , rgamon Press, Oxford, 1971.	einemann,	Oxford, 1993.
 Jer Mo 	vis M.J, " <i>Power Station Instrumentation</i> ", Butterworth Ho odern Power Station Practice, Vol.6, " <i>Instrumentation</i> ,	einemann,	Oxford, 1993. and Testing",
2. Jer 3. Mo Per	vis M.J, " <i>Power Station Instrumentation</i> ", Butterworth Ho odern Power Station Practice, Vol.6, " <i>Instrumentation</i> , rgamon Press, Oxford, 1971. Course Plan	einemann, Controls	Oxford, 1993. and Testing", Semester
 Jer Mo 	vis M.J, " <i>Power Station Instrumentation</i> ", Butterworth Ho odern Power Station Practice, Vol.6, " <i>Instrumentation</i> , rgamon Press, Oxford, 1971.	einemann,	Oxford, 1993. and Testing", Semester Exam
2. Jer 3. Mo Per Module	vis M.J, " <i>Power Station Instrumentation</i> ", Butterworth Ho odern Power Station Practice, Vol.6, " <i>Instrumentation</i> , rgamon Press, Oxford, 1971. Course Plan	einemann, Controls Hou	Oxford, 1993. <i>and Testing</i> ", Semester Irs Exam Marks
2. Jer 3. Mo Per	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Brief survey of methods of power generation-hyd	einemann, Controls Hou	Oxford, 1993. and Testing", Semester Exam
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Brief survey of methods of power generation-hydronyce thermal, nuclear, solar and wind power	einemann, Controls Hou Iro, 6	Oxford, 1993. <i>and Testing</i> ", Semester Irs Exam Marks
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hydro- thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build	einemann, Controls Hou Iro, 6	Oxford, 1993. <i>and Testing</i> ", Semester Irs Exam Marks
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Brief survey of methods of power generation-hydronyce thermal, nuclear, solar and wind power	einemann, Controls Hou Iro, 6	Oxford, 1993. <i>and Testing</i> ", Semester Irs Exam Marks
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyd thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles	einemann, Controls Hou Iro, 6 ing	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyd thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system	einemann, Controls Hou Iro, 6 ing ms, 7	Oxford, 1993. <i>and Testing</i> ", Semester Irs Exam Marks
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyd thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S	einemann, <i>Controls</i> Hou Iro, 6 ing ms, 7 oot	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyd thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S blowers, combustion process, products of combustion, f	einemann, Controls Hou Iro, 6 ing ms, 7 oot	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyd thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S blowers, combustion process, products of combustion, f systems, treatment of flue gases, smoke dens	einemann, Controls Hou Iro, 6 ing ms, 7 oot Suel sity	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyd thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S blowers, combustion process, products of combustion, f systems, treatment of flue gases, smoke dens measurements, steam turbine, condensate system	einemann, Controls Hou Iro, 6 ing ms, 7 oot iuel sity ms, 7	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyd thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S blowers, combustion process, products of combustion, f systems, treatment of flue gases, smoke dens measurements, steam turbine, condensate system alternator, feed water conditioning, turbine bypass valve	einemann, Controls Hou Iro, 6 ing ms, 7 oot iuel sity ms, zes.	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyd thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S blowers, combustion process, products of combustion, f systems, treatment of flue gases, smoke dens measurements, steam turbine, condensate system alternator, feed water conditioning, turbine bypass valv Importance of instrumentation in power generation	einemann, Controls Hou Iro, 6 ing ms, 7 oot Suel sity ms, ves.	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyd thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S blowers, combustion process, products of combustion, f systems, treatment of flue gases, smoke dens measurements, steam turbine, condensate system alternator, feed water conditioning, turbine bypass valv Importance of instrumentation in power generation details of boiler processes, combined cycle power plate	einemann, Controls Hou Iro, 6 ing ms, 7 oot iuel sity ms, ves. - ant,	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyd thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S blowers, combustion process, products of combustion, f systems, treatment of flue gases, smoke dense measurements, steam turbine, condensate system alternator, feed water conditioning, turbine bypass valv Importance of instrumentation in power generation details of boiler processes, combined cycle power pla power generation and distribution, burner tilting, a	einemann, Controls Hou Iro, 6 ing ms, 7 oot iuel sity ms, ves. - ant,	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth He odern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyd thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S blowers, combustion process, products of combustion, f systems, treatment of flue gases, smoke dens measurements, steam turbine, condensate system alternator, feed water conditioning, turbine bypass valv Importance of instrumentation in power generation details of boiler processes, combined cycle power plate	einemann, Controls Hou Iro, 6 ing ms, 7 oot iuel sity ms, ves. - ant,	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth Hodern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyde thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S blowers, combustion process, products of combustion, f systems, treatment of flue gases, smoke dens measurements, steam turbine, condensate system alternator, feed water conditioning, turbine bypass valv Importance of instrumentation in power generation details of boiler processes, combined cycle power pla power generation and distribution, burner tilting, a bypass damper.	einemann, Controls Hou Iro, 6 ing ms, 7 oot iuel sity ms, ves. - ant,	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%
2. Jer 3. Mo Per Module I	vis M.J, "Power Station Instrumentation", Butterworth Hodern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyde thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S blowers, combustion process, products of combustion, f systems, treatment of flue gases, smoke dems measurements, steam turbine, condensate system alternator, feed water conditioning, turbine bypass valv Importance of instrumentation in power generation details of boiler processes, combined cycle power plat power generation and distribution, burner tilting, a bypass damper.	einemann, <i>Controls</i> Hou Iro, 6 ing ms, 7 oot Sity ms, 7 es. - ant, and	Oxford, 1993. and Testing", Semester Exam Marks 15%
2. Jer 3. Mo Per Module	vis M.J, "Power Station Instrumentation", Butterworth Hodern Power Station Practice, Vol.6, "Instrumentation, rgamon Press, Oxford, 1971. Course Plan Contents Brief survey of methods of power generation-hyde thermal, nuclear, solar and wind power Introduction to thermal power plant processes – build blocks - ideal steam cycles Boiler – types, Boiler - turbine units and its range system feed water systems, steam circuits, air preheating. S blowers, combustion process, products of combustion, f systems, treatment of flue gases, smoke dens measurements, steam turbine, condensate system alternator, feed water conditioning, turbine bypass valv Importance of instrumentation in power generation details of boiler processes, combined cycle power pla power generation and distribution, burner tilting, a bypass damper.	einemann, <i>Controls</i> Hou Iro, 6 ing ms, 7 oot Sity ms, 7 es. - ant, and	Oxford, 1993. and Testing", Semester Irs Exam Marks 15%

	System for pressure measuring devices, smoke and dust monitor, flame monitoring.Introduction to turbine supervising system, pedestal vibration, shaft vibration, eccentricity measurement.Installation of non-contracting transducers for speed measurement.		
IV	Measurements in power plants: Electrical measurements – current, voltage, power, frequency, power factor etc. – non electrical parameters – flow of feed water, fuel, air and steam with correction factor for temperature – steam pressure and steam temperature – drum level measurement – radiation detector – smoke density measurement – dust monitor.	AL	15%
	SECOND INTERNAL EXAMINATION		
V	Controls in boiler: Boiler drum level measurement methods, feed water control, soot blowing operation, steam temperature control, Coordinated control, boiler following mode operation, turbine following mode operation, selection between boiler and turbine following modes. Distributed control system in power plants interlocks in boiler operation. Cooling system, Automatic turbine runs up systems.	8	20%
VI	Nuclear power plant instrumentation: Piping and instrumentation diagram of different types of nuclear power plant, Nuclear reactor control loops, reactor dynamics, pulse channel and logarithmic instrumentation, control and safety instrumentation, reliability aspects.	7	20%
	END SEMESTER EXAMINATION		

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

Estd.

(15 x 2 = 30 marks)

Exam Duration: 3 Hours

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course	Course name	L-T-P-	Year of
code		Credits	Introduction
AE431	CONTROL SYSTEM AND SIGNAL PROCESSING	0-0-3-1	2016
	LAB		
	site : AE301 & AE306		
Course o	0		
	give hands on experience in various digital Signal Processin		es using TMS
	OC6X family processors and in control system analysis using	MATLAB.	
	xperiments	NA.	
	OL SYSTEM LAB using MATLAB	1111	
	Familiarization of MATLAB commands used in control syste		
2.	Representation of system in MATLAB: state space represent	ation & tra	nsfer function
	representation		
	Stability analysis using Bode plot, root locus & their pole-ze		
4.		ethod for Is	t order system.
5.		1	
6.		nk.	
	Pole placement technique applied to stabilize a system.		
	Realization of a compensator design.		
	Modelling and analysis of a first order system.	plata avata	m ata)
	. Modelling of an unstable system (inverted pendulum, ball & ed Control	plate syste	III etc.)
	PLC programming: familiarization of instruction set.		
	PLC programming: simulation of process control.		
2.			
6.	Familiarization of Distributed Control System (DCS) with di	ifferent pro	cess stations
	pressure, flow and level.	inerent pro-	
LabVIE	W based Virtual Instrumentation		
	Getting started with LabVIEW: Basic operations, controls, in	ndicators, a	nd simple
	Programming structures.		F F
2.	Debugging a VI and sub-VI.		
	Familiarization of DAO card.		
	PROCESSING LAB Esto.		
1.	Familiarization of signal processing commands used in MAT	LAB Softw	vare.
2.	Developing elementary signal function modules (m-files) for	r unit impul	lse, step,
	exponent and ramp sequence.		
3.	Generating continuous and discrete time sequences.		
	Carrying out mathematical operations on signals.		
5.	Response of LTI system described by difference and differen	itial equation	on.
6.			
	Developing program for finding magnitude & phase respons	e of LTI Sy	stem
	Developing program for computing DFT & IDFT.		
	Developing a program for computing circular convolution.	•	• 、
	D. Design of filter: FIR, IIR, ECG Signal filter (can be done as	3 separate	experiments).
-	outcome		
	t the end of the semester students are expected to be familiar w	ith the basi	c signal
pr	ocessing & control system techniques.		

Course			Year of
code	Cree		ntroduction
AE461		0-3	2016
Prerequi			
	objectives		
	o introduce the concepts of embedded processors and ARM base	ed devel	opment.
Syllabus		. In at	mation Cat
	ed Computers - Embedded System Design - ARM Architectur rocessor – Assembly programming - Component Interfacing		
	s - Peripherals In ARM Processors - Peripherals and their cont		
	als - Arm Procedure Call Standard - Example C program.	101 - AI	tivi tools and
	l outcome	AL	
-	t the end of the semester students must be able to obtain compre	hensive	knowledge
	n embedded processors and ARM based system.		into wreage
Text Boo			
	teve Furber, "ARM system on Chip Architecture", 2nd Edition, A	1ddison	Weslev
	ublishers, 2013		2
2. W	Nayne Wolf, "Computers as Components Principles of Embedd	ed Com	outing
Sj	ystem Design", Morgan Kaufman Publishers, 2001		
Referenc			
1 D			
I. D	avid Seal, "ARM Architecture Reference Manual", 2nd Edition,	Addisor	n Wesley
Pu	ublishers, 2001		
Pu			
Pu 2. Fi	ublishers, 2001		
Pu 2. Fi	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>lardware/Software Introduction</i> ", John Wiley Sons, 2000.		
Pu 2. Fi	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design -</i> A		1
Pu 2. Fi <i>H</i>	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>Tardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan	l Unified	d Semester
Pu 2. Fi <i>H</i>	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>lardware/Software Introduction</i> ", John Wiley Sons, 2000.		l Semester s Exam
Pu 2. Fi H	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>lardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents	Unified	d Semester s Exam Marks
Pu 2. Fi H	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>Vardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded	Unified	l Semester s Exam
Pu 2. Fi H Module	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>lardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded	Unified	d Semester s Exam Marks
Pu 2. Fi H Module	ublishers, 2001 rank Vahid and Tony. D.Givargis, "Embedded System Design - A Pardware/Software Introduction", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process	Unified	d Semester s Exam Marks
Pu 2. Fi H Module	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>lardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification	1 Unified Hours 6	d Semester s Exam Marks 15%
Pu 2. Fi H Module I	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>ardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture.	1 Unified Hours 6	d Semester s Exam Marks
Pu 2. Fi H Module	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>ardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture. Bus structure and the peripherals. Register set, Exception	1 Unified Hours 6	d Semester s Exam Marks 15%
Pu 2. Fi H Module	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>ardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture.	1 Unified Hours 6	d Semester s Exam Marks 15%
Pu 2. Fi H Module	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>ardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture. Bus structure and the peripherals. Register set, Exception modes, Software Interrupt.	1 Unified Hours 6	d Semester s Exam Marks 15%
Pu 2. Fi H Module I II	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>ardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture. Bus structure and the peripherals. Register set, Exception modes, Software Interrupt.	Hours 6 6	d Semester S Exam Marks 15%
2. Fr H Module I II	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>lardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture. Bus structure and the peripherals. Register set, Exception modes, Software Interrupt. FIRST INTERNAL EXAMINATION ARM Processor – Memory organization and processor	Hours 6 6 8	d Semester s Exam Marks 15%
2. Fr H Module I II	ublishers, 2001 rank Vahid and Tony. D.Givargis, "Embedded System Design - A Vardware/Software Introduction", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture. Bus structure and the peripherals. Register set, Exception modes, Software Interrupt. FIRST INTERNAL EXAMINATION ARM Processor – Memory organization and processor initialization [start up code]. Load store instruction set.	Hours 6 6 8	d Semester S Exam Marks 15%
2. Fr H Module I II	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>ardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture. Bus structure and the peripherals. Register set, Exception modes, Software Interrupt. FIRST INTERNAL EXAMINATION ARM Processor – Memory organization and processor initialization [start up code]. Load store instruction set. Assembly programming using Assemblers, Linkers, Loaders	Hours 6 6 8	d Semester S Exam Marks 15%
2. Fr H Module I II	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>Vardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture. Bus structure and the peripherals. Register set, Exception modes, Software Interrupt. FIRST INTERNAL EXAMINATION ARM Processor – Memory organization and processor initialization [start up code]. Load store instruction set. Assembly programming using Assemblers, Linkers, Loaders and Debuggers.	Hours 6 6 8	d Semester S Exam Marks 15%
Pu 2. Fi H Module I II	ublishers, 2001 rank Vahid and Tony. D.Givargis, "Embedded System Design - A ardware/Software Introduction", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture. Bus structure and the peripherals. Register set, Exception modes, Software Interrupt. FIRST INTERNAL EXAMINATION ARM Processor – Memory organization and processor initialization [start up code]. Load store instruction set. Assembly programming using Assemblers, Linkers, Loaders and Debuggers. Component Interfacing – Designing with Microprocessor	Hours 6 6 8	d Semester S Exam Marks 15%
Pu 2. Fi	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>Vardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture. Bus structure and the peripherals. Register set, Exception modes, Software Interrupt. FIRST INTERNAL EXAMINATION ARM Processor – Memory organization and processor initialization [start up code]. Load store instruction set. Assembly programming using Assemblers, Linkers, Loaders and Debuggers.	Hours 6 6 8	d Semester S Exam Marks 15%
2. Fr H Module I II	ublishers, 2001 rank Vahid and Tony. D.Givargis, " <i>Embedded System Design - A</i> <i>ardware/Software Introduction</i> ", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture. Bus structure and the peripherals. Register set, Exception modes, Software Interrupt. FIRST INTERNAL EXAMINATION ARM Processor – Memory organization and processor initialization [start up code]. Load store instruction set. Assembly programming using Assemblers, Linkers, Loaders and Debuggers. Component Interfacing – Designing with Microprocessor Development and Debugging – Design Example Alarm Clock	Hours 6 6 8	d Semester S Exam Marks 15%
2. Fr H Module I II	ublishers, 2001 rank Vahid and Tony. D.Givargis, "Embedded System Design - A ardware/Software Introduction", John Wiley Sons, 2000. Course Plan Contents Embedded Computers – Characteristics of Embedded Computing Applications–Challenges in Embedded Computing. Embedded System Design –Process Requirements – Specification ARM Architecture: The ARM Instruction Set Architecture. Bus structure and the peripherals. Register set, Exception modes, Software Interrupt. FIRST INTERNAL EXAMINATION ARM Processor – Memory organization and processor initialization [start up code]. Load store instruction set. Assembly programming using Assemblers, Linkers, Loaders and Debuggers. Component Interfacing – Designing with Microprocessor	Unified Hours 6 6 8 8 8 8	d Semester Exam Marks 15% 15%

	control and touch monitoring		
	SECOND INTERNAL EXAMINATION		
V	Peripherals In ARM Processors: ARM / THUMB architecture. Program structure to Supervisor, Kernel, and User modes. Peripherals and their control: GPIO, Timers, Counters, PWM, ADC and serial communication channels.	7	20%
VI	ARM tools and Peripherals: ARM Development Environment, Arm Procedure Call Standard (APCS), Example C program.	7	20%
	END SEMESTER EXAMINATION		

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

014

Estd.

code	Course name L-T-H Credi		Year of troduction
AE462	OPTIMAL CONTROL SYSTEM 3-0-0-		2016
Prerequis		5	2010
Course O			
	formulate various types of optimal control problems		
	learn calculus of variations and dynamic programming for solv	ving onti	mal control
	blems	ving opti	inal control
Syllabus		A A	
•	ontrol problem formulation. Dynamic optimization- Uncons	strained	Problems -
-	of Variations. Continuous time and Discrete time Linear Qua		
	problems-LQG Problems. Constrained Problems- Pontryagin's		
	Programming-Constrained Problems.	1.4	
Expected			
-	nts will be able to		
	derstand the concepts related to calculus of variations and optim	nal contro	ol theory
	ply the optimal control concepts to formulate and solve various		•
-	blems	51	
Text Bool			
1. Do	nald E. Kirk, Optimal Control Theory: An Introduction, Prentic	e-Hall ne	etworks
ser	ies, 1970		
2. M.	Gopal, "Modern Control System Theory", Wiley Eastern, New	Delhi, se	cond
Ed	ition, 1993		
Reference	s:		
1. Br	an D O Anderson and John B Moor <mark>e,</mark> "Optimal Control - Linea	ır Quadra	tic
	thods", Prentice Hall of India, 1991		
	sineni Subbaram Naidu, Optimal Control System, CRC press		
3. Sa			
	ge.A.P & White.C.C, Optimum Systems Control, Prentice Hall		
	ge.A.P & White.C.C, Optimum Systems Control, Prentice Hall Course Plan		
	Course Plan		Semester
Module		Hours	Exam
	Course Plan Contents		Exam Marks
Module I	Course Plan Contents Optimal control problem - Problem formulation -	Hours 4	Exam
	Course Plan Contents Optimal control problem - Problem formulation - Mathematical model - Physical constraints - Performance		Exam Marks
	Course Plan Contents Optimal control problem - Problem formulation - Mathematical model - Physical constraints - Performance measure - Optimal control problem - Form of optimal		Exam Marks
	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem		Exam Marks
	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure -Open loop and closed		Exam Marks
	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure -Open loop and closed loop form of optimal control. Performance measures for		Exam Marks
	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure -Open loop and closed loop form of optimal control. Performance measures for optimal control problems – General form of performance		Exam Marks
I	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure -Open loop and closed loop form of optimal control. Performance measures for optimal control problems – General form of performance measure	4	Exam Marks 15%
	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure -Open loop and closed loop form of optimal control. Performance measures for optimal control problems – General form of performance measure Fundamental concepts and theorems of calculus of variations		Exam Marks
I	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure -Open loop and closed loop form of optimal control. Performance measures for optimal control problems – General form of performance measure Fundamental concepts and theorems of calculus of variations – Euler - Lagrange equation and extremal of functionals -	4	Exam Marks 15%
I	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure -Open loop and closed loop form of optimal control. Performance measures for optimal control problems – General form of performance measure Fundamental concepts and theorems of calculus of variations – Euler - Lagrange equation and extremal of functionals - the variational approach to solving optimal control problems	4	Exam Marks 15%
I	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure -Open loop and closed loop form of optimal control. Performance measures for optimal control problems – General form of performance measure Fundamental concepts and theorems of calculus of variations – Euler - Lagrange equation and extremal of functionals - the variational approach to solving optimal control problems	4	Exam Marks 15%
I	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure -Open loop and closed loop form of optimal control. Performance measures for optimal control problems – General form of performance measure Fundamental concepts and theorems of calculus of variations – Euler - Lagrange equation and extremal of functionals - the variational approach to solving optimal control problems - Hamiltonian and different boundary conditions for optimal	4	Exam Marks 15%
I	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure -Open loop and closed loop form of optimal control. Performance measures for optimal control problems – General form of performance measure Fundamental concepts and theorems of calculus of variations – Euler - Lagrange equation and extremal of functionals - the variational approach to solving optimal control problems - Hamiltonian and different boundary conditions for optimal control problem	4	Exam Marks 15% 15%
I	Course Plan Contents Optimal control problem - Problem formulation - Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure - Open loop and closed loop form of optimal control. Performance measures for optimal control problems – General form of performance measure Fundamental concepts and theorems of calculus of variations – Euler - Lagrange equation and extremal of functionals - the variational approach to solving optimal control problems - Hamiltonian and different boundary conditions for optimal control problem LINEAR QUADRATIC OPTIMAL CONTROLSYSTEM -	4	Exam Marks 15%
I	Course Plan Contents Optimal control problem - Problem formulation – Mathematical model – Physical constraints – Performance measure – Optimal control problem – Form of optimal control – Performance measures for optimal control problem – Selection of performance measure -Open loop and closed loop form of optimal control. Performance measures for optimal control problems – General form of performance measure Fundamental concepts and theorems of calculus of variations – Euler - Lagrange equation and extremal of functionals - the variational approach to solving optimal control problems - Hamiltonian and different boundary conditions for optimal control problem	4	Exam Marks 15% 15%

	Time-invariant case – Stability issues of Time-invariant regulator, Linear Quadratic Tracking system: Finite time case and Infinite time case— Optimal solution of LQR problem Different techniques for solution of algebraic Riccati equation LQG Problem		
IV	DISCRETE TIME OPTIMAL CONTROL SYSTEMS Variational calculus for Discrete time systems – Discrete time optimal control systems:-Fixed final state and open- loop optimal control and Free-final state and open-loop optimal control, Closed loop optimal control matrix difference Riccati equation – optimal cost function Discrete time linear state regulator system – Steady state regulator system	8 AL	20%
	SECOND INTERNAL EXAMINATION		
V	Dynamic Programming:- Principle of optimality, optimal control using Dynamic Programming –Interpolation-A recurrence relation of dynamic programming-Computational procedure for solving Control problems-Discrete linear regulator problems, Hamilton Jacobi-Bellman Equation – Continuous linear regulator problems	9	20%
VI	CONSTRAINED OPTIMAL CONTROL SYSTEMS – Pontryagin's minimum principle and sate inequality constraints –Minimum Time optimal problems Minimum control effort Problems – Optimal Control problems with State Constraints	7	20%
	END SEMESTER EXAMINATION		

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

Estd.

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

(15 x 2 = 30 marks)

Exam Duration: 3 Hours

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)

2014

Course	Course name	L-T-P-	Year of
code		Credits	Introduction
AE463	AEROSPACE & NAVIGATION INSTRUMENTS	3-0-0-3	2016
Prerequi Course (
	b introduce the basics of aerospace engineering		
	b impart ideas on aircraft and navigation instruments		
• 10	s impart ideas on anerart and navigation instruments		
Introduct Air spece Introduct acceleron Expected At the end i. be ii. ha Text Boo 1. N 2. Pa Reference 1. End D 2. Je Jo 3. M	l outcome d of semester, the students will e familiar with the basics of aerospace engg and navigation ave an idea about the instrumentation used in aerospace engi oks agaraja.M.S, Elements of electronic navigation, Tata McGra allet.E.H.J, Aircraft instruments- Principles and applications	neering w Hill s, Pitman	Pub tion and unnel Testing, ,
	Course Plan		
Module	Contents	Hou	rs Exam Marks
I	History of aviation and space flight- anatomy of airplan and space vehicle with emphasis on control surfaces- airfo nomenclature- basics of aerodynamics to illustrate lift and drag- types of drag – finite wings – swept wings –flaps.	oil	15%
Π	Airplane performance- thrust –power- rate of climb absolu and service ceiling- range and endurance. Introduction turbojet and turbofan engines. Space vehicle trajectorie Kepler's laws- rocket engines, propellants and stagin (Introductory treatment of the above topics is only expecte no detailed derivations)	to s- g.	15%
	FIRST INTERNAL EXAMINATION	1	I
III	Basic engine instruments- Capacitive fuel content- Gauge Standard atmosphere- Altimeters Aneroid and rad		15%

	altimeters.		
IV	Aircraft compass- Remote indicating magnetic compass- Rate of climb indicator- Pitot static system- Air speed	6	15%
	indicator- Mach meters- Integrated flight instruments		
	SECOND INTERNAL EXAMINATION		
V	GPS and GNSS, - Automatic Pilots- Aircraft flight	8	20%
	simulation instrumentation		
	Introduction to guidance, navigation and avionics- Radio navigational aids- automatic direction finder VHF- Phase- Comparison direction finder.	M	
VI	Introduction to navigation and guidance instrumentation-	8	20%
• •	Principle, construction and applications of inertial sensors-		2070
	Gyroscope and accelerometers- Ring laser gyroscope- Fibre		
	optic gyroscope, MEMS gyroscopes and accelerometers.		
	END SEMESTER EXAMINATION		1

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

2014

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course		L-T-P-		Year Of
code AE464		<u>Credits</u> 3-0-0-3		troduction
	ite : AE301 Control system	3-0-0-3	,	2016
Course of	•			
	familiarize the modelling of simple mechanical systems.			
	analyse stability of nonlinear control systems			
Syllabus	non linger system Common Nonlingerities in contra	ol avata		
	non-linear system - Common Nonlinearities in contra			
	nethod of iscoclanes- phase plane analysis of linear syst			
	ear systems- bendixon theorems - Describing Function			0
	of common nonlinearities - Concepts of Stability- Linear			•
	v's Direct Method - Generation of Lyapunov functions			
	ear control system design-stabilisation problems-track			
	ng non-linear controllers- available methods of non-linear	contro	i design	•
Expected		nd curt	omol	the
	the end of the semester students must be able to understa		-	une
	ferent behaviour of system performances and Stability teo	cnnique		
Text Bool		7 19	, D	TT . 11
	In Jacques Slotine and Weiping Li, "Applied Nonlinear C	ontrol	, Prenti	ce Hall
	2, 1991. K. Khalil "Narlinger Systems" Deerser Education 2 rd	ГJ		
	K. Khalil., "Nonlinear Systems", Pearson Education, 3 rd			L 4 J Marry
	Gopal "Digital Control and State Variable Methods", Tata	a McGr	aw-Hill	Ltd, New
	lhi, 2003.			
4. Na	goor Kani, "Advanced Control System", Rba Publication	IS		
	Cour <mark>se</mark> Plan			a (
M - JI-	Contents		T	Semester
Module	Contents			
			Hours	Exam Marla
т	Interdention I in an an linear and an li			Marks
Ι	Introduction: Linear vs non-linear system- non-lin	near 7		
I	systems and equilibrium points- non-linear sys	near 7 tem		Marks
I	systems and equilibrium points- non-linear systems behavior-examples-Common Nonlinearities in com	near 7 tem trol		Marks
Ι	systems and equilibrium points- non-linear systems behavior-examples-Common Nonlinearities in consystems-Autonomous and non-autonomous systems	near 7 tem ntrol ms-		Marks
I	systems and equilibrium points- non-linear systems-examples-Common Nonlinearities in consystems-Autonomous and non-autonomous systemodelling of simple pendulum- mass spring systems	near 7 tem ntrol ms-		Marks
	systems and equilibrium points- non-linear systems behavior-examples-Common Nonlinearities in consystems-Autonomous and non-autonomous system modelling of simple pendulum- mass spring system analysis and design of nonlinear system.	near 7 tem 1 ntrol 1 ms- em-		<u>Marks</u> 15%
I	systems and equilibrium points- non-linear systems-autonomous and non-autonomous systems-Autonomous and non-autonomous system of simple pendulum- mass spring systemalysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction	near 7 tem 1 trol		Marks
	systems and equilibrium points- non-linear systems and equilibrium points- non-linear systems-Autonomous and non-autonomous system modelling of simple pendulum- mass spring system analysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane analysis	near 7 tem 1 trol 1 ms- em- of 7 ysis		<u>Marks</u> 15%
	systems and equilibrium points- non-linear systems and equilibrium points- non-linear systems-Autonomous and non-autonomous system modelling of simple pendulum- mass spring systemalysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane analogi of non-linear systems- phase plane analysis of non-linear systems- phase plane analysis of non-linear systems- planear	near 7 tem htrol ms- em- of 7 ysis hear		<u>Marks</u> 15%
	systems and equilibrium points- non-linear systems-autonomous and non-autonomous systems-Autonomous and non-autonomous system modelling of simple pendulum- mass spring system analysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane analof linear systems- phase plane analysis of non-linear systems- local behaviour of non-linear systems-linear systems-linear systems-linear systems- linear sy	near 7 tem htrol ms- em- of 7 ysis hear		<u>Marks</u> 15%
	systems and equilibrium points- non-linear systems have behavior-examples-Common Nonlinearities in comsystems-Autonomous and non-autonomous system modelling of simple pendulum- mass spring systemalysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane analof linear systems- phase plane analysis of non-linear systems- local behaviour of non-linear systems-licycles- Stability- poincare- bendixon theorems.	near 7 tem 1 trol 1 ms- em- ysis 1 near 1 imit		<u>Marks</u> 15%
П	systems and equilibrium points- non-linear systems have behavior-examples-Common Nonlinearities in comsystems-Autonomous and non-autonomous system modelling of simple pendulum- mass spring system analysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane analor linear systems- phase plane analysis of non-linear systems-local behaviour of non-linear systems-licycles- Stability- poincare- bendixon theorems. FIRST INTERNAL EXAMINATION	near 7 tem 1 ms- em- of 7 ysis 1 near 1 imit		<u>Marks</u> 15% 15%
	systems and equilibrium points- non-linear systems-autonomous and non-autonomous system odelling of simple pendulum- mass spring system analysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane analof linear systems- phase plane analysis of non-linear systems- local behaviour of non-linear systems-licycles- Stability- poincare- bendixon theorems. FIRST INTERNAL EXAMINATION Describing Function: Describing Function: Examples and analysis function and analysis function fundamental function funct	near 7 tem 1 ms- em- 7 ysis 1 near 1 imit 1		<u>Marks</u> 15%
П	systems and equilibrium points- non-linear systems have behavior-examples-Common Nonlinearities in comsystems-Autonomous and non-autonomous system modelling of simple pendulum- mass spring system analysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane analof linear systems- phase plane analysis of non-linear systems- local behaviour of non-linear systems-licycles- Stability- poincare- bendixon theorems. FIRST INTERNAL EXAMINATION Describing Function: Describing Functions of common nonlinearities-hystem	near 7 tem htrol ms- em- 2 of 7 ysis near imit 1 1ls - 7 eris, 7		<u>Marks</u> 15% 15%
П	systems and equilibrium points- non-linear systems-autonomous and non-autonomous systems-Autonomous and non-autonomous system modelling of simple pendulum- mass spring system analysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane analor of linear systems- phase plane analysis of non-linear systems- local behaviour of non-linear systems-licycles- Stability- poincare- bendixon theorems. FIRST INTERNAL EXAMINATION Describing Function: Describing Function: Describing Function Fundamentar Describing functions of common nonlinearities-hyster backlash, relay, deadzone, saturation and combined effert	near 7 tem htrol ms- em- 2 of 7 ysis near imit 1 1ls - 7 eris, 7		<u>Marks</u> 15% 15%
П	systems and equilibrium points- non-linear systems have behavior-examples-Common Nonlinearities in comsystems-Autonomous and non-autonomous system modelling of simple pendulum- mass spring system analysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane analof linear systems- phase plane analysis of non-linear systems- local behaviour of non-linear systems-licycles- Stability- poincare- bendixon theorems. FIRST INTERNAL EXAMINATION Describing Function: Describing Functions of common nonlinearities-hystem	near 7 tem htrol ms- em- 2 of 7 ysis near imit 1 1ls - 7 eris, 7		<u>Marks</u> 15% 15%
II	systems and equilibrium points- non-linear systems have behavior-examples-Common Nonlinearities in comsystems-Autonomous and non-autonomous system modelling of simple pendulum- mass spring system analysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane anal of linear systems- phase plane analysis of non-linear systems- local behaviour of non-linear systems-licycles- Stability- poincare- bendixon theorems. FIRST INTERNAL EXAMINATION Describing Function: Describing Function: Describing Function Fundamentate backlash, relay, deadzone, saturation and combined efferstability analysis and limit cycles.	near 7 tem 1 ms- em- of 7 ysis 1 near 1 imit 1 als - 7 eris, 2 ects-		Marks 15% 15%
П	systems and equilibrium points- non-linear systems-autonomous and non-autonomous systems-Autonomous and non-autonomous systemodelling of simple pendulum- mass spring systemalysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane analor linear systems- phase plane analysis of non-linear systems- local behaviour of non-linear systems-licycles- Stability- poincare- bendixon theorems. FIRST INTERNAL EXAMINATION Describing Function: Describing Function Fundamenta Describing functions of common nonlinearities-hystems- backlash, relay, deadzone, saturation and combined effects ability analysis and limit cycles.	near 7 tem 1 ms- em- of 7 ysis near 1 imit 1 als - 7 eris, 2 ects- ew)- 7		<u>Marks</u> 15% 15%
II	systems and equilibrium points- non-linear systems-autonomous and non-autonomous systems-Autonomous and non-autonomous system modelling of simple pendulum- mass spring system analysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane anal of linear systems- phase plane analysis of non-linear systems- local behaviour of non-linear systems-licycles- Stability- poincare- bendixon theorems. FIRST INTERNAL EXAMINATION Describing Function: Describing Function Fundamentation Describing functions of common nonlinearities-hystem backlash, relay, deadzone, saturation and combined effects stability analysis and limit cycles.	near 7 tem 17 ms- em- 7 ysis 17 ysis 17 eris, 27 eris, 27 ium 7		Marks 15% 15%
II	systems and equilibrium points- non-linear systems-autonomous and non-autonomous systems-Autonomous and non-autonomous systemodelling of simple pendulum- mass spring systemalysis and design of nonlinear system. Phase Plane Analysis: Singular points-construction phase portraits- method of iscoclanes- phase plane analor linear systems- phase plane analysis of non-linear systems- local behaviour of non-linear systems-licycles- Stability- poincare- bendixon theorems. FIRST INTERNAL EXAMINATION Describing Function: Describing Function Fundamenta Describing functions of common nonlinearities-hystems- backlash, relay, deadzone, saturation and combined effects ability analysis and limit cycles.	near 7 tem 17 ms- em- 7 ysis 17 ysis 17 eris, 27 eris, 27 ium 7		Marks 15% 15%

	stability, Lyapunov's direct method, positive definite functions and Lyapunov functions, Lyapunov theorem for local stability and global stability		
	SECOND INTERNAL EXAMINATION		
V	Analysis based on Lyapunov's direct method-LTI systems- Krasovskii's method, Variable gradient method for constructing Lyapunov functions-simple examples, Popov's stability criterion. Stability of non-autonomous systems (basic concepts only)- Lyapunov's direct method – simple problems.	7 AI	20%
VI	Non-Linear control system design-stabilisation problems- tracking problems-relations between stabilization and tracking problems-desired behaviour of nonlinear systems- Issues in constructing non-linear controllers- available methods of non-linear control design.	7	20%
	END SEMESTER EXAMINATION		1

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

Estd.

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

2014

(15 x 2 = 30 marks)

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course code	Course name	L-T-P-Credits	Year of Introduction
AE465	INFORMATION SECURITY	3-0-0-3	2016
Prerequis			
Course O			
	understand the threat models and the basic type	es of authentication	mechanisms
	analyse cryptographic techniques, protocols, fo		
	analyse different log files and understand Cybe		
dat			na secure the
Syllabus	a.	ALAI	VI
•	on to security and services-Cryptography- Secur	ing the systems N	etwork security
	work perimeter security-Computer forensics and		ctwork security
Expected		u Cyber laws	
-	of the semester students will be able		
i.	to apply cryptographic algorithms to avoid data	accessing by una	uthorized users
ii.	to implement security algorithms as per the ne	.	
Text Book		eu or organization	
	ace Schneier, "Applied Cryptography", Second	Edition John Wild	w & Song 1006
	arlie Kaufman, Radia Perlman, and Mike Specifi		-
	mmunication in a Public World", 2nd Edition, F		2
	ek Lehtinen, G. T. Gangemi, SR.," <i>Computer See</i>	curity basics, sec	cond Edition,
Ur	Reilly Pubs, June 2006.		
Reference	Peaker		
		An Introduction D	nanti da Hall
	rije, "Computer Forensics and Cyb <mark>er</mark> Crime": 1	An introduction, P	rentice Hall,
200		6 7 • 1 N7 • 1	
	phen Northcutt, Karen Kent, and Lenny Zeltser	, Inside Network	Perimeter
	curity", Sams Publications, 200	aurite" Daurth Dd	itian Drantias
	lliam Stallings, "Cryptography and Network Ser	<i>curity</i> , Fourth Ed	luon, Prenuce
па	11, 2005		
	Course Plan		/
	Estu.		Semester
Module	Contents	Hour	s Exam
			Marks
Ι	Introduction to security and services, vulnerab	ilities and 6	15%
	countermeasures, malicious code, goals of	security-	
	prevention, detection, and recovery.		
II	Cryptography-Types of encryption, conf	identiality 6	15%
	using symmetric encryption, PKI,		
	RSA, Key management, Diffie- Hellman, E	ECC, CA,	
	etc., authentication protocols.		
	····,		
	FIRST INTERNAL EXAMIN	NATION	L
III	Securing the systems-Network security protoc		15%
	IPSEC, Kerberoes, X.509	,	
	Authentication service, Electronic mail	security	
	S/MME, Application security- SSL, PGP, SET		

IV	Network security topics: Network layer security – IPSec – overview, IP and IPv6, IPSec Protocols: AH and ESP, Tunnel Mode and transport mode. Internet Key exchange Protocol- IPSec cookies.	7	15%
	SECOND INTERNAL EXAMINATION		
V	Network perimeter security-Secured router configuration, firewall, design principles, trusted systems, VPN, IDS, IPS penetration testing, NAT.		20%
VI	Computer forensics and Cyber laws- data recovery, security policies and procedures, Security lifestyle management, security audit, managed security services.	8	20%
	END SEMESTER EXAMINATION		

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)

2014

Course code	Course name I	-T-P-Credits	Year of Introduction
AE466	INDUSTRIAL ROBOTICS	3-0-0-3	2016
Prerequis			
ToTo	familiarise automation and brief history of robot a study the kinematics of robots. give knowledge about robot end effectors and their	design.	-
	To learn about Robot Programming methods & Land	nguages of robot	·A
Basic conconsiderat	on and Robotics-configuration of robots-introduction ntrol system models-Robot actuation and fe ions in robot material handling- Robot Programmir e time analysis	edback compo	onents- General
Expected	outcome	A. A.	
	be equipped with the automation and brief history be familiarized with the kinematic motions of robo have good knowledge about robot end effectors ar s. Klafter, Thomas A. Chmielewski and Michael Ne atted Approach", Prentice Hall India, 2002	ot. ad their design co	oncepts.
Pu 2. K. Int 3. Mi	b S.R., " <i>Robotics Technology and Flexible Automo</i> blishing Co., Ltd., 1994. S. Fu., R.C.Gonalez, C.S.G.Lee, " <i>Robotics Control</i> elligence, McGraw Hill International Edition, 1987 kell P. Groover, Mitchell Weiss, " <i>Industrial Robotic</i> <i>d Applications</i> ", McGraw Hill International Edition	l Sensing ", Visi i <mark>cs, Technology,</mark>	on and Programming
	Course Plan		
Module	Contents	Hours	Semester Exam Marks
I	configuration of robots, joint notation schemes, volume, introduction to manipulator kiner	natics, everse in two ension, s, D-H	15%
П	Basic control system models, slew motion, j interpolated motion and straight line motion, cont like on/off, proportional, integral, proportional integral, proportional plus derivative, proportional integral plus derivative.	rollers 1 plus	15%

	FIRST INTERNAL EXAMINATION		1
III	Robot actuation and feedback components position and velocity sensors, actuators and power transmission devices, mechanical grippers, vacuum cups, magnetic grippers, pneumatic, electric, hydraulic and mechanical methods of power and control signals to end effectors.	7	15%
IV	General considerations in robot material handling, material transfer applications, pick and place operations, palletizing and related operations, machine loading and unloading, die casting, plastic molding, forging, machining operations, stamping press operations using robots.	7	15%
	SECOND INTERNAL EXAMINATION		
V	Robot Programming and AI: Methods - Languages - Computer control and Robot Software -VAL Language – Trajectory Planning, Basic robot motions - Point to point control & continuous path control and interpolations AI – Basics – Goals-AI Techniques – AI & Robotics.	7	20%
VI	Robot cell layouts , multiple robots and machine interface, other considerations in work cell design, work cell control, interlocks, error detection and recovery, work cell controller, robot cycle time analysis.	7	20%
	END SEMESTER EXAMINATION		

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

Estd.

2014

(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

Course		L-T-P-		ear of
code		Credits		oduction
AE467		3-0-0-3		2016
-	ite: EC204 Analog integrated circuits			
Course of	•	D:00	• • • •	· ~
	give ideas about basic amplifiers, current Mirrors and			
	impart idea of static and switching characteristics of t			
	study the operation of pass transistor logic and transm	•		
	analyse Operational Amplifiers on its design and stab		rs	
	familiarise different types of Memory and its decoder	Circuits	1.4.1	
Syllabus			A	~
	single stage MOS Amplifiers - current Mirrors - Dif			
	Sequential Logic Circuits- Different CMOS Fli			
	s- Stability and frequency compensation in Op amps			
	OS Circuit and Logic Design - Arithmetic Circuits i			
	Designing Memory and Array Structures- Designing C	Combinati	onal Log	ic Gates in
CMOS.				
Expected				
	the end of the semester students will be able to obtain	compreh	ensive kn	owledge
	CMOS Circuit Design.			
Text Bool			E 114	
	uglas A. Pucknell and K. Eshragian., "Basic VLSI Des	0		
2. 50	n P. Uyemura, "Introduction to VLSI Circuits and Sys	iems, jo.	in whey	& Sons
-	sshab K. Parhi, "VLSI DIGITAL SI <mark>G</mark> NAL PROCESS	NG SVS	TEMS"	John
	ley & Sons 2002		1 EIVIS ,	JOIIII
	il. H.E. Weste and K. Eshragian, "Principles of CMOS	S VLSI De	sion"? 1	nd Edition
	dison-Wesley, 2000.	, , LSI De	51811 . 21	
	Jacob Baker, Harry W. LI., & David K. Boyce., "CMC	DS Circuit	Design"	. 3 rd
	lian reprint, PHI, 2000.		8.	,
Reference	S Eated			
1. Jar	n M. Rabaey and et al, "DIGITAL INTEGRATED CIRC	<i>CUITS</i> ", P	earson E	dn. Inc.
20	03			
2. Ka	ng & Leblebigi "CMOS Digital IC Circuit Analysis &	Design"-	McGraw	^y Hill,
20				
3. We	este and Eshragh <mark>ian, "Princ</mark> iples of CMOS VLSI design	ı" <mark>A</mark> ddiso	n-Wesley	, 2002
	2014			
	Course Plan			~
				Semester
Module	Contents		Hours	Exam
.		<u>aa :</u>		Marks
Ι	Review of single stage MOS Amplifiers CS, CD,		6	15%
	cascode Amplifiers . Design of current Mirrors,			
	current mirrors and Widlar current mirrors. Ba	01		
	voltage reference Differential Amplifiers: MO	5 Load		
	Current Source, Current Mirror, Cascade Load.			
II	CMOS Inverter-Static Characteristics, Derivation for		7	15%
	LI WILLS INVERTER_STATIC Characteristics Derivation to	nr VIH	7	17%

	V IL and VIH Switching Characteristics and Calculation of		
	delay times Sequential Logic Circuits- Different CMOS Flip		
	flops Theory of operation and Circuits of Pass transistor		
	Logic and transmission gate.		
	FIRST INTERNAL EXAMINATION		
III	MOS Operational Amplifiers, Cascode and Folded Cascode	7	15%
	opamps. Stability and frequency compensation in Op amps.		
	Design of a two stage Op amp DRAM, SRAM, Sense		
	Amplifiers, Design of Row and Column Decoders Flash	N.A	
	Memory- NOR and NAND Flash Memory Cell	IVI	
	TECHNIQUARIC	A T	
IV	CMOS Circuit and Logic Design-CMOS Logic structures.	7	15%
	Advanced techniques in CMOS Logic Circuits-Mirror	h. And	
	circuits, Pseudo NMOS, Tri-state circuits, Clocked CMOS,		
	Dynamic CMOS Logic circuits, Dual Rail Logic Networks.		
	SECOND INTERNAL EXAMINATION		
V	Arithmetic Circuits in CMOS VLSI-Bit Adder Circuits,	8	20%
	Ripple Carry Adder, Carry Look Ahead Adders, Other High		
	speed adders-Multiplexer based fast binary adders,		
	Multipliers-Parallel multiplier, Wallace Tree and Dadda		
	multiplier, Low power design- Scaling Versus Power		
	consumption, Power reduction techniques.		
VI	Designing Memory and Array Structures - Memory	7	20%
	classification, Memory Core - Read Only Memories, Non-		
	volatile Read Write Memories, Read Write Memories,		
	Content - Addressable or Associative Memories, Memory		
	Peripheral Circuits - Address Decoders, Sense Amplifiers,		
	Designing Combinational Logic Gates in CMOS.		
	END SEMESTER EXAMINATION		

END SEMESTER EXAMINATION

QUESTION PAPER PATTERN:

Maximum Marks:100

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Exam Duration: 3 Hours

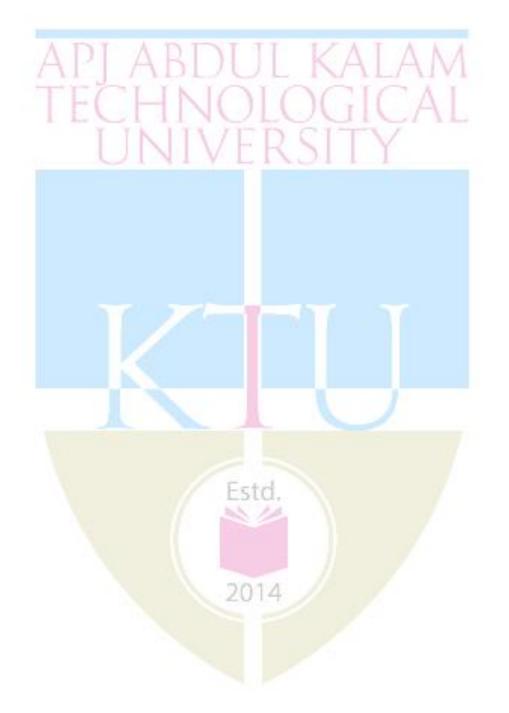
Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)



Course code	Course name	L-T-P-Credits		ear of oduction
AE468	NANO ELECTRONICS	3-0-0-3		2016
Course o	bjectives			
	impart the basic concepts of nanotechnology			
	o develop understanding about application of nation	nomaterials.		
Syllabus				
	on to nanotechnology and Nano electronic			
	ion to characterization tools of nano materials-			
	tures- The concept of super lattices Kronig	-	el of su	per lattice-
	tonic devices and systems- Nanocomposites- na	nominers	A	
-	l outcome t the end of the semester students will have good	d idaa ragarding	nono olor	tronios
	d their various applications.	u luca legaluling		uomes
Text boo	11			
	M. Martinez-Duart, R.J. Martin Palma, F. Agulle	Rueda "Nanotec	hnology	for
	<i>icroelectronics and optoelectronics</i> ", Elsevier,			0.
	.R. Fahrner,"Nanotechnology and Nanoelctronic		05	
Reference				
1. C	hattopadhyay,Banerjee, "Introduction to Nanosc	cience & Technol	ogy",PH	2009
	iwanand and Bharadwaj,"Nanoelectronics",Pent	•		
	oser, P. Glosekotter, J. Dienstuhl, "Nanoelectron	nics and nanosyst	<i>tems</i> ", Sp	ringer
	004.			
	bole, "Introduction to Nanotechnology ",John W		VOL	
	ilikel M. Ajayan," <i>Nanocomposite science and te</i>		-	
	apriyo Dutta, " <i>Quantum Transport- Atom to tran</i>	<i>isistor"</i> , Cambrid	ige Univ	ersity
	ress, 2005. Prodoon "Nano the Econotiale" TMH 2007			
7. T.	Pradeep, "Nano the Essentials", TMH, 2007. Course Plan			
	Course I fail			Semester
Module	Contents		Hours	Exam
lilouulo			110415	Marks
Ι	Introduction to nanotechnology and Nan	o electronics.	7	15%
	Impacts, Limitations of conventional m			
	Introduction to methods of fabrication of n		·	
	different approaches. fabrication of nano-la	yers -Physical		
	Vapor Deposition, Chemical Vapor Depos	ition, Epitaxy,		
	Molecular Beam Epitaxy, Ion Implantation,			
	Silicon Dioxide. Fabrication of nanoparticle-			
	iron balls, laser ablation, reduction methods	, sol gel, self-		
**	assembly.		-	1.501
II	Introduction to characterization tools of nar		6	15%
	principle of operation of STM, AFM, SEM, T			
	& UV instruments. Mesoscopic Nanotechnologies - trends in Microel	•		
	Optoelectronics, characteristic lengths in			
	systems, Quantum mechanical coheren	-		
	wells, wires and dots, Density of states and dim			
	FIRST INTERNAL EXAMI			
III	The physics of low dimensional structures - b		7	15%
		r-sperces	-	· - · -

	of two dimensional semiconductor nanostructures, square				
	quantum wells of finite depth, parabolic and triangular				
	quantum wells, quantum wires and quantum dots.				
	Semiconductor quantum nanostructures and super lattices –				
	MOSFET structures, Heterojunctions, Quantum wells,				
	modulation doped quantum wells, multiple quantum wells.				
IV	The concept of super lattices Kronig - Penney model of super	7	15%		
	lattice. Transport of charge in Nanostructures under Electric				
	field - parallel transport, perpendicular transport, quantum	N.A			
	transport in nanostructures. Transport of charge in magnetic	IVI			
	field and quantum Hall effect - Effect of magnetic field on a	A T			
	crystal, the Aharonov-Bohm effect, the Shubnikov-de Hass	4			
	effect, the quantum Hall effect.	J. Aust			
	SECOND INTERNAL EXAMINATION				
V	Nanoelectonic devices and systems - MODFETS,	8	20%		
	heterojunction bipolar transistors, resonant tunnel effect,				
	RTD, RTT,hot electron transistors, Coulomb blockade effect				
	and single electron transistor, CNT transistors,				
	heterostructure semiconductor laser, quantum well laser,				
	quantum dot LED, quantum dot laser, vertical cavity surface				
	emitting laser, quantum well optical modulator, quantum well				
	sub band photo detectors, Infrared detector, Nano switches,				
	principle of NEMS.				
VI	Nanocomposites, nanofillers, high performance materials,	7	20%		
	polymer nanocomposites, nanoclays, nanowires, nanotubes,				
	nanoclusters etc. Smart materials, self-assembly of materials,				
	safety issues with nanoscale powders.				
	END SEMESTER EXAMINATION				

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.

(20 x 2 = 40 marks)

2014

Estd.

Course	Course name	L-T-P-		Year of
code		Credits		roduction
AE472	PETROLEUM ENGINEERING	3-0-0-3		2016
Prerequis				
Course of	bjectives			
• To	impart the basic concepts of petroleum production, te	esting etc.		
• To	impart idea on Health Safety and Environment in Pe	troleum I	ndustry.	
• To	update with the latest trends in Petroleum Engineerin	ıg.		
Syllabus	ADI ARDI IL KA		NA.	
Refinery	products - Coking and thermal process - Catalytic	Cracking	g - Corin	g and core
analysis -	Reservoir fluid properties - Reserve estimation & te	chniques	- Well ed	quipments -
Well serv	icing & Workover operations - Field processing of o	oil & gas	- Produc	tion system
analysis a	& optimization - Nodal system analysis - LNG va	alue chain	n - Lub	ricating oil
blending	stocks petrochemical feedstocks - Evaluation of CH	BL/VDL,	USIT, S	FT, RFT
Production	n logging tools, principles, limitations and application	ns Cos	st Evaluat	ion - Latest
trends in I	Petroleum Engineering.			
Expected	outcome			
At the end	of the semester students will be able			
i. To	gain advanced knowledge in petroleum engineering			
ii. To	get knowledge in industrial safety and cost evaluation	on		
Text Boo	ks			
1. A.	Lucas Hurley, Modern Petroleum Technology Upstro	eam Vol I	Edition 2	2002.
2. A.	G. Lucas Hurley, Modern Petroleum Technology Dov	wnstream	Vol II Ed	lition 2002.
3. J.C	CH Garry , Hardward G.E and M.J.Kaiser, Petroleum	Refining	: Technol	ogy and
ec	onomics CRC Press V Edition			
	Cours <mark>e</mark> Plan			
				Semester
Module	Contents	7	Hours	Exam
		ノ		Exam Marks
Module I	Refinery products – Refinery Feeds – Crude distil		Hours 6	Exam
	Refinery products – Refinery Feeds – Crude distil Coking and thermal process : Classification and des	cription		Exam Marks
	Refinery products – Refinery Feeds – Crude distil Coking and thermal process : Classification and des of some common rocks with special reference to	cription clastic		Exam Marks
	Refinery products – Refinery Feeds – Crude distil Coking and thermal process : Classification and des of some common rocks with special reference to and nonclastic reservoir rocks. Origin, migration	cription clastic on and		Exam Marks
	Refinery products – Refinery Feeds – Crude distil Coking and thermal process : Classification and des of some common rocks with special reference to and nonclastic reservoir rocks. Origin, migratic accumulation of Petroleum. Petroleum exp	cription clastic		Exam Marks
I	Refinery products – Refinery Feeds – Crude distil Coking and thermal process : Classification and des of some common rocks with special reference to and nonclastic reservoir rocks. Origin, migratic accumulation of Petroleum. Petroleum exp methods.	cription clastic on and loration	6	Exam Marks 15%
	Refinery products – Refinery Feeds – Crude distil Coking and thermal process : Classification and des of some common rocks with special reference to and nonclastic reservoir rocks. Origin, migratic accumulation of Petroleum. Petroleum exp methods. Catalytic Cracking - Catalytical hydro cracking –	cription clastic on and loration		Exam Marks
I	Refinery products – Refinery Feeds – Crude distill Coking and thermal process : Classification and dest of some common rocks with special reference to and nonclastic reservoir rocks. Origin, migration accumulation of Petroleum. Petroleum exp methods. Catalytic Cracking - Catalytical hydro cracking – processing and Reused processing hydro to	cription clastic on and loration Hydro reating.	6	Exam Marks 15%
I	Refinery products – Refinery Feeds – Crude distill Coking and thermal process : Classification and dest of some common rocks with special reference to and nonclastic reservoir rocks. Origin, migration accumulation of Petroleum. Petroleum expression methods. Catalytic Cracking - Catalytical hydro cracking – processing and Reused processing hydro to Petrophysical properties of reservoir rocks. Cori	cription clastic on and loration - Hydro reating. ng and	6	Exam Marks 15%
I	Refinery products – Refinery Feeds – Crude distilCoking and thermal process : Classification and desiof some common rocks with special reference toand nonclastic reservoir rocks. Origin, migraticaccumulation of Petroleum. Petroleum expmethods.Catalytic Cracking - Catalytical hydro cracking –processing and Reused processing hydro tPetrophysical properties of reservoir rocks. Coricore analysis. Reservoir fluid properties. Phase behavior	cription o clastic on and loration - Hydro reating. ng and avior of	6	Exam Marks 15%
I	Refinery products – Refinery Feeds – Crude distill Coking and thermal process : Classification and dest of some common rocks with special reference to and nonclastic reservoir rocks. Origin, migration accumulation of Petroleum. Petroleum exp methods. Catalytic Cracking - Catalytical hydro cracking – processing and Reused processing hydro to Petrophysical properties of reservoir rocks. Cori core analysis. Reservoir fluid properties. Phase beha hydrocarbon system. Flow of fluids through porous	cription o clastic on and loration - Hydro reating. ng and avior of	6	Exam Marks 15%
I	Refinery products – Refinery Feeds – Crude distill Coking and thermal process : Classification and dest of some common rocks with special reference to and nonclastic reservoir rocks. Origin, migration accumulation of Petroleum. Petroleum exponent methods. Catalytic Cracking - Catalytical hydro cracking – processing and Reused processing hydro to Petrophysical properties of reservoir rocks. Corri core analysis. Reservoir fluid properties. Phase beha hydrocarbon system. Flow of fluids through porous Water and gas coning.	- Hydro reating. ng and avior of media.	6	Exam Marks 15%
I	Refinery products – Refinery Feeds – Crude distill Coking and thermal process : Classification and dest of some common rocks with special reference to and nonclastic reservoir rocks. Origin, migratic accumulation of Petroleum. Petroleum exp methods. Catalytic Cracking - Catalytical hydro cracking – processing and Reused processing hydro t Petrophysical properties of reservoir rocks. Cori core analysis. Reservoir fluid properties. Phase beach hydrocarbon system. Flow of fluids through porous Water and gas coning.	cription o clastic on and loration - Hydro reating. ng and avior of o media. ON	6	Exam Marks 15%
I	Refinery products – Refinery Feeds – Crude distill Coking and thermal process : Classification and dest of some common rocks with special reference to and nonclastic reservoir rocks. Origin, migration accumulation of Petroleum. Petroleum expressing methods. Catalytic Cracking - Catalytical hydro cracking – processing and Reused processing hydro to Petrophysical properties of reservoir rocks. Corri core analysis. Reservoir fluid properties. Phase behas hydrocarbon system. Flow of fluids through porous Water and gas coning. FIRST INTERNAL EXAMINATI Well equipments. Well completion techniques	cription clastic on and loration - Hydro reating. ng and avior of media. ON - Well	6	Exam Marks 15%
I	Refinery products – Refinery Feeds – Crude distill Coking and thermal process : Classification and dest of some common rocks with special reference to and nonclastic reservoir rocks. Origin, migration accumulation of Petroleum. Petroleum exponent methods. Catalytic Cracking - Catalytical hydro cracking – processing and Reused processing hydro to Petrophysical properties of reservoir rocks. Corricore analysis. Reservoir fluid properties. Phase behas hydrocarbon system. Flow of fluids through porous Water and gas coning. FIRST INTERNAL EXAMINATI Well equipments. Well completion techniques production problems and mitigation. Well servition	cription clastic on and loration - Hydro reating. ng and avior of a media. ON . Well cing &	6	Exam Marks 15%
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	testing. Multiphase flow in tubing and flow-lines. Nodal system analysis. Pressure vessels, storage tanks, shell and tube heat exchangers, pumps and compressors, LNG value chain.		
	SECOND INTERNAL EXAMINATION		
V	Lubricating oil blending stocks petrochemical feedstocks. Evaluation of petro physical of sub-surface formations: Principles applications, advantages and disadvantages of SP, resistivity, radioactive, acoustic logs and types of tools used. Evaluation of CBL/VDL, USIT, SFT, RFT. Production logging tools, principles, limitations and applications.	8 AL	20%
VI	 Special type of logging tools. Casing inspection tools (principles, applications and limitations), Formations micro scanner (FMS), NMR logging principles. Standard log interpretation methods. Cross-plotting methods. Cost Evaluation – Economic evaluation of petroleum reused and refineries. Latest trends in Petroleum Engineering: Coal bed methane, shale gas, oil shale, gas hydrate, and heavy oil. 	8	20%

Maximum Marks:100

Exam Duration: 3 Hours

Part A

Answer any two out of three questions uniformly covering Modules 1 and 2 together. Each question carries 15 marks and may have not more than four sub divisions.

(15 x 2 = 30 marks)

Part B

Answer any two out of three questions uniformly covering Modules 3 and 4 together. Each question carries 15 marks and may have not more than four sub divisions.

2014

(15 x 2 = 30 marks)

Part C

Answer any two out of three questions uniformly covering Modules 5 and 6 together. Each question carries 15 marks and may have not more than four sub divisions.